

A new approach to build a low-level malicious fault list starting from high-level description and alternative graphs

Benso, A.; Prinetto, Paolo; Rebaudengo, M.; Sonza, M.; **Ubar, Raimund-Johannes** Proceedings IEEE European Design & Test Conference, Paris, March 17-20, 1997 1997 / p. 560-565 <https://ieeexplore.ieee.org/document/582417>

A new evolutionary-technique-based approach to optimize pseudo-random TPG for logic BIST

Jutman, Artur; Aleksejev, Jevgeni; Ubar, Raimund-Johannes MEET/MARIND'2002 : proceedings of First International Congress on Mechanical and Electrical Engineering and Technology and Fourth International Conference on Marine Industry, 07-11 October 2002, Varna Bulgaria. Volume 1 2002 / p. 247-252 : ill

A new testability calculation method to guide RTL test generation

Raik, Jaan; Nõmmeots, Tanel; Ubar, Raimund-Johannes Journal of electronic testing : theory and applications 2005 / p. 71-82 : ill <https://doi.org/10.1007/s10836-005-5288-5>

A PC-based CAD system for training digital test

Ubar, Raimund-Johannes; Buldas, Ahto; Paomets, Priidu; Raik, Jaan; Tulit, Viljar The Fifth EUROCHIP Workshop on VLSI Design Training, 17-18-19 October 1994, Dresden, Germany 1994 / p. 152-157: ill

A scalable static test set compaction method for sequential circuits

Aleksejev, Igor; Raik, Jaan; Jutman, Artur; Ubar, Raimund-Johannes Proceedings of the 9th IEEE Latin-American Test Workshop : LATW2008 : February 17-20, 2008, Puebla, Mexico 2008 / p. 87-92 : ill

A study of the toxicity of the ozonation products of phenols and chlorophenols by daphnia magna test

Trapido, Marina; **Veressinina, Jelena** 23rd Estonian Chemistry Days : abstracts of scientific conference 1997 / p. 152

A testing strategy for interacting finite state machines

Yevtushenko, Nina; Petrenko, Alexandre; Trenkaev, Vadim BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 137-140: ill

About robustness of test patterns regarding multiple faults

Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan LATW 2012 : 13th IEEE Latin-American Test Workshop proceedings : April 10th-13th, 2012, Quito, Ecuador 2012 / p. 86-91 : ill <https://www.infona.pl/resource/bwmeta1.element.ieee-art-000006261243>

Abrasivity study of materials used at abrasive tests

Kulu, Priit; Veinthal, Renno; Käerdi, Helmo; Tarbe, Riho Tribology 2008 : proceedings of the 9th International Tribology Conference : University of Pretoria, South Africa, 2-4 April 2008 2008 / p. 3.4(1)-3.4(10)

Adaptive Extended Kalman Filter position estimation based on Ultra-Wideband Active-Passive Ranging Protocol

Laadung, Taavi; Ulp, Sander; Fjodorov, Aleksei; Alam, Muhammad Mahtab; Le Moullec, Yannick IEEE Access 2023 / p. 92575-92588 <https://doi.org/10.1109/ACCESS.2023.3308696> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Advances in moving speaker acoustic localization for operation in distributed systems

Astapov, Sergei; Berdnikova, Julia; Preden, Jürjo-Sören Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK seitsmenda aastakonverentsi artiklite kogumik : 15.-16. novembril 2013, Haapsalu 2013 / p. 9-12 : ill

AG-model for design of testable controllers

Kasirova, Lilia BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 303-306: ill

Air change efficiency of room ventilation units

Mikola, Alo; Rehand, Juhan; Kurnitski, Jarek E3S Web of Conferences : CLIMA 2019 Congress, Bucharest, Romania, May 26-29, 2019 2019 / art. 01017, 8 p <https://doi.org/10.1051/e3sconf/201911101017> [Conference proceedings at Scopus](#) [Article at Scopus](#)

Algorithms of functional level testability analysis for digital circuits

Ubar, Raimund-Johannes; Kuchcinski, Ktysztof Periodica polytechnica. Electrical engineering 1992 / 3/4, p. 295-308

Alternative graphs as a mathematical tool and knowledge representation for diagnosis purposes in digital systems

Ubar, Raimund-Johannes BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 285-292: ill

An approach for PSL assertion coverage analysis with high-level decision diagrams

Jenihhin, Maksim; Raik, Jaan; Ubar, Raimund-Johannes; Shchenova, Tatjana Proceedings of IEEE East-West Design & Test Symposium (EWDTS'10) : St. Petersburg, Russia, September 17-20, 2010 2010 / p. 13-16 : ill <https://ieeexplore.ieee.org/document/5742048>

An approach for verification assertions reuse in RTL test pattern generation

Jenihhin, Maksim; Raik, Jaan; Fujiwara, Hideo; Ubar, Raimund-Johannes; Viilukas, Taavi Digest of papers : IEEE 11th Workshop on RTL and High Level Testing : WRTL'10 : December 5-6, 2010, Shanghai, China 2010 / p. 107-110 : ill

An approach to model development for embedded testing

Timohovich, E. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 353-358

An aspect-oriented technique to model-based test design

Sarna, Külli Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK kuuenda aastakonverentsi artiklite kogumik : 3.-5. oktoobril 2012, Laulasmaa 2012 / p. 77-80

An automatic test generation system for microprocessor VLSI

Kont, Toomas Машинное проектирование электронных устройств и систем 1989 / p. 104-113

An educational environment for digital testing : hardware, tools, and web-based runtime platform

Jutman, Artur; Raik, Jaan; Ubar, Raimund-Johannes; Vislogubov, Vladislav Proceedings : DSD'2005 : 8th Euromicro Conference on Digital System Design : Architectures, Methods and Tools : Porto, Portugal, August 30 - September 3, 2005 2005 / p. 412-419 : ill https://www.researchgate.net/profile/Artur-Jutman/publication/220880167_An_Educational_Environment_for_Digital_Testing_Hardware_Tools_and_Web-Based_Runtime_Platform/links/02e7e53c3c71b0b2a7000000/An-Educational-Environment-for-Digital-Testing-Hardware-Tools-and-Web-Based-Runtime-Platform.pdf

An external test approach for network-on-a-chip switches

Raik, Jaan; Govind, Vineeth; Ubar, Raimund-Johannes ATS '06 : Proceedings of the 15th Asian Test Symposium : November 20-23, 2006, Fukuoka, Japan 2006 / p. 437-442 : ill <http://dx.doi.org/10.1109/ATS.2006.23>

An external test approach for network-on-a-chip switches

Raik, Jaan; Govind, Vineeth; Ubar, Raimund-Johannes 2002-2011 : 20th Anniversary compendium of papers from Asian Test Symposium 2011 / p. 185-190 : ill

An overview of expert system testing with remarks on distributed architecture

Parmakson, Priit; Tepandi, Jaak Proc. of the 11th Int. Scientific School on Distributed Information Systems Architecture, Wroclaw, 28.Jan.-1.Feb., 1990 1990

Analysis of a test method for delay faults in NoC interconnects

Bengtsson, Tomas; **Jutman, Artur; Kumar, Shashi; Ubar, Raimund-Johannes; Peng, Zebo** Proceedings of the IEEE East-West Design & Test Workshop (EWDWTW'06) : Sochi, Russia, September 15-19, 2006 2006 / p. 42-46 : ill

Analysis of a three-phase induction motor using the dynamic state space model

Asad, Bilal; Vaimann, Toomas; Belahcen, Anouar 17th International Symposium "Topical Problems in the Field of Electrical and Power Engineering". Doctoral school of energy and geotechnology. III : Kuressaare, Estonia, January 15-20, 2018 2018 / p. 65-69 : ill http://ise.elnet.ee/record=b2950017~S2*est

Applicability of the energetic erosion theory to hardened steels

Kleis, Ilmar; Remi, Toomas OST-03 Symposium on Machine Design 2003 / p. 245-252 : ill

Application of nanoindentation for constituent phases testing in ceramic-metal composites

Hussainova, Irina; Jasiuk, Iwona; Hussainov, Medhat Technical proceedings of the 2010 NSTI Nanotechnology Conference & Expo - Nanotech 2010. Vol. 1, Nanotechnology 2010 : Advanced materials, CNTs, Particles, Films and Composites 2010 / p. 152-155 : ill

Application of sequential test set compaction to LFSR reseeding

Aleksejev, Igor; Jutman, Artur; Raik, Jaan; Ubar, Raimund-Johannes 26th Norchip Conference : Tallinn, Estonia, 17-18 November 2008 : formal proceedings 2008 / p. 102-107 : ill <http://dx.doi.org/10.1109/NORCHIP.2008.4738292>

An approach for verification assertions reuse 2 in RTL test pattern generation

Jenihhin, Maksim; Raik, Jaan; Ubar, Raimund-Johannes; Viilukas, Taavi; Fujiwara, Hideo Journal of Shanghai Normal University : Natural Sciences 2010 / p. 441-447 : ill https://www.researchgate.net/publication/240613999_An_Approach_for_Verification_Assertions_Reuse_in_RTL_Test_Pattern_Generation

Approaches to improve hierarchical ATPG for synchronous sequential circuits

Viilukas, Taavi Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK kuuenda aastakonverentsi artiklite kogumik : 3.-5. oktoobril 2012, Laulasmaa 2012 / p. 105-108 : ill

Arterial pulse wave analysis during cold pressor test in patients with borderline hypertension [Electronic resource]

Hlimonenko, Irina; Meigas, Kalju; Vahisalu, Rein IFMBE proceedings 2005 / [5] p. [CD-ROM]

Aspect-oriented model-based testing = Aspekt-orienteeritud mudeli-põhine testimine

Sarna, Külli 2018 <https://digi.lib.ttu.ee/i/?11065> https://www.ester.ee/record=b5166882*est

Aspect-oriented Model-based testing with UPPAAL timed automata

Vain, Jüri; Tsiopoulos, Leonidas; Kanter, Gert Model and Data Engineering : 10th International Conference, MEDI 2021, Tallinn, Estonia, June 21–23, 2021 : proceedings 2021 / p. 117-124 https://doi.org/10.1007/978-3-030-78428-7_10 [Conference Proceedings at Scopus](#) [Article at Scopus](#)

Aspect-oriented testing of a rehabilitation system

Sarna, Külli; Vain, Jüri VALID 2014 : the Sixth International Conference on Advances in System Testing and Validation Lifecycle : October 12-16, 2014, Nice, France 2014 / p. 73-78 : ill

Assembling low-level tests to high-level symbolic test frames

Jervan, Gert; Markus, Antti; Raik, Jaan; Ubar, Raimund-Johannes Proceedings [of the] 15th NORCHIP Conference, Tallinn, 10-11 November 1997 1997 / p. 275-280: ill

Assessment of diagnostic test for automated bug localization

Tihomirov, Valentin; Tšepurov, Anton; Jenihhin, Maksim; Raik, Jaan; Ubar, Raimund-Johannes LATW2013 : 14th IEEE Latin-American Test Workshop, Cordoba, Argentina, April 3-5, 2013 : [proceedings] 2013 / [6] p. : ill

Assessment of durability of environmentally friendly wood-based panels

Kallavus, Urve; Järv, Hele; Kalamees, Targo; Kurik, Lembit Energy procedia 2017 / p. 207–212 : ill
<https://doi.org/10.1016/j.egypro.2017.09.756> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Assessment of the potential of lubricated contact condition laboratory testing and surface analysis for improving the performance of machine elements. Comparison of model and real component test methods

Antonov, Maksim; Michalczewski, Remigiusz; Pasaribu, Richard; Piekoszewski, Witold 18th International Baltic Conference : Engineering Materials & Tribology : BALTMATTRIB-2009 : October 22-23, 2009, Tallinn, Estonia : abstracts 2009 / p. 55

ATP-meetod mikroobse biomassi kiireks määramiseks ja selle kasutamine hügieeni testimisel toiduainetetööstuses

Kahru, Anne; Kurvet, Madis; Külm, I. EMS 96 teaduskonverents, 6.-7. juuni 1996, Tallinn = EMS 96 Scientific Conference, 6-7 June 1996, Tallinn 1996 / poster 17

At-speed functional built-in self-test methodology for processors [Electronic resource]

Ubar, Raimund-Johannes; Indus, Viljar; Kalmend, Oliver Proceedings of the IASTED International Conference on Engineering and Applied Science : December 27-29, 2012, Columbo, Sri Lanka 2012 / p. 168-172 : ill [CD-ROM]

At-speed self-testing of high-performance pipe-lined processing architectures [Electronic resource]

Gorev, Maksim; Ubar, Raimund-Johannes; Ellervee, Peeter; Devadze, Sergei; Raik, Jaan; Min, Mart 31st Norchip Conference : Vilnius, Lithuania, 11-12 November 2013 : conference program and papers 2013 / p. 1-6 : ill [USB]

At-speed testing and test quality evaluation for high-performance pipelined systems Töökiirusel testimine ja testi kvaliteedi hindamine kõrgjõudlus-konveierarhitektuuriga süsteemidele

Gorev, Maksim 2015 <https://digi.lib.ttu.ee/i/?3953>

At-speed testing of inter-die connections of 3D-SICs in the presence of shore logic

Shibin, Konstantin; Chickermane, Vivek; Keller, Brion; Papamietis, Christos; Marinissen, Erik Jan 2015 Asian Test Symposium : ATS 2015 : 22-25 November 2015, Mumbai, Maharashtra, India : proceedings 2015 / p. 79-84 : ill <https://doi.org/10.1109/ATS.2015.21> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Automated correction of design errors by edge redirection on high-level decision diagrams

Karputkin, Anton; Ubar, Raimund-Johannes; Tombak, Mati; Raik, Jaan 13th International Symposium on Quality Electronic Design (ISQED), 2012 2012 / p. 686-693 : ill <https://ieeexplore.ieee.org/document/6113980>

Automated software-based in-field self-test program synthesis

Jasnetski, Artjom; Ubar, Raimund-Johannes; Tšertov, Anton International journal of microelectronics and computer science 2017 / p. 57-64 : ill

Automated test pattern generator with constraint solver

Viilukas, Taavi; Raik, Jaan Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK neljanda aastakonverentsi artiklite kogumik : 26.-27. novembril 2010, Essu mõis 2010 / lk. 33-36

Automated test program synthesis for digital systems with high-level decision diagrams

Ubar, Raimund-Johannes Proc. of 7th International Conference 2005 / p. 171-180

Automated XML-based test modelling for mixed-signal circuits

Melik, Andres BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 203-204 : ill

Automatic distribution of local testers for testing distributed systems

Vain, Jüri; Halling, Evelin; Kanter, Gert; Anier, Aivo; Pal, Deepak Databases and information systems IX : selected papers from the twelfth International Baltic Conference, DB&IS 2016 2016 / p. 297-310 : ill <https://doi.org/10.3233/978-1-61499-714-6-297> [Conference Proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Automatic GUI model generation : state of the art

Kull, Andres ISSREW 2012 : 23rd IEEE International Symposium on Software Reliability Engineering Supplemental Proceedings : 27-30 November 2012, Dallas, Texas, USA 2012 / p. 207-212 <https://ieeexplore.ieee.org/stamp/stamp.jsp?arnumber=6405443>

Automatic SoC level test path synthesis based on partial functional models

Tšertov, Anton; Ubar, Raimund-Johannes; Jutman, Artur; Devadze, Sergei 2011 Asian Test Symposium (ATS) : New Delhi, India 2011 / p. 532-538 <https://ieeexplore.ieee.org/document/6114730>

Automatic synthesis of asynchronous circuits from synchronous RTL descriptions

Öberg, Johnny; Plosila, Juha; Ellervee, Peeter Proceedings 23rd NORCHIP Conference : Oulu, Finland, 21-22 November 2005 2005 / p. 200-205 : ill <https://ieeexplore.ieee.org/document/1597024/keywords#keywords>

Automatic system for testing of dynamic quality of PC plug-in A/D boards

Pokorny, Martin; Roztocil, Jaroslav; Haasz, Vladimir BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 61-62: ill

Automatic test generation system for VLSI

Jervan, Gert; Markus, Antti; Raik, Jaan; Ubar, Raimund-Johannes Proceedings of the First Electronic Circuits and Systems Conference : Bratislava, Slovakia, September 4-5, 1997 1997 / p. 255-258

Automation of testing beyond the SoCs

Tšertov, Anton; Jutman, Artur; Devadze, Sergei Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK neljanda aastakonverentsi artiklite kogumik : 26.-27. novembril 2010, Essu mõis 2010 / lk. 29-32 : ill

Automation of the 3-phase induction motor type test place for industrial use

Kuusk, Leho; Laugis, Juhan Baltic electrical engineering review 1998 / 1, p. 10-12

Bbuzz : a Bit-aware fuzzing framework for network protocol systematic reverse engineering and analysis

Blumbergs, Bernhards; Vaarandi, Risto MILCOM 2017 - 2017 IEEE Military Communications Conference : Baltimore, Maryland, USA, 23-25 October 2017 2017 / p. 707-712 <https://doi.org/10.1109/MILCOM.2017.8170785> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Behavior of carbonate-rich fuels in AFBC and PFBC conditions

Ots, Arvo; Arro, Hendrik; Pihu, Tõnu; Prikk, Arvi Proceedings of the 15th International Conference on Fluidized Bed Combustion : May 16-19, 1999, Savannah, Georgia [CD-ROM] 1999 / 20 p <https://www.osti.gov/biblio/20006717>

Behavioral level modeling of digital systems for testing purposes

Ubar, Raimund-Johannes 42nd International Conference, Ilmenau, Germany, September 22-25, 1997. Part 1 1997 / p. 510-515

A benchmark suite for evaluating the efficiency of test tools

Kruus, Helena; Ubar, Raimund-Johannes; Ellervee, Peeter; Gorev, Maksim; Pesonen, Vadim; Devadze, Sergei; Orasson, Elmet; Brik, Marina; Min, Mart; Annus, Paul; Kruus, Margus; Meigas, Kalju BEC 2012 : 2012 13th Biennial Baltic Electronics Conference : proceedings of the 13th Biennial Baltic Electronics Conference : October 3-5, 2012, Tallinn, Estonia 2012 / p. 85-88 : ill

BIST analyzer : a training platform for SoC testing [Electronic resource]

Jutman, Artur; Tšertov, Anton; Tšepurov, Anton; Aleksejev, Igor; Ubar, Raimund-Johannes Wuttke, Heinz-Dietrich 37th Annual Frontiers in Education Conference : Global Engineering : Knowledge Without Borders, Opportunities Without Passports : Milwaukee, Wisconsin, October 10-13, 2007 2007 / p. S3H-8-S3H-13 : ill. [CD-ROM] <http://dx.doi.org/10.1109/FIE.2007.4418125>

A BIST scheme for testing mixed analogue and digital circuits

Robson, Malcolm; Russel, Gordon BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 183-186: ill

Built-in self diagnosis with multiple signature analyzers in digital systems

Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan Proceedings of the 9th IEEE Latin-American Test Workshop : LATW2008 : February 17-20, 2008, Puebla, Mexico 2008 / p. 29-34 : ill

A CAD system for teaching digital test

Ubar, Raimund-Johannes; Ivask, Eero; Paomets, Priidu; **Raik, Jaan** BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 369-372: ill

Calculation of probabilistic testability measures for digital circuits with Structurally Synthesized BDDs

Jürimägi, Lembit; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan Microprocessors and microsystems 2020 / art. 103117, 12 p <https://doi.org/10.1016/j.micpro.2020.103117> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Calculation of testability measures on structurally synthesized binary decision diagrams

Ubar, Raimund-Johannes; Heinlaid, J.; Raik, Jaan; Raun, L. BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 179-182: ill

Case study in testing digital systems

Ubar, Raimund-Johannes Baltic electronics 1995 / 1, p. 24-27

Case study-based performance evaluation of reactive planning tester

Kull, Andres; Raiend, Kullo; Vain, Jüri; Kääramees, Marko Model-based Testing in Practice : 2nd Workshop on Model-based Testing in Practice(MoTiP 2009) : Enschede, The Netherlands, June 23, 2009 : proceedings 2009 / p. 87-96 : ill <https://www.etis.ee/Portal/Publications/Display/c507fc75-771f-419a-bf67-571af65fdb66>

Circular production, designing, and mechanical testing of polypropylene-based reinforced composite materials : statistical analysis for potential automotive and nuclear applications

Hussain, Abrar; Podgurski, Vitali; Goljandin, Dmitri; Antonov, Maksim; Sergejev, Fjodor; Krasnou, Illia Polymers 2023 / art. 3410, 30 p. : ill <https://doi.org/10.3390/polym15163410> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

The class of test signals for dynamic testing of AD converters

Land, Raul The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 127-128 : ill

A classification of epileptic spikes in the EEG

Lossmann, Eerik Tallinna Tehnikaülikooli Toimetised 1994 / lk. 52-61: ill

Code coverage analysis for concurrent programming languages using high-level decision diagrams

Jenihhin, Maksim; Raik, Jaan; Tšepurov, Anton; Reinsalu, Uljana; Ubar, Raimund-Johannes Proceedings of the 12th European Workshop on Dependable Computing : EWDC 2009 : Toulouse, France, May 14-15, 2009 2009 / [4] p. : ill <https://hal.archives-ouvertes.fr/hal-00381559>

Cognitive disorders in patients with chronic kidney disease : specificities of clinical assessment

Pepin, Marion; Ferreira, Ana Carina; Arici, Mustafa; Bachmann, Maie; Barbieri, Michelangela; Bumblyte, Inga Arune Nephrology Dialysis Transplantation 2022 / p. ii23-ii32 <https://doi.org/10.1093/ndt/gfab262> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Combined pseudo-exhaustive and deterministic testing of array multipliers

Oyeniran, Adeboye Stephen; Azad, Siavoosh Payandeh; Ubar, Raimund-Johannes 2018 IEEE International Conference on Automation, Quality and Testing, Robotics (AQTR) : THETA 21st edition, 24th-26th May, Cluj-Napoca, Romania : proceedings 2018 / 6 p. : ill <https://doi.org/10.1109/AQTR.2018.8402708>

Combining dynamic slicing and mutation operators for ESL correction

Repinski, Urmas; Hantson, Hanno; Jenihhin, Maksim; Raik, Jaan; Ubar, Raimund-Johannes Proceedings : 2012 17th IEEE European Test Symposium (ETS) : May 28th-June 1st, 2012, Annecy, France 2012 / [6] p. : ill <https://ieeexplore.ieee.org/document/6233020>

Combining functional and structural approaches in test generation for digital systems

Ubar, Raimund-Johannes Microelectronics reliability 1998 / p. 317-329 : ill [https://doi.org/10.1016/S0026-2714\(97\)00192-3](https://doi.org/10.1016/S0026-2714(97)00192-3)

Combining learning, training and research in laboratory course for design and test

Ubar, Raimund-Johannes; Orasson, Elmet; Raik, Jaan; Wuttke, Heinz-Dietrich The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 221-224 : ill https://www.researchgate.net/publication/242397131_Combining_Learning_Training_and_Research_in_Laboratory_Course_for_Design_and_Test

Combining symbolic techniques with topological approach in test generation

Ubar, Raimund-Johannes Proceedings of the 3rd Workshop on Mixed Design of Integrated Circuits and Systems, Lodz, May 1996

Compaction of decision diagrams for describing multi-process VHDL descriptions

Leveugle, R.; Saucier, Gabriele; **Ubar, Raimund-Johannes** BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 195-198: ill

Comparative analysis of sequential circuit test generation approaches

Raik, Jaan; Krivenko, Anna; **Ubar, Raimund-Johannes** BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 225-228 : ill

Comparative mixed-signal test method and toolset

Mellik, Andres Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK teise aastakonverentsi artiklite kogumik : 11.-12. mai 2007, Viinistu kunstimuseum 2007 / lk. 153-154 : ill

Comparative mixed-signal test method and toolset

Mellik, Andres; Raik, Jaan IEEE International Workshop on Open Source Test Technology Tools (IOST3) 2007 / ? p

A comparative study of battery degradation cost modeling in residential PV-battery systems for day-ahead optimization

Lekhel, Cheikh Elekbir Sidi; Mbayed, Rita; **Hokmabad, Hossein Nourollahi**; Velihorskyi, Oleksandr; Monmasson, Eric 2025 IECON – 51st Annual Conference of the IEEE Industrial Electronics Society 2025 / 6 p <http://doi.org/10.1109/IECON58223.2025.11221673>

Comparison of different soil compaction test methods [Electronic resource]

Aavik, Andrus 26th International Baltic Road Conference : Kuressaare, 28-30 August, 2006 2006

Comparison of genetic and random techniques for test pattern generation

Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 163-166: ill

Compliance testing concept of grid-connected inverter-based resources using simulated input

Dvoracek, Jiri; Drapela, Jiri; Moravek, Jan; Vojtek, Martin; Toman, Petr; **Rassõlkin, Anton; Vaimann, Toomas** 2023 23rd International Scientific Conference on Electric Power Engineering (EPE) 2023 / p. 1-6 <https://doi.org/10.1109/EPE58302.2023.10149232>

A comprehensive methodology for stress procedures evaluation and comparison for Burn-In of automotive SoC

Appello, D.; Bernardi, P.; Giacomelli, G.; **Ruberg, Priit** Proceedings of the 2017 Design, Automation & Test in Europe (DATE) : 27-31 March 2017, Swisstech, Lausanne, Switzerland 2017 / p. 646-649 : ill <https://doi.org/10.23919/DATE.2017.7927068>

Concept drift and cross-device behavior : challenges and implications for effective android malware detection

Guerra Manzanares, Alejandro; Luckner, Marcin; Bahsi, Hayretin Computers & Security 2022 / art. 102757, 20 p. : ill <https://doi.org/10.1016/j.cose.2022.102757> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Conceptual test bench for small class unmanned autonomous vehicle performance estimation

Pütsep, Kristjan; Rassõlkin, Anton; Vaimann, Toomas 2021 IEEE 19th International Power Electronics and Motion Control Conference, The Silesian University of Technology Gliwice, Poland, 25 - 29 April, 2021 (PEMC) : proceedings 2021 / p. 695-698 : ill <https://doi.org/10.1109/PEMC48073.2021.9432509>

Condition assessment of power plant components operating under creep by testing of miniature specimens

Klevtsov, Ivan; Dedov, Andrei Creep and Fracture in High Temperature Components : April 21-23, 2009, Zurich, Switzerland 2009 / p. 1126-1137

Conditional fault collapsing in digital circuits with shared structurally synthesized BDDs [Online resource]

Jürimägi, Lembit; Ubar, Raimund-Johannes BEC 2018 : 2018 16th Biennial Baltic Electronics Conference (BEC) : proceedings of the 16th Biennial Baltic Electronics Conference, October 8-10, 2018 2018 / 4 p. : ill <https://doi.org/10.1109/BEC.2018.8600967>

Constraint-based heuristic on-line test generation from non-deterministic I/O EFSMs

Ahman, Danel; **Kääramees, Marko** EPTCS 80 : proceedings of the 7th Workshop on Model-Based Testing : Tallinn, Estonia, 25 March 2012 2012 / p. 115-129 : ill <https://www.semanticscholar.org/paper/Constraint-Based-Heuristic-On-line-Test-Generation-Ahman-K%C3%A4r%C3%A4amees/c798ef6753277479b79652be2a5921a1db94c74c>

Constraint-based hierarchical untestability identification for synchronous sequential circuits

Raik, Jaan; Rannaste, Anna; Jenihhin, Maksim; Viilukas, Taavi; Ubar, Raimund-Johannes; Fujiwara, Hideo Sixteenth IEEE European Test Symposium : 23-27 May 2011, Trondheim 2011 / p. 147-152

Constraint-based hierarchical untestability identification for synchronous sequential circuits

Viilukas, Taavi; Raik, Jaan; Ubar, Raimund-Johannes; Rannaste, Anna; Jenihhin, Maksim; Fujiwara, Hideo Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK viienda aastakonverentsi artiklite kogumik : 25.-26. novembril 2011, Nelijärve 2011 / p. 139-142 : ill

Constraint-based test pattern generation at the register-transfer level

Viilukas, Taavi; Raik, Jaan; Jenihhin, Maksim; Ubar, Raimund-Johannes; Krivenko, Anna Proceedings of the 13th IEEE Symposium on Design and Diagnostics of Electronic Circuits and Systems : April 14-16, 2010, Vienna, Austria 2010 / p. 352-357 : ill
<http://dx.doi.org/10.1109/DDECS.2010.5491752>

Constraint-based test scenario description language

Vain, Jüri; Halling, Evelin BEC 2012 : 2012 13th Biennial Baltic Electronics Conference : proceedings of the 13th Biennial Baltic Electronics Conference : October 3-5, 2012, Tallinn, Estonia 2012 / p. 89-92 : ill

A constraint-driven gate-level test generator

Raik, Jaan; Ubar, Raimund-Johannes; Jervan, Gert; Krupnova, Helena BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 237-240: ill

Constraints analysis in hierarchical test generation for digital systems

Ubar, Raimund-Johannes; Krupnova, Helena BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 313-318: ill

Constraints solving based hierarchical test generation for synchronous sequential circuits = Kitsenduste lahendamisel baseeruv hierarhiline testigeneerimine sünkroonsetele järjestikskeemidele

Viilukas, Taavi 2012 https://www.ester.ee/record=b2888278*est

Construction of aspect models for model-based testing

Sarna, Külli; Vain, Jüri Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK viienda aastakonverentsi artiklite kogumik : 25.-26. novembril 2011, Nelijärve 2011 / p. 67-70 : ill

Construction of the tests of combinational circuit failures by analyzing the orthogonal disjunctive normal forms represented by the alternative graphs

Matrosova, A.Yu.; Pleshkov, A.G.; Ubar, Raimund-Johannes Automation and remote control 2005 / p. 313-327 : ill
<https://doi.org/10.1007/s10513-005-0054-9>

Contributions to ventilation system demand response: a case study of an educational building

Maask, Vahur; Mikola, Alo; Korõtko, Tarmo; Rosin, Argo; Thalfeldt, Martin E3S Web Conference: Cold Climate HVAC and Energy 2021 2021 / art. 11001, 6 p <https://doi.org/10.1051/e3sconf/202124611001> [Conference Proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Correlation between COVID-19 cases and gold price fluctuation

Gautam, Roshan; Kim, Yoochan; Topal, Erkan; Hitch, Michael William International journal of mining, reclamation and environment 2022 / p. 574-586 <https://doi.org/10.1080/17480930.2022.2077542>

Corrosion of cement and concrete - methods of testing and evaluation

Raado, Lembi-Merike; Hain, Tiina Management of Durability in the Building Process : International Workshop : Milan, 25-26 June 2003 : proceedings 2003 / [7] p. : ill

Cybersecurity test range for autonomous vehicle shuttles

Roberts, Andrew James; Snetkov, Nikita; Maennel, Olaf Manuel 2021 IEEE European Symposium on Security and Privacy Workshops EuroS&PW 2021 : Virtual Conference, 6-10 September 2021 : proceedings 2021 / p. 239-248 : ill
<https://doi.org/10.1109/EuroSPW54576.2021.00031>

Cybersecurity testing and attack propagation analysis of autonomous driving software = Autonomse sõiduki juhtimistarkvara küberturvalisuse testimine ja rünnakute leviku analüüs

Roberts, Andrew James 2025 https://www.ester.ee/record=b5750527*est <https://digikogu.taltech.ee/et/Item/fbecd0b1-252c-4a7d-b06c-588683fd4640> <https://doi.org/10.23658/taltech.41/2025>

DACA : automated attack scenarios and dataset generation

Korving, Frank; Vaarandi, Risto Proceedings of the 18th International Conference on Cyber Warfare and Security, ICCWS 2023, a conference hosted by Towson University, Baltimore County, Maryland, USA, 9-10 March 2023 2023 / p. 550-559 : ill
<https://papers.academic-conferences.org/index.php/iccws/article/download/962/938> <https://doi.org/10.34190/iccws.18.1.962>

DECIDER : a decision diagram based hierarchical test generation system

Jervan, Gert; Markus, Antti; Raik, Jaan; Ubar, Raimund-Johannes Proceedings of the 2nd International Workshop on Design and Diagnostics of Electronic Circuits and Systems, Szczyrk, Poland, September 2-4, 1998 1998 / p. 269-273
<https://www.ida.liu.se/labs/eslab/publications/pap/db/DDECS98.pdf>

DECIDER : a system for hierarchical test pattern generation

Raik, Jaan; Ubar, Raimund-Johannes Radioelectronics and informatics 2003 / p. 40-45 : ill
https://www.researchgate.net/publication/250395975_DECIDER_A_System_for_Hierarchical_Test_Pattern_Generation

A decision diagram based hierarchical test pattern generator

Jervan, Gert; Markus, Antti; Raik, Jaan; Ubar, Raimund-Johannes BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 159-162: ill

Decision diagrams - from a mathematical notion to engineering applications

Stankovic, Radomir S.; **Ubar, Raimund-Johannes**; Astola, Jaakko Facta Universitatis [Niš]. Series electronics and energetics 2011 / p. 281-301 : ill <http://dx.doi.org/10.2298/FUEE1103281S>

Decision diagrams and digital test

Ubar, Raimund-Johannes 41th International Conference on Microelectronics, Devices and Materials : MIDEEM 2005 : Ribno at Bled, Slovenia : invited plenary paper 2005 / p. 15-26

Decision diagrams and digital test

Ubar, Raimund-Johannes ECMS 2003 : 6th International Workshop on Electronics, Control, Measurement and Signals : Liberec, Czechia, June 2-4, 2003 2003 / p. 266-273 : ill [http://www.midem-drustvo.si/Journal%20papers/MIDEM_35\(2005\)4p187.pdf](http://www.midem-drustvo.si/Journal%20papers/MIDEM_35(2005)4p187.pdf)

Decompositional design of testable Decompositional design of testable FSM networks

Keevallik, Andres; Kruus, Margus; Lensen, Harri Proceedings of the 4th International Workshop Mixed Design of Integrated Circuits and Systems : MIXDES'97 : Poznan, Poland, 12-14 June 1997 1997 / p. 431-436

Deep Learning Based Segmentation of Luria's Alternating Series Test to Support Diagnostics of Parkinson's Disease

Valla, Elli; Laur, Henry; Nõmm, Sven; Medijainen, Kadri; Taba, Pille; Toomela, Aaro 2023 International Conference on Machine Learning and Applications (ICMLA) 2023 / p. 1066-1071 : ill <https://doi.org/10.1109/ICMLA58977.2023.00158>

DeepAxe : a framework for exploration of approximation and reliability trade-offs in DNN accelerators

Taheri, Mahdi; Riazati, Mohamad; **Ahmadilivani, Mohammad Hasan; Jenihhin, Maksim; Daneshtalab, Masoud; Raik, Jaan**; Sjödin, Mikael; Lisper, Björn 2023 24th International Symposium on Quality Electronic Design (ISQED) 2023 / 8 p. : ill <https://doi.org/10.1109/ISQED57927.2023.10129353>

Defect-oriented BIST quality analysis

Kruus, Helena; Ubar, Raimund-Johannes; Raik, Jaan BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 153-156 : ill

Defect-oriented fault simulation and test generation in digital circuits

Kuzmicz, W.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes** IEEE ISQED 2001 : proceedings of the IEEE 2001 2nd International Symposium on Quality Electronic Design : March 26-28, 2001, San Jose, California 2001 / p. 365-371 <https://ieeexplore.ieee.org/document/915257>

Defect-oriented library builder and hierarchical test generation

Cibakova, Tatiana; Gramatova, Elena; Kuzmicz, W.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes** IEEE Design and Diagnostics of Electronic Circuits and Systems - IEEE DDECS 2001 : Fourth International Workshop on IEEE Design and Diagnostics of Electronic Circuits and Systems : Győr, Hungary, April 18-20, 2001 2001 / p. 163-168 : ill

Defect-oriented test- and layout-generation for standard-cell ASIC designs

Sudbrock, Joachim; **Raik, Jaan; Ubar, Raimund-Johannes**; Kuzmicz, Wieslaw; Pleskacz, Witold A. Proceedings : DSD'2005 : 8th Euromicro Conference on Digital System Design : Architectures, Methods and Tools : Porto, Portugal, August 30 - September 3, 2005 2005 / p. 79-82 : ill <https://ieeexplore.ieee.org/document/1559781>

Defect-oriented test generation and fault simulation in the environment of MOSCITO

Schneider, Andre; Diener, Karl-Heinz; Gramatova, Elena; Fisherova, Maria; **Ivask, Eero; Ubar, Raimund-Johannes**; Pleskacz, Witold A.; Kuzmicz, W. BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 303-306 : ill

Defect-oriented test generation using probabilistic estimation

Cibakova, Tatiana; Fischerova, Maria; Gramatova, Elena; Kuzmicz, W.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes** Proceedings of the 8th International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2001 : Zakopane, Poland, 21-23 June 2000 2001 / p. 131-136 : ill

Defects, faults and fault models

Gramatova, Elena; Fisherova, Maria; **Ubar, Raimund-Johannes**; Pleskacz, Witold A. Handbook of testing electronic systems 2005 / p. 26-96 : ill

Deformation-burst schemes of 3-piece aerosol containers

Ratas, Kaarin; Peetsalu, Priidu Engineering materials & tribology XXII 2014 / p. 55-58

<https://doi.org/10.4028/www.scientific.net/KEM.604.55> Conference proceedings at Scopus Article at Scopus Conference proceedings at WOS Article at WOS

DefSim: a remote laboratory for studying physical defects in CMOS digital circuits

Pleskacz, Witold A.; Stopjakova, Viera; Borejko, Tomasz; **Jutman, Artur**; Walkanis, Andrzej IEEE transactions on industrial electronics 2008 / 6, p. 2405-2415 : ill

https://www.researchgate.net/publication/3219964_DefSim_A_Remote_Laboratory_for_Studying_Physical_Defects_in_CMOS_Digital_Circuits

DefSim: measurement environment for CMOS defects

Borejko, Tomasz; **Jutman, Artur**; Pleskacz, Witold A.; **Ubar, Raimund-Johannes** 2006 25th International Conference on Microelectronics : Belgrade, Serbia and Montenegro, 14-17 May 2006 : proceedings. Volume 2 2006 / p. 679-682

<https://ieeexplore.ieee.org/document/1651048>

Delay fault investigation at the register transfer level

Fischerova, Maria; Gramatova, Elena BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 141-144

Delay testing of asynchronous NoC interconnects

Bengtsson, Tomas; **Jutman, Artur**; Kumar, Shashi; **Ubar, Raimund-Johannes** Proceedings of the 12th International Conference : Mixed Design of Integrated Circuits and Systems : MIXDES 2005 : Krakow, Poland, 22-25 June, 2005. Vol. 1 of 2 2005 / p. 419-424 : ill

Design and analysis of a DC solid-state circuit breaker for energy router application : [conference paper]

Rahimpour, Saeed 21st International Symposium "Topical problems in the field of electrical and power engineering. Doctoral school of energy and geotechnology. III" : Pärnu, Estonia, June 15-18, 2022 2022 / p. 63-64 : ill https://www.ester.ee/record=b5504019*est

Design and modelling of electric drive in database environment [Electronic resource]

Vodovozov, Valery; Pettai, Elmo; Auväärt, Aivar ISIE08 : 2008 IEEE International Symposium on Industrial Electronics : 30 June - 2 July 2008, Cambridge, United Kingdom 2008 / p. 764-767 : ill. [CD-ROM] <https://ieeexplore.ieee.org/document/4676891>

Design and test technology for dependable systems-on-chip

2011 https://www.ester.ee/record=b4467408*est

Design and testing of new composite from recycled GFRP

Kers, Jaan; Majak, Jüri; Goljandin, Dmitri; Saarna, Mart; Gregor, Andre; Siinmaa, A.; Tall, Kaspar 14th European Conference on Composite Materials : 7-10 June 2010, Budapest, Hungary 2010 / [10] p

Design and testing of sandwich structures with different core materials

Herranen, Henrik; Pabut, Ott; Eerme, Martin; Majak, Jüri; Pohlak, Meelis; Kers, Jaan; Saarna, Mart; Allikas, Georg; Aruniit, Aare Materials science = Medžiagotyra 2012 / p. 45-50 : ill

https://www.researchgate.net/publication/268366546_Design_and_Testing_of_Sandwich_Structures_with_Different_Core_Materials

Design for accelerated testing of DC-link capacitors in photovoltaic inverters based on mission profiles

Sangwongwanich, Ariya; Shen, Yanfeng; **Chub, Andrii; Liivik, Elizaveta; Vinnikov, Dmitri**; Wang, Huai; Blaabjerg, Frede IEEE transactions on industry applications 2021 / p. 741-753 <https://doi.org/10.1109/TIA.2020.3030568> Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Design obfuscation versus test

Farahmandi, Farimah; Sinanoglu, Ozgur; Blanton, Ronald; **Pagliarini, Samuel Nascimento** 2020 IEEE European Test Symposium (ETS) : ETS 2020, May 25 - 29, 2020, Tallinn, Estonia 2020 / 10 p <https://doi.org/10.1109/ETS48528.2020.9131590>

Design of an lddq current sensor built of current devices

Spacek, Vladimir; Molnar, Jozef; Stopjakova, Viera; Weber, Bedrich BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 179-182: ill

Design, optimization and prototyping of small power transformes

Reinap, Avo; Pikner, Rando; Jonikan, Roman; Pärn, Karl; Jakobsons, Edgars; Papickas, Andrius; Dworakowski, Piotr 4th International Symposium Topical Problems of Education in the Field of Electrical and Power Engineering. Doctoral School of Energy and Geotechnology : Kuressaare, Estonia, January 15-20, 2007 2007 / p. 219-225 : ill

The design-build-test-learn cycle for investigating lipid synthesis in oleaginous Rhodotorula toruloides

Rekena, Alina; Gavrilovic, Srdjan; Lahtee, Petri-Jaan The 7th applied synthetic biology in Europe : programme and abstracts 2024 / p. 80 <https://bipeek-resources-onsite-prd.s3.amazonaws.com/54015/ASBE7-Programme-and-Abstract-Book.pdf?v=1730830392>

Design-for-testability for application of external test patterns in a NoC

Govind, Vineeth; **Raik, Jaan** 2nd Workshop on Diagnostic Services in Network-on-Chips - Test, Debug, and On-Line Monitoring, in

A detailed testing procedure of numerical differential protection relay for EHV auto transformer

Ehsan, Umer; Jawad, Muhammad; Javed, Umar; Zaidi, Khuram Shabih; Rehman, Ateeq Ur; **Rassõlkin, Anton**; Althobaiti, Maha M.; Hamam, Habib; **Shafiq, Muhammad** Energies 2021 / art. 8447 <https://doi.org/10.3390/en14248447> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Detection of cracks in a sawblade by eddy current measurements

Mårtens, Olev; Land, Raul; **Metshein, Margus**; **Abdullayev, Anar**; **Vennikas, Henri**; **Le Moullec, Yannick** 2024 19th Biennial Baltic Electronics Conference (BEC) 2024 / 6 p <https://doi.org/10.1109/BEC61458.2024.10737981> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Determining asphalt binder aging by using limiting phase angle temperature

Lill, Kristjan; **Kontson, Karli**; **Aavik, Andrus** Baltic journal of road and bridge engineering 2024 / p. 28-49 <https://doi.org/10.7250/bjrbe.2024-19.647> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Deterministic and probabilistic analyses of the bearing capacity of screw cast in situ displacement piles in silty soils as measured by CPT and SDT

Leetsaar, Lehar; Korkiala-Tanttu, Leena The Baltic journal of road and bridge engineering 2023 / p. 99-127 : ill <https://doi.org/10.7250/bjrbe.2023-18.600> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Deterministic defect-oriented test generation for combinational circuits

Raik, Jaan; **Ubar, Raimund-Johannes**; Sudbrock, Joachim; Kuzmich, Wieslaw; Pleskacz, Witold A. LATW 2005 : 6th IEEE Latin-American Test Workshop : March 30 - April 2, 2005, Salvador, Bahia, Brazil : [digest of papers] 2005 / p. 325-330 : ill

Developing courseware with textbook : hierarchies, field testing, reuse

Henno, Jaak; Kampman, H. On-line learning Euro 98 CD, Cheltenham, 1998 1998 / [5] lk

Development and testing of vertical take-off and landing aerial vehicle with tandem electric ducted fan motor

Pütsep, Kristjan; **Nerep, Tõivo**; **Tiismus, Hans**; **Rassõlkin, Anton** Proceedings of the Estonian Academy of Sciences 2023 / p. 184–193 <https://doi.org/10.3176/proc.2023.2.08> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Development methodology for creating the digital twin for propulsion drive of an electric vehicle = Elektrisõiduki veoajami digitaalse kaksiku arendusmetoodika

Rjabtšikov, Viktor 2024 https://www.ester.ee/record=b5685462*est <https://digikogu.taltech.ee/et/Item/6cbd2dba-76a5-4931-a9f3-53b9d4d87c1e> <https://doi.org/10.23658/taltech.29/2024>

Development of a validation regime for an autonomous campus shuttle

Medrano-Berumen, Christopher; **Malajerdi, Mohsen**; Ilhan Akbas, Mustafa; **Sell, Raivo** IEEE SoutheastCon 2020, Raleigh, NC, 28-29 March 2020 : IEEE Region 3's annual conference : virtual : proceedings 2020 / 8 p <https://doi.org/10.1109/SoutheastCon44009.2020.9249692>

Development of an AR-based application for assembly assistance and servicing

Mahmood, Kashif; **Pizzagalli, Simone Luca**; **Otto, Tauno**; **Symotiuk, Ivan** Procedia CIRP 2024 / p. 638-643 <https://doi.org/10.1016/j.procir.2024.04.017> [Conference proceedings at Scopus](#) [Article at Scopus](#)

Development of high sensitive and rapid test system for simultaneous quantitative and qualitative detection of plant viruses

Raudsepp, Raul; Reintamm, Tõnu; **Järvekülg, Lilian** International Symposium 75 Years of Phytopathological and Resistance Research at Aschersleben, 12-16 June, 1995, Aschersleben, Germany : programme, abstracts, list of participants 1995 / p. P21

Development of regional specialisat[i]on in Estonia: empirical implications for new economic geography hypotheses'

Fainštein, Grigori; **Lubenets, Natalja** Euroopa Liiduga liitumise mõju Eesti majanduspoliitikale : X teadus- ja koostöökongressi ettekanded - artiklid : (Tartu - Värska, 27.-29. juuni 2002) 2002 / lk. 277-284

Development of testing method for smart substations with prosumers

Korõtko, Tarmo; **Merisalu, Ülo**; Mägi, Marek; **Peterson, Kristjan**; **Pettai, Elmo** Journal of microelectronics, electronic components and materials 2014 / p. 185-200 : ill <https://www.dlib.si/details/URN:NBN:SI:doc-N5PGZIFC> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Development of testing procedure for ceramic disc filters

Savolainen, Mikko; Huhtanen, Mikko; Häkkinen, Antti; Ekberg, Bjarne; Hindström, R.; **Kallas, Juha** Minerals engineering 2011 / p. 876-885 : ill

Development of testing procedure for ceramic disc filters [Electronic resource]

Savolainen, Mikko; Häkkinen, Antti; Ekberg, Bjarne; **Kallas, Juha** Physical Separation 09 : Falmouth, Cornwall, UK, June 16-17,

DFT for application of external test patterns in a Network-on-a-Chip

Govind, Vineeth; Raik, Jaan; Ubar, Raimund-Johannes Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK kolmanda aastakonverentsi artiklite kogumik : 25.-26. aprill 2008, Voore külalistemaja 2008 / p. 25-28 : ill

A DFT scheme to improve coverage of hard-to-detect faults in FinFET SRAMs

Cardoso Medeiros, Guilherme; **Gürsoy, Cemil Cem**; Fieback, Moritz; Wu, Lizhou; **Jenihhin, Maksim**; Taouil, Mottaqiallah; Hamdioui, Said 2020 Design, Automation & Test in Europe Conference & Exhibition (DATE), 9-13 March 2020, Grenoble, France : proceedings 2020 / p. 792-797 <https://doi.org/10.23919/DATE48585.2020.9116278>

DFT-based external test and diagnosis of mesh-like networks on chips = Testitavusel põhinev välise testi ja diagnoosi meetod kahemõõtmelistele kiipvõrkudele

Govind, Vineeth 2009 <https://digi.lib.ttu.ee/ii/?454> https://www.ester.ee/record=b2539211*est

Diagnostic modeling of digital systems with low- and high-level decision diagrams

Ubar, Raimund-Johannes LATW2013 : 14th IEEE Latin-American Test Workshop, Cordoba, Argentina, April 3-5, 2013 : [proceedings] 2013 / [1] p

Diagnostic modeling of digital systems with multi-level decision diagrams

Ubar, Raimund-Johannes; Raik, Jaan; Jutman, Artur; Jenihhin, Maksim Design and test technology for dependable systems-on-chip 2011 / p. 92-118 : ill https://www.researchgate.net/publication/344994231_Diagnostic_Modeling_of_Digital_Systems_with_Multi-Level_Decision_Diagrams

Digital electronics design and test at Computer Engineering Department of Tallinn University of Technology

Ubar, Raimund-Johannes; Raik, Jaan; Jutman, Artur; Ellervee, Peeter The house magazine : the parliamentary weekly 2006 / 1198, p. 42 : ill

Digital realization of retuning fractional-order controllers for an existing closed-loop control system

Tepljakov, Aleksei; Petlenkov, Eduard; Gonzalez, Emmanuel A.; **Belikov, Juri** Journal of circuits, systems, and computers 2017 / art. 1750165, p. 1-26 <https://doi.org/10.1142/S0218126617501651> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Digital test in WEB-based environment

Ivask, Eero 2006 https://www.ester.ee/record=b2158119*est

Digitally controlled reference impedance device for test and calibration of the bio-impedance measurement system (BIMS) in a networked environment

Birjukov, Andrei; Krivošei, Andrei; Parve, Toomas 13th International Conference on Electrical Bioimpedance and 8th Conference on Electrical Impedance Tomography 2007 : ICEBI2007 : August 29th - September 2nd 2007, Graz, Austria 2007 / p. 276-279 https://link.springer.com/chapter/10.1007/978-3-540-73841-1_73

Direct eddy current method for volumetric flaws of cylindrical shape

Koliškina, Valentina; Kolyshkin, Andrei; **Gordon, Rauno; Märten, Olev** ECCOMAS Congress 2016 : VII European Congress on Computational Methods in Applied Sciences and Engineering : proceedings. Vol. 1 2016 / p. 7659-7665 : ill <https://www.eccomas2016.org/proceedings/pdf/5264.pdf>

Distributed fault simulation with collaborative load balancing for VLSI circuits

Ivask, Eero; Devadze, Sergei; Ubar, Raimund-Johannes Scalable computing : practice and experience 2011 / p. 153-163 : ill

A DSP-based EBI, ECG and PPG measurement platform

Abdullayev, Anar; Rist, Marek; Märten, Olev; Metshein, Margus; Larras, Benoit; Frappe, Antoine; Gautier, Antoine; **Min, Mart**; John, Deepu; Cardiff, Barry; **Krivošei, Andrei; Annus, Paul** IEEE transactions on instrumentation and measurement 2023 / art. 2007808, 8 p <https://doi.org/10.1109/TIM.2023.3320771> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

DTRON : a tool for distributed model-based testing of time critical applications

Anier, Aivo; Vain, Jüri; Tsiopoulos, Leonidas Proceedings of the Estonian Academy of Sciences 2017 / p. 75-88 : ill <https://doi.org/10.3176/proc.2017.1.08> http://www.ester.ee/record=b2355998*est [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Eddy current testing models for the analysis of corrosion effects in metal plates

Koliškina, Valentina; Kolyshkin, Andrei; **Gordon, Rauno; Märten, Olev** 19th European Conference on Mathematics for Industry : June, 13-17, 2016, Santiago de Compostela (Spain) : book of abstracts 2016 / p. 200 <http://dx.doi.org/10.15304/cc.2016.968>

Eesti laste kõne põhitooni ja vokaaliruumi areng

Meister, Lya; Meister, Einar Eesti-uuringute Tippkeskuse aastakonverents ja Kreutzwaldi päevade 60. konverents "Suuline ja kirjalik kultuuris: põimimised ja põrkumised" : 12. ja 13. detsembril 2016 Eesti Kirjandusmuuseumis : ajakava ja ettekannete kokkuvõtted 2016 / lk. 27-28 <http://www.digar.ee/viewer/et/nlib-digar:297946/265944/page/23>

Eesti päritolu koroonaviiruse antikehade kiirtest on valmis saanud [Võrguväljaanne]
Jürisoo, Lauri forte.delfi.ee 2021 ["Eesti päritolu koroonaviiruse antikehade kiirtest on valmis saanud"](https://www.delfi.ee/et/teadus/Eesti-paritolu-koroonaviiruse-antikehade-kiirtest-on-valmis-saanud)

Eesti teadlaste leiutis: uus koroonaviiruse kiirtest ootab heakskiitu ja otsib tootjat
Ladva, Asso Õhtuleht 2020 / Lk. 5 <https://dea.digar.ee/article/ohuleht/2020/12/07/2.12>

Eesti tudengid testisid esimesena maailmas arvutihiire täpsust : [TTÜ tootearenduse tudengid Birthe Matsi ja Triin Toon]
Postimees 2005 / lk. 9

Eesti-Saksa ettevõtte arendas laboritäpsusega koroonaviiruse kiirtesti
Eesti Elu : [Kanada ajaleht] 2020 / lk. 3 <https://eesti.elu.com/et/eesti-elu/paberleht/11209-eesti-elu-nr-48-4-detsember-2020-digileht>

Effect of hard cyclic viscoplastic deformation on hardening/softening of SPD-copper
Kommel, Lembit TMS 2004 : 133rd Annual Meeting & Exhibition : The Minerals, Metals & Materials Society welcomes you to the technical program for the 133rd TMS Annual Meeting & Exhibition, to be held March 14-18, 2004, in Charlotte, North Carolina 2004 / p. 258
https://www.researchgate.net/publication/360806886_Effect_of_Hard_Cyclic_Viscoplastic_Deformation_on_the_Microstructure_Mechanical_Properties_and_Electrical_Conductivity_of_Cu-Cr_Alloy

Effect of hard cyclic viscoplastic deformation on the microstructure, mechanical properties, and electrical conductivity of Cu-Cr alloy
Kommel, Lembit; Huot, Jacques; Omranpour Shahreza, Babak Journal of Materials Engineering and Performance 2022 / p. 9690-9702 <https://doi.org/10.1007/s11665-022-06997-w> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Effect of N₂ and CO₂ on shale oil from pyrolysis of Estonian oil shale
Mozaffari, Sepehr; Järvik, Oliver; Baird, Zachariah Steven International journal of coal preparation and utilization 2022 / p. 2908-2922 <https://doi.org/10.1080/19392699.2021.1914025> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Effect of quality properties of added gluten on the texture and sensory properties of rye and buckwheat breads
Traksmäa, Anna; Kaleda, Aleksei; Nurme, Britta; Laos, Katrin Agronomy research 2023 / 13 p. : ill <https://doi.org/10.15159/ar.23.082>
[Journal metrics at Scopus](#) [Article at Scopus](#)

Effect of strain rate, volume fraction of particles and temperature on fracture mechanism in Al-Al₄C₃ systems
Velgosova, Oksana; Besterici, Michal; Kovac, Ladislav; **Kulu, Priit**; Huang, Song-Jeng Kovove materialy = Metallic materials 2011 / p. 361-367 : ill
[https://www.researchgate.net/publication/273435866_Effect_of_strain_rate_volume_fraction_of_particles_and_temperature_on_fracture_mechanism_in_Al-Al₄C₃ systems](https://www.researchgate.net/publication/273435866_Effect_of_strain_rate_volume_fraction_of_particles_and_temperature_on_fracture_mechanism_in_Al-Al4C3_systems)

Efficient at-speed interconnect BIST and diagnosis framework
Jutman, Artur Informal Digest of Papers : 10 IEEE European Test Symposium : Tallinn, Estonia, May 22-25, 2005 2005 / p. 257-258 : ill https://artiklid.elnet.ee/record=b1018804*est

Efficient hierarchical approach to test generation for digital systems
Ubar, Raimund-Johannes; Raik, Jaan IEEE ISQED 2000 : proceedings of the IEEE 2000 1st International Symposium on Quality Electronic Design : March 20-22, 2000, San Jose, California 2000 / p. 189-195 : ill <https://ieeexplore.ieee.org/document/838873>

Ein universeller Weg zur Automatisierung des Testentwurfs für digitale Objekte
Ubar, Raimund-Johannes; Lohuaru, Tõnu Fehler in Automaten 1989 / S. 16-30 : Ill

E-learning tool and exercises for teaching digital test
Ubar, Raimund-Johannes; Orasson, Elmet Proceedings of the 2nd IEEE Conference on Signals, Systems, Decision and Information Technology : Sousse, Tunisia, 2003 2003 / [6] p. : ill <https://pld.ttu.ee/dildis/publications/E-Learning%20tool%20and%20Exercises.pdf>

E-learning tools for digital test
Devadze, Sergei; Gorjachev, R.; Jutman, Artur; Orasson, Elmet; Rosin, Vjatšeslav; **Ubar, Raimund-Johannes** Proc. III International Conference "Distance Learning - Educational Sphere of XXI Century" : Minsk, Belorussia, 2003 2003 / p. 336-342

Electrical conductivity and mechanical properties of Cu-0.7wt% Cr and Cu-1.0wt% Cr alloys processed by severe plastic deformation
Kommel, Lembit; Pokatilov, Andrei IOP conference series : materials science and engineering 2014 / p. 1-7 : ill
<https://doi.org/10.1088/1757-899X/63/1/012169> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Electronics design and test

Ubar, Raimund-Johannes; Kruus, Margus; Rang, Toomas Public service review : European Union. 13 2007 / p. 52-53

Embedded synthetic instruments for board-level testing

Jutman, Artur; Devadze, Sergei; Aleksejev, Igor; Wenzel, Thomas Proceedings : 2012 17th IEEE European Test Symposium (ETS) : May 28th–June 1st, 2012, Annecy, France 2012 / 1 p. : ill <https://ieeexplore.ieee.org/document/6233044>

Embedded test processors (ETP)

Petersen, Kim; Magnhagen, Bengt; Linden, Henric BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 89-92: ill

Energy efficiency profiles for unmanned ground vehicles

Väljaots, Eero; Sell, Raivo Proceedings of the Estonian Academy of Sciences 2019 / p. 55–65 : ill

<https://doi.org/10.3176/proc.2019.1.04> http://www.kirj.ee/public/proceedings_pdf/2019/issue_1/proc-2019-1-55-65.pdf [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Energy-efficient multi-fragment Markov model guided online model-based testing for MPSoC

Vain, Jüri; Tsiopoulos, Leonidas; Kharchenko, Vyacheslav; **Apneet Kaur; Jenihhin, Maksim; Raik, Jaan; Nömm, Sven** Green IT Engineering: Social, Business and Industrial Applications 2019 / p. 273-297 https://doi.org/10.1007/978-3-030-00253-4_12 [Article collection at Scopus](#) [Article at Scopus](#)

Enhancing hierarchical ATPG with a functional fault model for multiplexers [Electronic resource]

Raik, Jaan; Ubar, Raimund-Johannes 7th IEEE Workshop on Design and Diagnostics of Electronic Circuits and Systems : April 18-21, 2004, Stará Lesná, Slovakia : proceedings 2004 / p. 219-222 : ill. [CD-ROM] <https://www.semanticscholar.org/paper/Enhancing-Hierarchical-Atpg-with-a-Functional-Fault-Raik-Ubar/b42e913ac070fd774df97bd644c4e6220704f8d4>

Enhancing the aspect robustness score of the HAABSA++ model using adversarial training

Agha, Milad; Frasinicar, Flavius; Zhu, Beilly; **Robal, Tarmo** Web Engineering : 25th International Conference, ICWE 2025, Delft, The Netherlands, June 30 – July 3, 2025 : Proceedings 2026 / p. 89-103 <https://doi.org/10.1007/978-3-031-97207-2> https://link.springer.com/chapter/10.1007/978-3-031-97207-2_7

Environment for the analysis of functional self-test quality in digital systems

Ubar, Raimund-Johannes; Kostin, Sergei; Kruus, Helena; Aarna, Margit; Devadze, Sergei Proceedings of the Estonian Academy of Sciences 2014 / p. 151-162 : ill https://artiklid.elnet.ee/record=b2673964*est <https://doi.org/10.3176/proc.2014.2.05> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Erosion testing of refractory cermets at high temperature [Electronic resource]

Antonov, Maksim; Hussainova, Irina Proceedings of 12th Nordic Symposium in Tribology : NORDTRIB 2006 : Helsingor, Denmark, 7-9 June 2006 2006 / [10] p. [CD-ROM]

Erosive wear of boiler steels by sand and ash

Huttunen-Saarivirta, E.; Kinnunen, H.; Tuiremo, J.; Uusitalo, M.; **Antonov, Maksim** Wear 2014 / p. 213-224 : ill <https://doi.org/10.1016/j.wear.2014.06.007> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Erratum: Cognitive disorders in patients with chronic kidney disease: specificities of clinical assessment (Nephrol Dial Transplant DOI: 10.1093/ndt/gfab262)

Pépin, Marion; Ferreira, Ana Carina; Arici, Mustafa; **Bachmann, Maie;** Barbieri, Michelangela; Bumblyte, Inga Arune; Carriazo, Sol; Delgado, Pilar; Garneata, Liliana; Giannakou, Konstantinos Nephrology dialysis transplantation 2022 / 1 p <https://doi.org/10.1093/ndt/gfab339> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Ettevõtte sisekontrollisüsteem ja selle hindamine auditeerimisel

Leppik, Enn Arvestuse ja maksunduse aktuaalsed probleemid : konverents 1997 / lk. 94-96 https://www.ester.ee/record=b1293554*est

Ettevõtted saavad tooteid ja teenuseid testida TalTechi asjade interneti ja 5G platvormil

Mente et Manu 2020 / lk. 11 <https://dea.digar.ee/cgi-bin/dea?a=is&oid=AKmenteetmanu202011&type=staticpdf>

European Test Symposium : ETS 2005 : 22-25 May 2005, Tallinn, Estonia : proceedings

Cantarella, JD 2005 https://www.ester.ee/record=b2300865*est

Evaluating cybersecurity-related competences through serious games

Mäses, Sten 19th Koli Calling Conference on Computing Education Research Koli Calling 2019 : November 21-24, 2019, Koli, Finland : proceedings 2019 / 2 p <https://doi.org/10.1145/3364510.3366163> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Evaluation of some mechanical and physical properties of 'Oriented Strand Board (OSB/3)' following cyclic accelerated

aging tests

Lille, Harri; **Kiviste, Mihkel**; Telling, Renar; Leppik, Taimo; Virro, Indrek; Kask, Regino European journal of wood and wood products 2022 / p. 731–740 <https://doi.org/10.1007/s00107-022-01803-9>

Evaluation of VRLA battery under overcharging : model for battery testing

Tenno, Ander; Tenno, Robert; Suintio, Teuvo Journal of power sources 2002 / p. 65-82
<https://www.sciencedirect.com/science/article/pii/S0378775302002768>

Evolutionary approach to the functional test generation for digital circuits

Skobtsov, Y.A.; Ivanov, D.E.; Skobtsov, V.Y.; **Ubar, Raimund-Johannes** BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 229-232 : ill

Exact static compaction of independent test sequences

Raik, Jaan; **Jutman, Artur**; **Ubar, Raimund-Johannes** BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 315-318 : ill

Executable black-box tester model synthesis from a non-deterministic EFSM of the system

Kull, Andres; **Raiend, Kullo**; **Vain, Jüri** Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK teise aastakonverentsi artiklite kogumik : 11.-12. mai 2007, Viinistu kunstimuuseum 2007 / lk. 105-108

Experiences of lexicographers and computer scientists in validating Estonian Wordnet with test patterns

Lohk, Ahti; Orav, Heili; Vare, Kadri; **Võhandu, Leo** Proceedings of the Eighth Global WordNet Conference : Bucharest, Romania, January 27-30, 2016 2016 / p. 184-191 : ill <http://gwc2016.racai.ro/>

Experiences with steady-state PMU compliance testing using standard relay testing equipment

Almas, Muhammad Shoaib; **Kilter, Jako**; Vanfretti, Luigi PQ2014 : the 9th International 2014 Electric Power Quality and Supply Reliability Conference (PQ) : June 11-13, 2014, Rakvere, Estonia : proceedings 2014 / p. 103-110 : ill

Experimental comparison of different diagnosis algorithms in the BIST environment

Ubar, Raimund-Johannes; **Kostin, Sergei**; **Raik, Jaan**; **Kruus, Margus** Proceedings of the 16th IASTED International Conference on Applied Simulation and Modelling : August 29-31, 2007, Palma de Mallorca, Spain 2007 / p. 271-276 : ill
https://www.researchgate.net/publication/262275431_Experimental_comparison_of_different_diagnosis_algorithms_in_the_BIST_environment

Experimental determination of equivalent circuit parameters for a synchronous generator

Naseer, Muhammad Usman; **Asad, Bilal**; **Shams Ghahfarokhi, Payam**; **Kallaste, Ants**; **Vaimann, Toomas**; **Rassõlkin, Anton** 2021 IEEE Open Conference of Electrical, Electronic and Information Sciences (eStream): proceedings of the conference, April 22, 2021, Vilnius, Lithuania 2021 / 7 p. : ill <https://doi.org/10.1109/eStream53087.2021.9431442>

Experimental determination of sound transmission in turbo-compressors : SAE Tech. paper no.2009-01-2045

Rämmal, Hans; Abom, Mats SAE Technical Papers 2009 / [7] p <https://www.diva-portal.org/smash/record.jsf?pid=diva2%3A750030&dswid=9882>

Experimental study on the influence of process variable on the performance of a horizontal belt filter

Häkkinen, Antti; Huhtanen, Mikko; Ekberg, Bjørne; **Kallas, Juha** FILTECH 2009, Wiesbaden, October 13-15, 2009 2009 / ? p
https://www.researchgate.net/publication/289851256_Experimental_study_of_the_influence_of_process_variables_on_the_performance_of_a_horizontal_belt_filter

Experimental testing of exterior wall mounted mechanical ventilation exhaust air outlet devices

Palmiste, Ülar; **Meier, Tauno**; **Kurnitski, Jarek**; **Voll, Hendrik** E3S Web Conference: Cold Climate HVAC and Energy 2021 2021 / art. 02001, 8 p. : ill https://doi.org/10.1051/e3sconf/202124602001_Conference_Proceedings_at_Scopus_Article_at_Scopus_Article_at_WOS

Exploiting aspects in model-based testing

Sarna, Külli; **Vain, Jüri** FOAL'12 : proceedings of the eleventh workshop on Foundations of Aspect-Oriented Languages : March 26, 2012, Potsdam, German 2012 / p. 45-47 : ill https://www.researchgate.net/publication/254007794_Exploiting_aspects_in_model-based_testing

An external diagnosis method for network-on-a-chip

Raik, Jaan; Govind, Vineeth; **Ubar, Raimund-Johannes** IEEE/ACM Design Automation and Test in Europe, Workshop on Diagnostic Services in Networks-on-Chips - Test, Debug and On-line Monitoring : April 16-20, 2007, Nice, France 2007 / [2] p. : ill

Fast and efficient static compaction of test sequences based on greedy algorithms

Raik, Jaan; **Jutman, Artur**; **Ubar, Raimund-Johannes** IEEE Design and Diagnostics of Electronic Circuits and Systems - IEEE DDECS 2001 : Fourth International Workshop on IEEE Design and Diagnostics of Electronic Circuits and Systems : Győr, Hungary, April 18-20, 2001 2001 / p. 117-122 https://slideplayer.com/slide/9971880/#google_vignette

Fast and efficient static compaction of test sequences using bipartite graph representations

Markus, Antti; **Raik, Jaan**; **Ubar, Raimund-Johannes** ECS'99 : proceedings of the 2nd Electronic Circuits and Systems

Fast extended test access via JTAG and FPGAs

Devadze, Sergei; Jutman, Artur; Alekseyev, Igor; Ubar, Raimund-Johannes International Test Conference 2009 : November 1 - November 6, 2009, Austin Convention Center, Austin, Texas USA : proceedings 2009 / p. 1-7 : ill
<http://dx.doi.org/10.1109/TEST.2009.5355668>

Fast fault emulation for synchronous sequential circuits

Raik, Jaan; Ellervee, Peeter; Tihomirov, Valentin; Ubar, Raimund-Johannes Proceedings of East-West Design & Test Workshop (EWDWTW'04) : Yalta, Alushta, Crimea, Ukraine, September 23-26, 2004 2004 / p. 35-40
<https://citeseerx.ist.psu.edu/document?repid=rep1&type=pdf&doi=a6eb712498a5f23db3f95ad66bada257c21e96f0>

Fast identification of true critical paths in sequential circuits

Ubar, Raimund-Johannes; Kostin, Sergei; Jenihhin, Maksim; Raik, Jaan; Jürimägi, Lembit Microelectronics reliability 2018 / p. 252-261 : ill <https://doi.org/10.1016/j.microrel.2017.11.027> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Fast static compaction of test sequences using implications and greedy search

Raik, Jaan; Jutman, Artur; Ubar, Raimund-Johannes ETW 2001 : IEEE European Test Workshop : Stockholm, May 29 June 1, 2001 : informal digest 2001 / p. 207-209 : ill <https://www.semanticscholar.org/paper/Fast-Static-Compaction-of-Test-Sequences-using-and-Raik-Jutman/3a7a8ddda6e63d3e2fde0c8650d4518851746221>

Fast static compaction of tests composed of independent sequences : basic properties and comparison of methods

Raik, Jaan; Jutman, Artur; Ubar, Raimund-Johannes The 9th IEEE International Conference on Electronics, Circuits and Systems : ICECS 2002 : September 15-18, 2002, Dubrovnik, Croatia. Volume II 2002 / p. 445-448 : ill
<http://dx.doi.org/10.1109/ICECS.2002.1046190> <https://ieeexplore.ieee.org/document/1046190>

Fast test cost calculation for hybrid BIST in digital systems

Orasson, Elmet; Raidma, Rein; Ubar, Raimund-Johannes; Jervan, Gert; Peng, Zebo Euromicro Symposium on Digital Systems Design : [Architectures, Methods and Tools : DSD 2001] : September 4-6, 2001, Warsaw, Poland : proceedings 2001 / p. 318-325 : ill <https://www.semanticscholar.org/paper/Fast-test-cost-calculation-for-hybrid-BIST-in-Orasson-Raidma/5aafcd5a18c2aabf0ad20cac10af10727f3c58f>

Fast test pattern generation for sequential circuits using decision diagram representations

Raik, Jaan; Ubar, Raimund-Johannes Journal of electronic testing : theory and applications (JETTA) 2000 / 3, p. 213-226 : ill
<https://link.springer.com/article/10.1023/A:1008335130158>

Fault collapsing with linear complexity in digital circuits

Ubar, Raimund-Johannes; Mironov, Dmitri; Raik, Jaan; Jutman, Artur Proceedings of 2010 IEEE International Symposium on Circuits and Systems (ISCAS 2010) : 30 May - 2 June 2010, Paris, France 2010 / p. 653-656 : ill
<https://ieeexplore.ieee.org/document/5537504>

Fault diagnosis in the BIST environment based on bisection of detected faults

Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan LATW2007 : 8th IEEE Latin-American Test Workshop : March 11-14, 2007, Cuzco, Peru 2007 / [6] p. : ill

Fault effect reasoning in digital systems by topological view on low- and high-level decision diagrams

Ubar, Raimund-Johannes Вестник Томского государственного университета. Управление, вычислительная техника и информатика 2014 / p. 99-113 : ill http://journals.tsu.ru/informatics/&journal_page=archive&id=923&article_id=12107

Fault model and test synthesis for RISC-processors

Ubar, Raimund-Johannes; Markus, Antti; Jervan, Gert; Raik, Jaan BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 229-232: ill

Fault modeling and test generation with low- and high-level decision diagrams

Ubar, Raimund-Johannes 24. GI/GMM/ITG-Workshop : Testmethoden und Zuverlässigkeit von Schaltungen und Systemen 2012 / p. 1-12

Fault oriented test pattern generation for sequential circuits using genetic algorithms

Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes IEEE European Test Workshop 2000 / p. 319-320

Fault simulation and code coverage analysis of RTL designs using high-level decision diagrams = Rikete simuleerimine ja koodikatte analüüs register-siirde tasemel kasutades kõrgtaseme otsustusdiagramme

Reinsalu, Uljana 2013 https://www.ester.ee/record=b2963595*est

Fault simulation of digital systems = Digitaalsüsteemide rikete simuleerimine

Devadze, Sergei 2009 <https://digi.lib.ttu.ee/i/?445> https://www.ester.ee/record=b2508727*est

Feasibility of structurally synthesized BDD models for test generation

Raik, Jaan; Ubar, Raimund-Johannes Proceedings of the IEEE European Test Workshop, Barcelona, Spain, May 27-29, 1998
1998 / p. 145-146

Fenoolide ning klorofenoolide osoonimise produktide toksilisuse uurimine Daphnia magna testiga

Trapido, Marina; **Veressinina, Jelena** XXIII Eesti keemiapäevad : teaduskonverentsi ettekannete referaadid 1997 / lk. 140

Field work in the role of teaching and research of rock properties

Karu, Veiko; Kolats, Margit; Väizene, Vivika; Anepaio, Ain; **Valgma, Ingo** 5th International Symposium "Topical Problems in the Field of Electrical and Power Engineering". Doctoral School of Energy and Geotechnology : Kuressaare, January 14-19, 2008 2008 / p. 66-70 : ill

Fire tests on glued-laminated timber beams with specific local material properties

Fahrni, Reto; Klippel, Michael; **Just, Alar**; Ollinoc, A.; Frangi, Andrea Fire safety journal 2019 / p. 161-169 : ill
<https://doi.org/10.1016/j.firesaf.2017.11.003> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Fire-separating assemblies

Werther, Norman; Dagenais, Christian; **Just, Alar**; Wade, Colleen Fire safe use of wood in buildings : global design guide 2022 / p. 193-226 : ill <https://doi.org/10.1201/9781003190318-6>

First results from a benchmarking of quality control frameworks

Kedar, A.; **Sein, Sander** Life cycle analysis and assessment in civil engineering: towards an integrated vision : proceedings of the Sixth International Symposium on Life-Cycle Civil Engineering (IALCCE 2018), 28-31 October 2018, Ghent, Belgium 2019 / p. 1799-1804 : ill <https://www.taylorfrancis.com/books/9781351857574> <https://doi.org/10.1201/9781315228914>

FOPID controllers and their industrial applications: a survey of recent results

Tepljakov, Aleksei; Alagoz, Baris Baykant; **Petlenkov, Eduard** IFAC-PapersOnLine 2018 / p. 25-30
<https://doi.org/10.1016/j.ifacol.2018.06.014> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Foreword

Ubar, Raimund-Johannes; Prinetto, Paolo; Al-Hashimi, Bashir Informal Digest of Papers : 10 IEEE European Test Symposium : Tallinn, Estonia, May 22-25, 2005 2005 / p. III

Formal Techniques for Networked and Distributed Systems - FORTE 2007 : 27th IFIP WG 6.1 International Conference : Tallinn, Estonia, June 27-29, 2007 : proceedings

Derrick, John; **Vain, Jüri** 2007 https://www.ester.ee/record=b2286028*est

FPGA design flow with automated test generation

Elst, G.; Diener, Karl-Heinz; **Ivask, Eero**; **Raik, Jaan**; **Ubar, Raimund-Johannes** Proc. of German 11th Workshop on Test Technology and Reliability of Circuits and Systems : Potsdam, 1999 1999 / p. 120-123
<https://masters.donntu.ru/2010/fknt/masyakin/library/article7.pdf>

FPGA-based embedded virtual instrumentation = FPGA-sisesed virtuaalsed test- ja mõõtevahendid

Aleksejev, Igor 2013 http://www.ester.ee/record=b2927687*est

FPGA-based fault emulation of synchronous sequential circuits

Ellervee, Peeter; **Raik, Jaan**; **Tammemäe, Kalle**; **Ubar, Raimund-Johannes** IET computers and digital techniques 2007 / 2, p. 70-76 : ill <https://ieeexplore.ieee.org/abstract/document/1423822>

FPGA-based synthetic instrumentation for board test

Aleksejev, Igor; **Jutman, Artur**; **Devadze, Sergei**; **Odintsov, Sergei**; Wenzel, Thomas Proceedings : International Test Conference 2012 2012 / p. 1-10 : ill <https://ieeexplore.ieee.org/document/6401571>

Fracture micromechanism of Cu-Cr-Zr system by "in-situ tensile test in SEM"

Besterci, Michal; Ivan, Jozef; **Kulu, Priit**; **Arensburger, Daniil**; Velgosova, Oksana Acta metallurgica Slovaca 2000 / p. 20-24

Fracture micromechanism of Cu-Cr-Zr system by "in-situ tensile test in SEM"

Besterci, Michal; Ivan, Jozef; **Kulu, Priit**; **Arensburger, Daniil** Proceedings of the 2nd International Conference, 27-29th April 2000, Tallinn, Estonia / DAAAM International Vienna, DAAAM National Estonia 2000 / p. 193-196 : ill

A framework for improving web application user interfaces through immediate evaluation

Marenkov, Jevgeni; **Robal, Tarmo**; **Kalja, Ahto** Databases and information systems IX : selected papers from the twelfth International Baltic Conference, DB&IS 2016 2016 / p. 283-296 : ill <https://doi.org/10.3233/978-1-61499-714-6-283> [Article collection metrics at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Fully synchronized acoustomechanical testing of skin : biomechanical measurements of nonclassical nonlinear parameters

Lints, Martin; Dos Santos, Serge; Kozena, Colette; Kus, Vaclav; **Salupere, Andrus** 24th International Congress on Sound and Vibration 2017 (ICSV 24) : London, United Kingdom, 23-27 July 2017. Vol. 3 2017 / p. 1970-1977 : ill https://www.iiav.org/archives_icsv_last/2017_icsv24/content/papers/papers/full_paper_867_20170403135841549.pdf

Functional built-in self-test for processor cores in SoC

Ubar, Raimund-Johannes; Indus, Viljar; **Kalmend, Oliver;** **Evertson, Teet;** **Orasson, Elmet** 30th IEEE NORCHIP Conference : Copenhagen, Denmark, November 12-14, 2012 2012 / p. 1-4 : ill <https://ieeexplore.ieee.org/document/6403148>

Functional self-test of high-performance pipe-lined signal processing architectures

Gorev, Maksim; **Ubar, Raimund-Johannes;** **Ellervee, Peeter;** **Devadze, Sergei;** **Raik, Jaan;** **Min, Mart** Microprocessors and microsystems 2015 / p. 909-918 : ill <https://doi.org/10.1016/j.micpro.2014.11.002> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Functional test generation for finite state machines

Ubar, Raimund-Johannes; **Brik, Marina;** **Jutman, Artur;** **Raik, Jaan;** Bengtsson, Tomas; Kumar, Shashi BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 205-208 : ill

Functional test program generation for digital systems

Ubar, Raimund-Johannes; Dušina, Julia; **Krupnova, Helena;** **Storožev, Sergei;** **Zaugarov, Viktor** Testmethoden und Zuverlässigkeit von Schaltungen und Systemen : proceedings of the 6th workshop, Vaals (Niederlande), March 6-8, 1994 1994 / p. 14-18: ill

GA-based test generation for sequential circuits

Brik, Marina; **Raik, Jaan;** **Ubar, Raimund-Johannes;** **Ivask, Eero** Proceedings of East-West Design & Test Workshop (EWDWTW'04) : Yalta, Alushta, Crimea, Ukraine, September 23-26, 2004 2004 / p. 30-34

Generating directed tests for C programs using RTL ATPG

Raik, Jaan; Drenkhan, Tiia; **Jenihhin, Maksim;** **Viilukas, Taavi;** **Karputkin, Anton;** **Tšepurov, Anton;** **Ubar, Raimund-Johannes** Proceedings of the IEEE 13th Workshop on RTL and High Level Testing (WRTL'12) 2012 / p. 1-6

Generating optimal test cases for real-time systems using DIVINE model checker

Pal, Deepak; **Vain, Jüri** BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 99-102 : ill http://www.estee.ee/record=b2150914*est

Generating TTCN-3 test cases from EFSM models of reactive software using model checking

Ernits, Juhan-Peep; **Kull, Andres;** Raiend, Kullo; **Vain, Jüri** Informatik 2006 - Informatik für Menschen : proceedings : Beiträge der 36. Jahrestagung der Gesellschaft für Informatik e.V.(GI) : 2.bis 6.Oktober in Dresden 2006 / p. 241-248 <https://www.semanticscholar.org/paper/Generating-TTCN-3-Test-Cases-from-EFSM-Models-of-Ernits-Kull/b626c55f607826939345eec24e985adf268b15e5>

Generation of tests for the localization of single gate design errors in combinational circuits using the stuck-at fault model

Ubar, Raimund-Johannes; Borrione, Dominique XI Brazilian Symposium on Integrated Circuit Design, September 30 - October 3, 1998, Rio de Janeiro, Brazil : proceedings 1998 / p. 51-54 <https://ieeexplore.ieee.org/document/715409>

A generic synthesizable NoC switch with a scalable testbench

Govind, Vineeth; **Raik, Jaan;** **Ubar, Raimund-Johannes** BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 91-94 : ill

A global methodology for test program generation starting from high level specifications

Storojev, Sergei; Leveugle, Regis; Saucier, Gabriele BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 305-311: ill https://www.estee.ee/record=b2150914*est

A global survey of standardization and industry practices of automotive cybersecurity validation and verification testing processes and tools

Roberts, Andrew James; Marksteiner, Stefan; Soyuturk, Mujdat; Yaman, Berkay; Yang, Yi SAE international journal of connected and automated vehicles 2023 / art. 12-07-02-0013 <https://doi.org/10.4271/12-07-02-0013> [Journal metrics at Scopus](#) [Article at Scopus](#)

Guardbands in random testing

Kemnitz, Günter BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 85-88: ill

Guardbands in random testing

Guest editorial

Min, Mart Proceedings of the Estonian Academy of Sciences. Engineering 2001 / 4, p. 251-252

[**H. Bleeker, P. Van Den Eijnden, F. De Jong. Boundary-scan test. Boston : Kluwer Academic, 1993. 225 p. : book review**]
Ubar, Raimund-Johannes Engineering applications of artificial intelligence 1994 / p. 86-87 https://www.ester.ee/record=b1200126*est

Handbook of testing electronic systems

Novak, Ondrej; Gramatova, Elena; **Ubar, Raimund-Johannes; Jutman, Artur; Raik, Jaan** 2005
https://www.ester.ee/record=b2102523*est

Hierarchical analysis of short defects between metal lines in CMOS IC

Pleskacz, Witold A.; **Jenihhin, Maksim; Raik, Jaan; Rakowski, Michal; Ubar, Raimund-Johannes; Kuzmich, Wieslaw**
Proceedings : 11th EUROMICRO Conference on Digital System Design : Architectures, Methods and Tools : (DSD 2008) :
September 3-5, 2008, Parma, Italy 2008 / p. 729-734 : ill <https://ieeexplore.ieee.org/document/4669309>

Hierarchical approach to test generation for digital systems at system, circuit and defect levels

Ubar, Raimund-Johannes 45. Internationales Wissenschaftliches Kolloquium, 04.-06.10.2000 : Tagungsband 2000 / S. 711-716 : ill

A hierarchical automatic test pattern generator based on using alternative graphs

Brik, Marina; Jervan, Gert; Markus, Antti; Raik, Jaan; Ubar, Raimund-Johannes Proceedings of the 4th International Workshop
Mixed Design of Integrated Circuits and Systems : MIXDES'97 : Poznan, Poland, 12-14 June 1997 / p. 415-420

Hierarchical concurrent test generation for synchronous sequential circuits

Ubar, Raimund-Johannes; Brik, Marina Proceedings of the 7th International Conference Mixed Design of Integrated Circuits and
Systems : MIXDES 2000 : Gdynia, Poland, 15-17 June 2000 / p. 533-538 : ill

Hierarchical defect-oriented fault simulation for digital circuits

Blyzniuk, M.; Cibakova, Tatiana; Gramatova, Elena; Kuzmich, W.; Lobur, M.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes**
IEEE European Test Workshop : 23-26 May 2000, Cascais, Portugal : ETW 2000 : proceedings 2000 / p. 69-74 : ill
<https://ieeexplore.ieee.org/document/873781>

Hierarchical identification of untestable faults in sequential circuits

Raik, Jaan; Ubar, Raimund-Johannes; Krivenko, Anna; Kruus, Margus 10th Euromicro Conference on Digital System Design
Architectures, Methods and Tools, DSD 2007 : 29-31 August 2007, Lübeck, Germany : proceedings 2007 / p. 668-671 : ill
<http://dx.doi.org/10.1109/DSD.2007.4341539>

Hierarchical test generation based on alternative graph model

Ubar, Raimund-Johannes Proceedings of the Second Workshop on Hierarchical Test Generation : Microelectronics Technology
Park, Duisburg, Germany, September 25-26, 1995 / p. 18

Hierarchical test generation for combinational circuits with real defects coverage

Cibakova, Tatiana; Fischerova, Maria; Gramatova, Elena; Kuzmich, W.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes**
Microelectronics reliability 2002 / p. 1141-1149 : ill <https://www.sciencedirect.com/science/article/pii/S002627140200080X>

Hierarchical test generation for complex digital systems with control and data processing parts

Ubar, Raimund-Johannes; Raik, Jaan "Test, Assembly and Packaging" : SEMICON Technical Symposium : Singapur, May 3-6,
1999 / p. 43-52

Hierarchical test generation for digital systems

Brik, Marina; Jervan, Gert; Markus, Antti; Raik, Jaan; Ubar, Raimund-Johannes Mixed design of integrated circuits and
systems 1998 / p. 131-136: ill https://link.springer.com/chapter/10.1007/978-1-4615-5651-0_20

Hierarchical test generation for digital systems based on combining bottom-up and top-down approaches

Raik, Jaan; Ubar, Raimund-Johannes World Multiconference on Systemics, Cybernetics and Informatics, July 12-16, 1998,
Orlando, Florida : proceedings. Vol. 1 1998 / p. 374-381: ill

Hierarchical test generation for finite state machines

Brik, Marina; Ubar, Raimund-Johannes BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference,
October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 319-324: ill

Hierarchical test generation with multi-level decision diagram models

Jervan, Gert; Markus, Antti; Raik, Jaan; Ubar, Raimund-Johannes Proceedings of the 7th IEEE North Atlantic Test Workshop,
West Greenwich RI, USA, May 28-29, 1998 / p. 26-33
https://www.academia.edu/67811738/Hierarchical_Test_Generation_with_Multi_Level_Decision_Diagram_Models?hb-g-sw=7883185

Hierarchical test generation. SEMI show slides

Ubar, Raimund-Johannes; Raik, Jaan "Test, Assembly and Packaging" : SEMICON Technical Symposium : Singapur, May 3-6, 1999 1999 / p. 53-64

Hierarchical test pattern generation and untestability identification techniques for synchronous sequential circuits =

Hierarhilised testintegreerimise ja mittetestitavuse identifitseerimise meetodid sünkroonsetele järjestikskeemidele

Rannaste, Anna 2010 https://www.ester.ee/record=b2637391*est

Hierarchical test synthesis for digital systems using alternative graph model

Ubar, Raimund-Johannes Quantitative aspects of designing and validating dependable computing systems 1995

Hierarhilisest testigeneerimisest ja mittetestitavuse analüüsist

Rannaste, Anna A & A 2010 / 4, lk. 38-39 https://artiklid.elnet.ee/record=b2286481*est

High quality test generation for digital systems

Ubar, Raimund-Johannes; Aarna, Margit; Kruus, Helena; Raik, Jaan Romanian journal of information science and technology 2005 / 1, p. 73-84 : ill

High-level combined deterministic and pseudo-exhaustive test generation for RISC processors

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Jenihhin, Maksim; Gürsoy, Cemil Cem; Raik, Jaan 2019 IEEE European Test Symposium (ETS) : proceedings 2019 / 6 p. : ill <https://doi.org/10.1109/ETS.2019.8791526>

High-Level Combined Deterministic and Pseudo-exhaustive Test Generation for RISC Processors

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan 2019 IEEE European Test Symposium (ETS) : ETS 2019, May 27-31, 2019, Baden-Baden, Germany : Proceedings 2019 / 6 p. : ill <https://doi.org/10.1109/ETS.2019.8791526>

High-level decision diagrams based coverage metrics for verification and test

Jenihhin, Maksim; Raik, Jaan; Tšepurov, Anton; Reinsalu, Uljana; Ubar, Raimund-Johannes LATW 2009 : 10th IEEE Latin American Test Workshop : Buzios, Rio de Janeiro, Brazil, March 2-5, 2009 2009 / [6] p. : ill <http://dx.doi.org/10.1109/LATW.2009.4813792>

High-level fault diagnosis in RISC processors with Implementation-Independent Functional Test

Oyeniran, Adeboye Stephen; Jenihhin, Maksim; Raik, Jaan; Ubar, Raimund-Johannes 2022 IEEE Computer Society Annual Symposium on VLSI (ISVLSI) : Nicosia, Cyprus : 04-06 July 2022 2022 / p. 32-37 <https://doi.org/10.1109/ISVLSI54635.2022.00019>

High-level functional test generation for microprocessor modules

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes Proceedings of 26th International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2019 : Rzeszów, Poland, June 27 - 29, 2019 2019 / p. 356-361 : ill <https://doi.org/10.23919/MIXDES.2019.8787131>

High-Level Implementation-Independent Functional Software-Based Self-Test for RISC Processors

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan Journal of electronic testing : theory and applications 2020 / p. 87-103 <https://doi.org/10.1007/s10836-020-05856-7>

High-level modeling and testing of multiple control faults in digital systems

Jasnetski, Artjom; Oyeniran, Adeboye Stephen; Tšertov, Anton; Schölzel, Mario; Ubar, Raimund-Johannes Formal proceedings of the 2016 IEEE 19th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 20-22, 2016, Košice, Slovakia 2016 / [6] p. : ill <http://dx.doi.org/10.1109/DDECS.2016.7482445>

High-level path activation technique to speed up sequential circuit test generation

Raik, Jaan; Ubar, Raimund-Johannes European Test Workshop 1999 : proceedings, May 25-28, 1999, Constance, Germany 1999 / p. 84-89 : ill <https://ieeexplore.ieee.org/document/804289>

High-level synthesis and test in the MOSCITO-based virtual laboratory

Schneider, Andre; Diener, Karl-Heinz; Jervan, Gert; Peng, Z.; Raik, Jaan; Ubar, Raimund-Johannes; Hollstein, Thomas; Glesner, M. BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 287-290 : ill

High-level test data generation for software based self-test in microprocessors

Oyeniran, Adeboye Stephen; Jasnetski, Artjom; Tšertov, Anton; Ubar, Raimund-Johannes 2017 6th Mediterranean Conference on Embedded Computing (MECO) : including ECYPS'2017 : proceedings : research monograph : Bar, Montenegro, June 11th-15th, 2017 2017 / p. 86-91 : ill <https://doi.org/10.1109/MECO.2017.7977167>

High-level test generation for processing elements in many-core systems

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Azad, Siavoosh Payandeh; Raik, Jaan 12th International Symposium on Reconfigurable Communication-centric Systems-on-Chip (ReCoSoC2017), July 12-14, 2017, Madrid, Spain : proceedings 2017 /

High-level test synthesis with hierarchical test generation

Jervan, Gert; Eles, Petru; Peng, Zebo; **Raik, Jaan**; **Ubar, Raimund-Johannes** 17th NORCHIP Conference : Oslo, Norway, 8-9 November 1999 : proceedings 1999 / p. 291-296

Hiired laboris : [arvutihiirte testist TTÜ mehaanikateaduskonna laboris]

Urbas, Ando; **Einama, Kaido** Arvutimaailm 2010 / 11, lk. 40-45 : ill

How to generate high quality tests for digital systems

Ubar, Raimund-Johannes; **Aarna, Margit**; **Kruus, Helena**; **Raik, Jaan** 2004 International Semiconductor Conference : 27th edition, October 4-6, 2004, Sinaia, Romania : CAS 2004 proceedings. Volume 2 2004 / p. 459-462 : ill
<http://dx.doi.org/10.1109/SMICND.2004.1403048>

How to generate test data for applications using relational databases

Tamme, Risto Eleventh Estonian Winter School in Computer Science (EWSCS'06) : Park Hotel Palmse, Lahemaa, Estonia : March 5-10, 2006 2006 / [1] p

Hädavalgustuse automaattestimise näide

Tamm, Tiiu Elektriala 2015 / lk. 22-23 : ill https://artiklid.elnet.ee/record=b2721082*est

A hybrid BIST architecture and its optimization for SoC testing

Jervan, Gert; Peng, Zebo; **Ubar, Raimund-Johannes**; **Kruus, Helena** Proceedings of the 3rd International Symposium on Quality Electronic Design : ISQED 2002, March 18-21, 2002, San Jose, California 2002 / p. 273-279 : ill
<https://ieeexplore.ieee.org/document/996750>

Hybrid BIST methodology for testing core-based systems

Jervan, Gert; **Ubar, Raimund-Johannes**; Peng, Zebo Proceedings of the Estonian Academy of Sciences. Engineering 2006 / 3-2, p. 300-322 : ill

Hybrid BIST optimization for core-based systems with test pattern broadcasting

Ubar, Raimund-Johannes; **Jenihhin, Maksim**; **Jervan, Gert**; Peng, Zebo DELTA 2004 : second IEEE International Workshop on Electronic Design, Test and Applications : 28-30 January 2004, Perth, Australia : proceedings 2004 / p. 3-8 : ill
<https://ieeexplore.ieee.org/document/1409808>

Hybrid BIST optimization using reseeding and test set compaction

Jervan, Gert; **Orasson, Elmet**; **Kruus, Helena**; **Ubar, Raimund-Johannes** 10th Euromicro Conference on Digital System Design Architectures, Methods and Tools, DSD 2007 : 29-31 August 2007, Lübeck, Germany : proceedings 2007 / p. 596-603 : ill
<http://dx.doi.org/10.1109/DSD.2007.4341529>

Hybrid BIST optimization using reseeding and test set compaction

Jervan, Gert; **Orasson, Elmet**; **Kruus, Helena**; **Ubar, Raimund-Johannes** Microprocessors and microsystems 2008 / 5/6, p. 254-262 : ill <https://www.sciencedirect.com/science/article/abs/pii/S0141933108000288>

Hybrid BIST scheduling for NoC-based SoCs

Jervan, Gert; **Shchenova, Tatjana**; **Ubar, Raimund-Johannes** Proceedings [of] 24th IEEE Norchip Conference : Linköping, Sweden, 20-21 November 2006 2006 / p. 141-144 : ill <https://ieeexplore.ieee.org/document/4126966>

Hybrid BIST time minimization for core-based systems with STUMPS architecture

Jervan, Gert; Eles, Petru; Peng, Zebo; **Ubar, Raimund-Johannes**; **Jenihhin, Maksim** 18th IEEE International Symposium on Defect and Fault Tolerance in VLSI Systems : 3-5 November 2003, Boston, Massachusetts : proceedings 2003 / p. 225-232 : ill
<https://ieeexplore.ieee.org/document/1250116>

Hybrid built-in self-test : methods and tools for analysis and optimization of BIST = Sisseehitatud hübriidne isetestimine : meetodid ja vahendid analüüsiks ning optimeerimiseks

Orasson, Elmet 2007 https://www.ester.ee/record=b2305436*est

Hybrid built-in self-test and test generation techniques for digital systems

Jervan, Gert 2005 https://www.ester.ee/record=b2177537*est

Hybrid functional BIST for digital systems

Mazurova, Natalja; **Smahtina, Julia**; **Ubar, Raimund-Johannes** BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 205-208 : ill

Hydraulic conductivity testing method for all-in aggregates and mining waste materials

Šommet, Julija; **Pastarus, Jüri-Rivaldo**; **Sabanov, Sergei** 10th International Symposium "Topical Problems in the Field of

Electrical and Power Engineering". Doctoral School of Energy and Geotechnology II : Pärnu, Estonia, January 10-15, 2011 2011 / p. 122-126 : ill

HyFBIST : hybrid functional built-in self-test in microprogrammed data-paths of digital systems

Ubar, Raimund-Johannes; Mazurova, Natalja; Smahtina, Julia; **Orasson, Elmet**; **Raik, Jaan** Proceedings of the 11th International Conference : Mixed Design of Integrated Circuits and Systems : MIXDES 2004 : Szczecin, Poland, 24-26 June 2004 2004 / p. 497-502 : ill

Hygrothermal calculations and laboratory tests on timber-framed wall structures

Kalamees, Targo; Vinha, Juha Building and environment 2003 / 5, p. 689-697 : ill

<https://www.sciencedirect.com/science/article/pii/S036013230200207X>

IEEE European Test Symposium (ETS)

Eggersgluss, Stephan; Hamdioui, Said; **Jutman, Artur**; Michael, Maria K.; **Raik, Jaan** 2019 IEEE International Test Conference (ITC) 2019 / 4 p <https://doi.org/10.1109/ITC44170.2019.9000148> [Conference proceeding at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

IEEE P1687 JTAG demonstrator on FPGA

Shibin, Konstantin; **Aleksejev, Igor**; **Jutman, Artur**; **Devadze, Sergei** DATE 2012 University Booth : Design Automation and Test in Europe : Dresden, Germany, March 12-16, 2012 2012 / 1 p. : ill

https://www.academia.edu/22101517/IEEE_P1687_JTAG_demonstrator_on_FPGA

IF filter design for satellite TV FM video modulator

Kinks, Priit; **Laidvee, Andres**; **Taklaja, Andres** BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 367-370: ill

Impact of small specimens sampling on durability of in-service power plant components

Klevtsov, Ivan; **Dedov, Andrei**; Bogoljubova, Elena Conference Proceedings : 2nd International Conference SSTT : Determination of mechanical properties of materials by small punch and other miniature testing techniques 2012 / p. 373-378

Impact wear tester for the s[t]udy of abrasive erosion and milling processes

Tarbe, Riho; **Kulu, Priit** Proceedings of the 6th International Conference of DAAAM Baltic "Industrial Engineering" : 24-26th April 2008, Tallinn, Estonia. [2] 2008 / p. 561-566 : ill <http://innomet.ttu.ee/daaam08/online/Materials%20Engineering/Tarbe-rev.pdf>

Implementation-independent functional test for transition delay faults in microprocessors

Oyeniran, Adeboye Stephen; **Ubar, Raimund-Johannes**; **Jenihhin, Maksim**; **Raik, Jaan** 2020 23rd Euromicro Conference on Digital System Design (DSD), 26-28 August 2020, Kranj, Slovenia 2020 / p. 646-650 <https://doi.org/10.1109/DSD51259.2020.00105>

Implementation-independent functional test generation for RISC microprocessors

Oyeniran, Adeboye Stephen; **Ubar, Raimund-Johannes**; **Jenihhin, Maksim**; **Raik, Jaan** VLSI-SoC 2019 : 27th IFIP/IEEE International Conference on Very Large Scale Integration : [proceedings] 2019 / p. 82-87 : ill <https://doi.org/10.1109/VLSI-SoC.2019.8920323>

An improved estimation methodology for hybrid BIST cost calculation

Jervan, Gert; Peng, Zebo; **Ubar, Raimund-Johannes**; Korelina, Olga Proceedings [of] 22nd NORCHIP Conference : Oslo, Norway, 8-9 November 2004 2004 / p. 297-300 : ill <https://ieeexplore.ieee.org/document/1423882>

An improved estimation technique for hybrid BIST test set generation

Jervan, Gert; Peng, Zebo; **Ubar, Raimund-Johannes**; Korelina, Olga DDECS : 8th IEEE Workshop on Design and Diagnostics of Electronic Circuits and Systems : April 13-16, 2005, Sopron, Hungary : proceedings 2005 / p. 182-185 : ill <https://www.ida.liu.se/labs/eslab/publications/pap/db/ddecs05.pdf>

Improved modeling of audio signals by modifying transient locations

Vafin, Renat; Heusdens, Richard; Par, Steven van de; Kleijn, W. Bastiaan Proceedings of the 2001 IEEE Workshop on Applications of Signal Processing to Audio and Acoustics : October 21-24, 2001, Mohonk Mountain House, New Paltz, New York, USA 2001 / p. 143-143 : ill <https://ieeexplore.ieee.org/document/969563>

An improved test generation approach for sequential circuits using decision diagrams

Brik, Marina; **Ubar, Raimund-Johannes** BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 155-158: ill

Improving embedded software testing

Savimaa, Raul SCI 2004 : the 8th World Multi-Conference on Systemics, Cybernetics and Informatics : July 18-21, 2004, Orlando, Florida, USA. Volume 1, Information Systems, Technologies and Applications : proceedings 2004 / p. 270-274

Inductive and coinductive predicate liftings for effectful programs

Veltri, Niccolò; **Voorneveld, Niels F.W.** Proceedings 37th Conference on Mathematical Foundations of Programming

Instrument-free Lab-on-a-Chip DNA amplification test for pathogen detection [Online resource]

Pardy, Tamas; Rang, Toomas; Kremer, Clemens; Tulp, Indrek BEC 2018 : 2018 16th Biennial Baltic Electronics Conference (BEC) : proceedings of the 16th Biennial Baltic Electronics Conference, October 8-10, 2018 2018 / 4 p. : ill
<https://doi.org/10.1109/BEC.2018.8600991>

Integrated design and test generation under Internet based environment MOSCITO

Schneider, Andre; **Ivask, Eero; Ubar, Raimund-Johannes** Euromicro Symposium on Digital System Design : Architectures, Methods and Tools : September 4-6, 2002, Dortmund, Germany : proceedings 2002 / p. 187-194 : ill
<http://dx.doi.org/10.1109/DSD.2002.1115368>

Integrated self-regulating resistive heating for isothermal nucleic acid amplification tests (NAAT) in Lab-on-a-Chip (LoC) devices

Pardy, Tamas; Tulp, Indrek; Kremer, Clemens; **Rang, Toomas;** Stewart, Ray PLoS ONE 2017 / p. 1-11 : ill
<https://doi.org/10.1371/journal.pone.0189968> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Integration of digital test tools to the internet-based environment MOSCITO

Schneider, Andre; Diener, Karl-Heinz; Elst, Günter; **Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes** SCI 2003 : the 7th World Multiconference on Systemics, Cybernetics and Informatics : July 27-30, 2003, Orlando, Florida, USA : proceedings. Volume VIII, Applications of Informatics and Cybernetics in Science and Engineering 2003 / p. 136-141 : ill
https://www.researchgate.net/publication/250063424_Integration_of_Digital_Test_Tools_to_the_Internet-Based_Environment_MOSCITO

Intelligent support for expert system verification and testing in object-oriented programming environments : (preprint)

Trausan-Matu, S.; **Tepandi, Jaak;** Barbuceanu, M. 1990

Interaction coefficient for resistance to fragmentation by GOST and EN test results

Koreneva, Julia; Šommet, Julija Road and Rail Infrastructure V : proceedings of the 5th International Conference on Road and Rail Infrastructures – CETRA 2018, 17-19 May 2018, Zadar, Croatia 2018 / p. 207–214 <https://doi.org/10.5592/CO/cetra.2018.896>

Internet based test generation and fault simulation

Ivask, Eero; Ubar, Raimund-Johannes; Raik, Jaan; Schneider, Andre IEEE Design and Diagnostics of Electronic Circuits and Systems - IEEE DDECS 2001 : Fourth International Workshop on IEEE Design and Diagnostics of Electronic Circuits and Systems : Győr, Hungary, April 18-20, 2001 2001 / p. 57-60 : ill

Internet-based collaborative test generation with MOSCITO [Electronic resource]

Schneider, Andre; **Ivask, Eero;** Miklos, P.; **Raik, Jaan;** Diener, Karl-Heinz; **Ubar, Raimund-Johannes;** Cibakova, Tatiana; Gramatova, Elena SIGDA publications on CD-ROM : DATE'02 : Design, Automation and Test in Europe, Paris, France, March 4-8, 2002 2002 / [6] p. [CD-ROM] https://www.cecs.uci.edu/~papers/date07/PAPERS/2002/DATE02/PDFFILES/02E_2.PDF

Internet-based software for teaching test of digital circuits

Ubar, Raimund-Johannes; Orasson, Elmet; Wuttke, Heinz-Dietrich 23rd International Conference on Microelectronics : MIEL 2002, Niš, Yugoslavia, 12-15 May 2002 : proceedings. Volume 2 2002 / p. 659-662 : ill <https://ieeexplore.ieee.org/document/1003344>

Internet-based software for teaching test of digital circuits

Ubar, Raimund-Johannes; Jutman, Artur; Orasson, Elmet; Raik, Jaan; Evarson, Teet; Wuttke, Heinz-Dietrich Microelectronics education : proceedings of the 4th European Workshop on Microelectronics Education : EWME 2002, Spain, May 23-24, 2002 2002 / p. 317-320 : ill <https://ieeexplore.ieee.org/document/1003344>

Internet-based testability-driven test generation in the virtual environment MOSCITO

Schneider, Andre; Diener, Karl-Heinz; Elst, G.; **Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes** International Federation for Information Processing IFIP : International Workshop on IP-Based SoC Design 2002 : proceedings : Grenoble, October 30-31, 2002 2002 / p. 357-362 : ill <http://publica.fraunhofer.de/dokumente/N-287433.html>

ISS seminar disaini verifitseerimisest ja testimise automatiseerimisest

Tammemäe, Kalle Arvutustehnika ja Andmetöötlus 1997 / 7/8, lk. 47-52

IST project REASON : handbook of testing electronic systems

Novak, Ondrej; Gramatova, Elena; **Ubar, Raimund-Johannes** IEEE Proceedings of the 5th European Dependable Computing Conference : EDCC-5 : Budapest, 2005 2005 / p. 15-18

An iterative approach to test time minimization for parallel hybrid BIST architecture

Ubar, Raimund-Johannes; Jenihhin, Maksim; Jervan, Gert; Peng, Z. 5th IEEE Latin-American Test Workshop - LATW 2004 : Cartagena, Colombia, 2004 : digest of papers 2004 / p. 98-103 : ill <https://www.ida.liu.se/labs/eslab/publications/pap/db/latw04.pdf>

An iterative approach to test time minimization for parallel hybrid BIST architectures

Ubar, Raimund-Johannes; Jenihhin, Maksim; Jervan, Gert; Peng, Z. System-on-Chip Conference 2004 : Bastad, Sweden 2004 / p. ? <https://www.ida.liu.se/labs/eslab/publications/pap/db/latw04.pdf>

Iterative optimization of hyperparameter-based metamorphic transformations

Sudheerbabu, Gaadha; Ahmad, Tanwir; Truscan, Dragos; **Vain, Jüri;** Porres, Ivan 2024 IEEE International Conference on Software Testing, Verification and Validation Workshops (ICSTW) 2024 / p. 13-20 <https://doi.org/10.1109/ICSTW60967.2024.00016> [Article at Scopus](#) [Article at WOS](#)

Java applet for self-learning of digital test issues [Electronic resource]

Ubar, Raimund-Johannes; Orasson, Elmet; Evertson, Teet 13th EAAEIE Annual Conference, 8th-10th April, 2002, York, England 2002 / [4] p. [CD-ROM]

Java applets support for an asynchronous-mode learning of digital design and test

Jutman, Artur; Sudnitsõn, Aleksander; Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich ITHET 2003 proceedings : 4th International Conference on Information Technology Based Higher Education and Training : July 7-9, 2003, Marrakech, Morocco 2003 / p. 397-401 : ill <https://citeseerx.ist.psu.edu/document?repid=rep1&type=pdf&doi=92f0b0e5011a2192d5a1b98baa751cb8cd2f7ff3>

Java technology based training system for teaching digital design and test

Devadze, Sergei; Jutman, Artur; Sudnitsõn, Aleksander; Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 283-286 : ill

Kaablitester

Sinivee, Veljo Arvutikasutaja 2003 / 7, lk. 31

Kaljajook kustutab janu : [kalja testivad A.Virkus jt.]

Virkus, Ants; Visnapuu, Manona Sõnumileht 1999 / 19. aug., lk. 14

Keerukate arvutisüsteemide uurimine Tallinna Tehnikaülikoolis

Jervan, Gert; Ellervee, Peeter; Ubar, Raimund-Johannes Tallinna Tehnikaülikooli aastaraamat 2007 2008 / lk. 42-60 : ill

Kersna : koolide tulevik on kiirtestid [Võrguväljaanne]

Krjukov, Aleksander err.ee 2021 ["Kersna: koolide tulevik on kiirtestid"](#)

Kliimaseadmed, vedelikjahutid ja elektrilise ajamiga kompressoriga soojuspumbad ruumide kütmiseks ja jahutuseks : testimine ja hindamine osalise koormuse tingimustes ja sesoonsete näitajate arvutamine = Air conditioners, liquid chilling packages and heat pumps, with electrically driven compressors, for space heating and cooling : testing and rating at part load conditions and calculation of seasonal performance

2024 https://www.ester.ee/record=b5671708*est

A knowledge-based approach to the specification-based program testing

Tepandi, Jaak Computers and artificial intelligence = Вычислительные машины и искусственный интеллект = Põhitähtne a umela inteligencia 1988 / p. 39-48 https://www.ester.ee/record=b1482459*est

Koolitestide tarnijal kaelas juba järgmine menetlus

Alas, Brita-Maria Postimees 2021 / Lk. 4-5 <https://dea.digar.ee/article/postimees/2021/11/22/3.9>

Kuidas testida arvutivõrku ränikiibil

Raik, Jaan; Govind, Vineeth A & A 2010 / 4, lk. 35-37 https://artiklid.elnet.ee/record=b2286479*est

Kundas testitakse uut mineraalivarude kaevandamise robotit

toostusuudised.ee 2023 [Kundas testitakse uut mineraalivarude kaevandamise robotit](#)

Kuulipilduri seljakott: vajadusest sündinud

Nooni, Jukko Postimehe lisa 2022 / Lk. 6 [Kuulipilduri seljakott: vajadusest sündinud](#)

Kuus TalTechi teadustööd, mis võivad muuta maailma

Vilbo, Kätliin Gertrud Trialoog 2025 <https://trialoog.taltech.ee/kuus-taltech-teadustood-mis-voivad-muuta-maailma/>

Kütuste testimisest

Poobus, Arvi; Tiikma, Toomas Tehnika ja Tootmine 1995 / 5, lk. 25-28: ill

Laboratory course for training "Digital design and test"

Ubar, Raimund-Johannes; Tulit, Viljar; Buldas, Ahto; **Saarepera, Märt** Fourth EUROCHIP Workshop on VLSI Design Training, 29 September to 1 October 1993, Toledo : [proceedings] 1993 / p. 112-117: ill

Laboratory framework TEAM for investigating the dependability issues of microprocessor systems

Jasnetski, Artjom; Tšertov, Anton; Ubar, Raimund-Johannes; Kruus, Helena 10th European Workshop on Microelectronics Education : EWME 2014 : May 14-16, 2014, Tallinn, Estonia 2014 / p. 80-83 : ill

Laboratory tests and modelling of mineral wool insulated steel sandwich panels

Laukkarinen, Anssi; Vinha, Juha; **Kalbe, Kristo; Kalamees, Targo** E3S Web of Conferences : 12th Nordic Symposium on Building Physics (NSB 2020) : Tallinn, Estonia, September 6-9, 2020 2020 / art. 17006, 8 p. : ill <https://doi.org/10.1051/e3sconf/202017217006>
[Conference proceedings at Scopus](#) [Article at Scopus](#) [Conference proceedings at WOS](#) [Article at WOS](#)

Laboratory training for teaching design and test of digital circuits

Jutman, Artur; Ubar, Raimund-Johannes Proceedings of the 8th International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2001 : Zakopane, Poland, 21-23 June 2000 2001 / p. 521-524 : ill <https://pld.ttu.ee/~artur/papers/TestLabs-MIXDES01.pdf>

Ladestatava prügi leostustestimisalasest koostööst

Wahlström, Margareta; Laine-Ylijoki, Jutta; Hjelm, Ole; **Nuutre, Maaris; Loosaar, Jüri** Keskkonnatehnika 2003 / 5, lk. 43-47
https://artiklid.elnet.ee/record=b1014022*est

Lasnamäel saab testida isesõitvat bussi [Võrguväljaanne]

Autonet.ee 2022 "[Lasnamäel saab testida isesõitvat bussi](#)"

Learning digital test and diagnostics via internet [Electronic resource]

Ubar, Raimund-Johannes; Jutman, Artur; Kruus, Margus; Orasson, Elmet; Devadze, Sergei; Wuttke, Heinz-Dietrich International journal of computing & information sciences 2006 / 2, p. 86-96 : ill

A library of samples for testing variable load electric drives

Liivik, Liisa; Vodovozov, Valery; Rassõlkin, Anton Digest book and electronic proceedings : 54th International Scientific Conference of Riga Technical University : Section of Power and Electrical Engineering 2013 / p. 12.1-12.6 : ill

Liginullenergiahoone - meie majaehituse lähitulevik : [TTÜ testhoonest]

Inseneria 2013 / lk. 14 : ill

Linear algorithms for testing superpositional graphs

Peder, Ahti; Nestra, Härmel; **Raik, Jaan; Tombak, Mati; Ubar, Raimund-Johannes** Proceedings of the Reed-Muller 2011 Workshop : May 25-26, 2011, Tuusula, Finland 2011 / p. 111-118 : ill

Low-area boundary BIST architecture for mesh-like network-on-chip

Raik, Jaan; Govind, Vineeth Proceedings of the 2012 IEEE 15th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 18-20, 2012 Tallinn, Estonia 2012 / p. 95-100 : ill

Low-cost CAD software for teaching digital test

Ubar, Raimund-Johannes; Raik, Jaan; Paomets, Priidu First European Workshop on Microelectronics Education, Villard de Lans, France, February 5-6, 1996 : proceedings 1996 / p. 48

Lääne-Virumaal katsetatav kaevandusrobot säästab keskkonda

Nikolajev, Jüri err.ee 2023 [Lääne-Virumaal katsetatav kaevandusrobot säästab keskkonda](#)

Mapping faults in hierarchical testing of digital systems

Ubar, Raimund-Johannes International Conference on Computer, Communication and Control Technologies CCCT'03 and the 9th International Conference on Information Systems, Analysis and Synthesis ISAS'03 : July 31 - August 1-2, Orlando, Florida, USA : proceedings. Volume I, Computing/Information Systems and Technologies 2003 / p. 14-19 : ill

Mapping physical defects to logic level for defect oriented testing

Ubar, Raimund-Johannes SCS 2003 : International Symposium on Signals, Circuits and Systems : July 10-11, 2003, Iasi, Romania : proceedings. Vol. 2 2003 / p. 453-456 : ill <https://ieeexplore.ieee.org/document/5731320>

Material characterization for laminated glass composite panel

Väer, Kaur; Anton, Johan; Klauson, Aleksander; Eerme, Martin; Õunapuu, Erko; Tšukrejev, Pavel Journal of achievements in materials and manufacturing engineering 2017 / p. 11-17 <https://doi.org/10.5604/01.3001.0010.2032> [Journal metrics at Scopus](#) [Article at Scopus](#)

MCM-test

Magnhagen, Bengt; Linden, Henric BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 297-304: ill

Measuring mining influence in the form of students practice in opposition to the emotional environmental impact assessment

Robam, Karin; Väizene, Vivika; Anepaio, Ain; Kolats, Margit; **Valgma, Ingo** 5th International Symposium "Topical Problems in the Field of Electrical and Power Engineering". Doctoral School of Energy and Geotechnology : Kuressaare, January 14-19, 2008 2008 / p. 62-65 : ill

Meie igapäevane testimine

Markvardt, Maili A & A 2010 / 3, lk. 5-11 https://artiklid.elnet.ee/record=b2183723*est

A method for crosstalk fault detection in on-chip buses

Bengtsson, Tomas; **Jutman, Artur; Ubar, Raimund-Johannes**; Kumar, Shashi Norchip : proceedings : Oulu, Finland, 21-22 November 2005 2005 / p. 285-288 : ill <https://doi.org/10.1109/NORCHIP.2005.1597045>

A method for identification dynamic parameters of mixed signal circuits

Zagursky, V.; Semyonova, N.; Gertners, A. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 211-215 https://www.ester.ee/record=b2150914*est

A method for testing dynamic characteristics of analog-digital converters in spectral domain

Zagursky, V.; Semyonova, N.; Gertners, A. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 207-210 https://www.ester.ee/record=b2150914*est

Method for testing the brain

Hinrikus, Hiie; Bachmann, Maie; Lass, Jaanus; Tuulik, Viuu; Ubar, Raimund-Johannes 5th European Conference of the International Federation for Medical and Biological Engineering : 14-18 September 2011, Budapest, Hungary 2012 / p. 1198-1201 : ill

Microprocessor-based system test using debug interface

Devadze, Sergei; Jutman, Artur; Tšertov, Anton; Instenberg, Martin; **Ubar, Raimund-Johannes** 26th Norchip Conference : Tallinn, Estonia, 17-18 November 2008 : formal proceedings 2008 / p. 98-101 : ill <http://dx.doi.org/10.1109/NORCHIP.2008.4738291>

Microprogram automation : design for testability

Keevallik, Andres; Kruus, Margus; Lensen, Harri BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 171-174

Microprogrammed test generator for bus oriented devices

Szegi, A.; Feher, B. Automation, simulation & measurement. Section A, Automation. Section M, Measurement : 3rd biennial conference : Tallinn, Estonia, October 7-11, 1991 = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 88-94: ill

Mikroelektroonika kiipide testimise tarkvara turbo-tester : kommentaar Eesti Teaduste Akadeemia Bernhard Schmidt'i preemia pälvinud tööle

Raik, Jaan Tallinna Tehnikaülikooli aastaraamat 2007 2008 / lk. 275-278

Milleks ja kuidas katsetada laevu?

Hartikainen, Anni Paat & Meremees 2016 / lk. 30 http://www.ester.ee/record=b4471304*est

Milline on parim hiir? : [TTÜ tootearenduse tudengid testisid arvutihiiri]

Toon, Triin; Matsi, Birthe; **Otto, Tauno** Arvutikasutaja 2005 / 8, lk. 34-37 : ill https://artiklid.elnet.ee/record=b1050729*est

Milline pann osta? Kas odav pann teeb töö ära sama hästi kui kallis?

Arndt-Kalju, Margit; Kirikal, Siiri; Skuin, Mari; Tarkmeel, Krõõt delfi.ee 2023 [Milline pann osta? Kas odav pann teeb töö ära sama hästi kui kallis?](#)

Minimization of the high-level fault model for microprocessor control parts [Online resource]

Ubar, Raimund-Johannes; Oyeniran, Adeboye Stephen; Medaiyese, Olusiji BEC 2018 : 2018 16th Biennial Baltic Electronics Conference (BEC) : proceedings of the 16th Biennial Baltic Electronics Conference, October 8-10, 2018 2018 / 4 p.: ill <https://doi.org/10.1109/BEC.2018.8600980>

Mis on head ja halba Bioestis? : [prof. Anti Viikna TTÜ teadlaste korraldatud testist]

Viikna, Anti; Luts, Eva Postimees 1996 / 12. nov., Kasu, lk. 3

Mixed bottom-up/top-down hierarchical test generation for digital systems

Ubar, Raimund-Johannes Proceedings of the 9th European Workshop on Dependable Computing, Gdansk, Poland, May 14-16, 1998 1998 / p. 37-40

Mixed-level defect simulation in data-paths of digital systems

Ubar, Raimund-Johannes; Raik, Jaan; Ivask, Eero; Brik, Marina 23rd International Conference on Microelectronics : MIEL 2002,

Niš, Yugoslavia, 12-15 May 2002 : proceedings. Volume 2 2002 / p. 617-620 : ill <https://ieeexplore.ieee.org/document/1003333>

Model based approach for testing: distributed real-time systems augmented with online monitors

Pal, Deepak; Vain, Jüri Databases and Information Systems : 13th International Baltic Conference, DB&IS 2018, Trakai, Lithuania, July 1-4, 2018 : proceedings 2018 / p. 142-157 https://doi.org/10.1007/978-3-319-97571-9_13 [Conference proceedings at Scopus](#)
[Article at Scopus](#)

Model based framework for testing distributed systems

Pal, Deepak; Vain, Jüri Proceedings of the 8th Annual Conference of the Estonian National Doctoral School in Information and Communication Technologies : December 5-6, 2014, Rakvere 2014 / p. 91-94 : ill

Model based testing of distributed time critical systems

Vain, Jüri; Kanter, Gert; Srinivasan, Seshadri 2017 6th International Conference on Reliability, Infocom Technologies and Optimization (Trends and Future Directions) (ICRITO 2017) : Noida, India 20-22 September 2017 2017 / p. 99-105 : ill
<https://doi.org/10.1109/ICRITO.2017.8342406>

Model driven engineering in automatic test generation

Domiczi, E.; **Vain, Jüri** Proceedings of the NWUML'2005 : The Nordic Workshop on UML and Software Modeling 2005 / p. 208-216

Model of fracture micromechanism of Cu-Cr-Zr system by "in-situ" test in SEM

Besteri, Michal; Ivan, Jozef; **Kulu, Priit; Arensburger, Daniil;** Velgosova, Oksana Proceedings of 9th International Scientific Conference "Achievements in Mechanical & Materials Engineering" : Gliwice, Poland, 11.-14.10.2000 2000 / p. 59-62
<https://doiserbia.nb.rs/img/doi/1450-5339/2003/1450-53390304499B.pdf>

Model synthesis from VHDL for the functional test generation system

Krupnova, Helena 1993 https://www.ester.ee/record=b2090509*est

Model-based integration testing of ROS packages : a mobile robot case study

Ernits, Juhan-Peep; Halling, Evelin; Kanter, Gert; Vain, Jüri 2015 European Conference on Mobile Robots : Lincoln, United Kingdom, September 2-4, 2015 : conference proceedings 2015 / [7] p. : ill <http://dx.doi.org/10.1109/ECMR.2015.7324210>

Model-based synthesis of reactive planning on-line testers for non-deterministic embedded systems

Kääramees, Marko; Vain, Jüri; Raiend, Kullo BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 189-192 : ill

Model-based testing framework for autonomous multi-robot systems = Mudelipõhine testimisraamistik autonoomsetele multirobotsüsteemidele

Kanter, Gert 2020 <https://digikogu.taltech.ee/et/Item/575133f2-f94a-49d4-a7c9-0615b54ae139> <https://doi.org/10.23658/taltech.19/2020>

Model-based testing of a web-based positioning application

Roo, Rivo; Ernits, Juhan-Peep 20th Nordic Workshop on Programming Theory : NWPT 2008 : Tallinn, Estonia, 19-21 November 2008 : abstracts 2008 / p. 75-77 : ill https://link.springer.com/chapter/10.1007/978-3-642-05031-2_14

Model-based testing of reactive systems = Reaktiivsete süsteemide mudelipõhine testimine

Kull, Andres 2009 https://www.ester.ee/record=b2539853*est

Model-based testing of real-time distributed systems

Vain, Jüri; Halling, Evelin; Kanter, Gert; Anier, Aivo; Pal, Deepak Databases and Information Systems : 12th International Baltic Conference, DB&IS 2016, Riga, Latvia, July 4-6, 2016 : proceedings 2016 / p. 272-286 : ill https://doi.org/10.1007/978-3-319-40180-5_19 [Conference Proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Model-based testing of real-time distributed systems = Reaalaja hajussüsteemide mudelipõhine testimine

Pal, Deepak 2020 https://www.ester.ee/record=b5389209*est <https://digikogu.taltech.ee/et/Item/b919afec-e786-4e14-9918-7d8db3b20cfe>

Model-based testing of robots with NMmodel

Ernits, Juhan-Peep; Veanes, Margus; Helander, Johannes TESTCOM/FATES 2008 : Tokyo, Japan, June 12-13, 2008 : short papers 2008 / p. 40-49 https://www.researchgate.net/publication/228824559_Model-Based_Testing_of_Robots_with_NMmodel

Modeling and simulation of circuits with shared structurally synthesized BDDs

Ubar, Raimund-Johannes; Jürimägi, Lembit; Raik, Jaan; Viies, Vladimir Microprocessors and microsystems 2017 / p. 56-61 : ill
<https://doi.org/10.1016/j.micpro.2016.09.006> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Modelling and testing of the properties of recovered composite material

Kers, Jaan; Goljandin, Dmitri; Tall, Kaspar; Aruniit, Aare; Adoberg, Eron; Saarna, Mart; Majak, Jüri Proceedings of the Tenth International Conference on Computational Structures Technology : Valencia, Spain, 14-17 September 2010 2010 / Paper 81

Moisture dry-out capability of steel-faced mineral wool insulated sandwich panels

Kalbe, Kristo; Piikov, Hubert; Kalamees, Targo Sustainability 2021 / 18 p. : ill <https://doi.org/10.3390/su12219020> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Motion control system for ship model towing test tank control system using synchronous servo drives

Liyanage, Dhanushka Chamara; Hiilemaa, Maido; Tamre, Mart Proceedings of the 11th International Conference of DAAAM Baltic Industrial Engineering : 20-22th April 2016, Tallinn, Estonia 2016 / p. 151-156 : ill <http://innomet.ttu.ee/daaam/>

Motor Mode Analysis of Exterior-Rotor PM Machine with Gramme's Winding

Nukki, Rene; Kilk, Aleksander; Saarts, Samo; Tiimus, Kristjan Elektronika ir elektrotehnika = Electronics and electrical engineering 2017 / p. 21-25 : ill <https://doi.org/10.5755/j01.eie.23.1.17579> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Mudelipõhine testimine

Kull, Andres Tallinna Tehnikaülikooli aastaraamat 2010 2011 / lk. 115-118

Mudelipõhine testimine : kas teoreetikute näpuharjutus või testimise homme päev?

Markvardt, Maili A & A 2010 / 3, lk. 48-56 https://artiklid.elnet.ee/record=b2183739*est

Multi-fragment Markov model guided online test generation for MPSoC

Vain, Jüri; Tsiopoulos, Leonidas; Kharchenko, Vyacheslav; Apneet Kaur; Jenihhin, Maksim; Raik, Jaan ICTERI 2017 : ICT in Education, Research and Industrial Applications. Integration, Harmonization and Knowledge Transfer : proceedings of the 13th International Conference on ICT in Education, Research and Industrial Applications. Integration, Harmonization and Knowledge Transfer, Kyiv, Ukraine, May 15-18, 2017 2017 / p. 594-607 : ill <http://www.scopus.com/inward/record.uri?eid=2-s2.0-85020540459&partnerID=40&md5=af226e25c344c52689f23bf5c39cc267> <http://ceur-ws.org/Vol-1844/10000594.pdf> [Conference proceedings at Scopus](#) [Article at Scopus](#)

Multifrequency testing and diagnosis of analog and mixed signal circuits using neuromorphic classifier

Lantsov, V.; Rudakov, O.; Mosin, S. BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 347-348

Multi-level test generation and fault diagnosis for finite state machines

Ubar, Raimund-Johannes; Brik, Marina Dependable computing : proceedings / EDCC-2, Second European Dependable Computing Conference, Taormina, Italy, October 2-4, 1996 1996 / p. 264-281: ill

Multi-level test generation and fault diagnosis in digital systems

Ubar, Raimund-Johannes 1992

Multi-level test generation for digital systems at system, circuit and defect levels

Ubar, Raimund-Johannes Proceedings of the 7th International Scientific Conference "Theory and Technique of Information Transmission, Reception and Processing" : Tuapse, October 1-4, 2001 2001 / p. 286-288

Multiple control fault testing in digital systems with high-level decision diagrams

Ubar, Raimund-Johannes; Oyeniran, Adeboye Stephen 2016 IEEE International Conference on Automation, Quality and Testing, Robotics (AQTR) : THETA 20th edition : 19th-21st May, Cluj-Napoca, Romania : proceedings 2016 / [6] p. : ill <http://dx.doi.org/10.1109/AQTR.2016.7501287>

Multiple fault analyses in logic circuits

Ubar, Raimund-Johannes IFAC-Symposium Discrete Systems : Dresden, 14.-19. 3. 77 1977 / p. [?]

Multiple stuck-at-fault detection theorem

Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan Proceedings of the 2012 IEEE 15th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 18-20, 2012 Tallinn, Estonia 2012 / p. 236-241 : ill

Multiple-objective backtrace for solving test generation constraints

Mekler, A.; Raik, Jaan International Symposium on System-on-Chip : November 19-21, 2003, Tampere, Finland : proceedings 2003 / p. 123-126 : ill <https://ieeexplore.ieee.org/document/1267732>

Multiscale memristive properties of skin induced by memory effects of cyclic stress-relaxation loadings : data fusion from ground truth nonlinear acousto-mechanical testing

Dos Santos, Serge; Masood, Ali; Lints, Martin; Salupere, Andrus; Kozena, Colette; Kus, Vaclav ICSV 2018: 25th International Congress on Sound and Vibration (ICSV25), Hiroshima, Japan, 8-12 July, 2018 : proceedings. Vol. 1 2018 / p. 1965-1972 : ill <http://toc.proceedings.com/40638webtoc.pdf> https://www.researchgate.net/publication/326668548_MULTISCALE_MEMRISTIVE_PROPERTIES_OF_SKIN_INDUCED_BY_MEMORY_EFFECTS_OF_CYCLIC_STRESS-RELAXATION_LOADINGS_DATA_FUSION_FROM_GROUND_TRUTH_NONLINEAR_ACOUSTO-MECHANICAL_TESTING

Multi-view modeling for MPSoC design aspects [Online resource]

Vain, Jüri; Apneet Kaur; Tsiopoulos, Leonidas; Raik, Jaan; Jenihhin, Maksim BEC 2018 : 2018 16th Biennial Baltic Electronics Conference (BEC) : proceedings of the 16th Biennial Baltic Electronics Conference, October 8-10, 2018 2018 / 4 p.: ill
<https://doi.org/10.1109/BEC.2018.8600986>

Mutation analysis for systemC designs at TLM

Guarnieri, Valerio; Bombieri, Nicola; Pravadelli, Graziano; Fummi, Franco; **Hantson, Hanno; Raik, Jaan; Jenihhin, Maksim; Ubar, Raimund-Johannes** 12th IEEE Latin American Test Workshop (LATW) : Porto de Galinhas, Brasil, 27-30 March 2011 2011 / [6] p
<https://ieeexplore.ieee.org/document/5985925>

Mutations for testing hardware and correcting design errors

Hantson, Hanno Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK viienda aastakonverentsi artiklite kogumik : 25.-26. novembril 2011, Nelijärve 2011 / p. 105-108 : ill

Nanoindentation testing and modeling of chromium carbide based composites

Hussainova, Irina; Hamed, Elham; Jasiuk, Iwona Mechanics of composite materials 2011 / p. 667-678 : ill

Nanomaterials Al-Al4-C3 studied by "In-situ Tensile Test in SEM"

Besterci, Michal; Velgosova, Oksana; Ivan, Jozef; Hvizdoš, Pavol; Kvackaj, Tibor; **Kulu, Priit** 18th International Baltic Conference : Engineering Materials & Tribology : BALTMATRIB-2009 : October 22-23, 2009, Tallinn, Estonia : abstracts 2009 / p. 73

Narkotestide idufirma sihib 700 miljoni eurost käivet

Mandel, Meelis aripaev.ee 2025 [Narkotestide idufirma sihib 700 miljoni eurost käivet](#)

Narkotestri arendamine narkootikumide tuvastamiseks süljes

Saar-Reismaa, Piret; Erme, E.; **Kulp, Maria; Gorbatšova, Jelena; Kaljurand, Mihkel; Vaher, Merike; Mazina-Šinkar, Jekaterina** XXXIV Eesti keemiapäevad : 100. aastapäeva teaduskonverentsi teesid 2019 / lk. 27
https://www.ester.ee/record=b5208044*est

Natural apeaking and how to assess it

Pajupuu, Hille; Kerge, Krista; **Meister, Lya**; Asu, Eva Liina; Alp, Pilvi Trames 2010 / 2, p. 120-140 : ill
https://www.researchgate.net/publication/238451077_Natural_speaking_and_how_to_assess_it

New built-in self-test scheme for SoC interconnect

Jutman, Artur; Ubar, Raimund-Johannes; Raik, Jaan The 9th World Multi-Conference on Systemics, Cybernetics and Informatics : WMSCI 2005 : July 10-13, 2005, Orlando, Florida, USA. Vol. IV 2005 / p. 19-24 : ill
https://www.researchgate.net/publication/237375234_New_Built-In_Self-Test_Scheme_for_SoC_Interconnect

New fault models and self-test generation for microprocessors using High-Level Decision Diagrams

Jasnetski, Artjom; **Raik, Jaan; Tšertov, Anton; Ubar, Raimund-Johannes** 2015 IEEE 18th International Symposium on Design and Diagnostics of Electronic Circuits & Systems DDECS 2015 : 22-24 April 2015, Belgrade, Serbia : proceedings 2015 / p. 251-254 : ill

New foreign language text-books as objects of testing

Rapoort, I.; Petrova, N. V Regional Seminar East-West Meeting of Language Testing, Tallinn, September 2-4, 1991 : summaries 1991 / p. 77

New high frequency surface fatigue wear tester : design and first results

Antonov, Maksim; Kulu, Priit; Sergejev, Fjodor; Hussainova, Irina; Veinthal, Renno Proceedings of Nordtrib 2008 : 13th Nordic Symposium on Tribology : Tampere, Finland, 10-13 June, 2008 2008 / p. NT2008-87-24
https://www.researchgate.net/publication/288482524_New_high_frequency_surface_fatigue_wear_tester_Design_and_first_results

A new measure for calculating multiple fault coverage of microprocessor self-test

Oyeniran, Adeboye Stephen; Odozi, Uzochukwu Eddie; Ubar, Raimund-Johannes BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 75-78 : ill http://www.ester.ee/record=b2150914*est

New method of testability calculation to guide RT-level test generation

Raik, Jaan; Nõmmeots, Tanel; Ubar, Raimund-Johannes 4th IEEE Latin-American Test Workshop : LATW2003 : Natal, Brazil, February 16-19, 2003 2003 / p. 46-51 : ill <https://link.springer.com/article/10.1007/s10836-005-5288-5>

New system of testing pupils' abilities in British schools

Gizatullin, N.; Koptelova, N. V Regional Seminar East-West Meeting of Language Testing, Tallinn, September 2-4, 1991 : summaries 1991 / p. 36-37

A new test suite reduction approach based on hypergraph minimal transversal mining

Trabelsi, Shaima; Bennani, Mohamed Taha; **Ben Yahia, Sadok** Future Data and Security Engineering : 6th International Conference, FDSE 2019, Nha Trang City, Vietnam, November 27–29, 2019, Proceedings 2019 / p. 15-30 https://doi.org/10.1007/978-3-030-35653-8_2 [Conference proceeding at Scopus](#) [Article at Scopus](#) [Conference proceeding at WOS](#) [Article at WOS](#)

Noise behavioral model of testing system

Brygilewicz, Volodymyr; Wojciechowski, Jacek BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 57-60 : ill

A novel artificial neural networks based automatic adaptive fault detection technique for analog circuits

Petlenkov, Eduard; Jutman, Artur; Nömm, Sven; Ubar, Raimund-Johannes BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 167-170 : ill

NP-hard graph problems' algorithms testing guidelines : artificial intelligence principles and testing as a service

Kumlander, Deniss Advances in computer and information sciences and engineering 2008 / p. 114-118 : ill
https://link.springer.com/chapter/10.1007/978-1-4020-8739-4_20

NP-hard graph problems' algorithms testing guidelines : artificial intelligence principles and testing as a service

Kumlander, Deniss Innovative techniques in instruction technology, e-learning, e-assessment, and education 2008 / p. 112-116
https://link.springer.com/chapter/10.1007/978-1-4020-8739-4_20

A numerical study for plant-independent evaluation of fractional-order PID controller performance

Alagoz, Baris Baykant; **Tepljakov, Aleksei**; Yeroglu, Celaleddin; Gonzalez, Emmanuel A.; Hossein Nia, S. Hassan; **Petlenkov, Eduard** IFAC-PapersOnLine 2018 / p. 539-544 : ill <https://doi.org/10.1016/j.ifacol.2018.06.151> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Off-line testing of crosstalk induced glitch faults in NoC Interconnects

Bengtsson, Tomas; Kumar, Shashi; **Jutman, Artur; Ubar, Raimund-Johannes** Proceedings [of] 24th IEEE Norchip Conference : Linköping, Sweden, 20-21 November 2006 2006 / p. 221-225 : ill <http://dx.doi.org/10.1109/NORCHIP.2006.329215>

Off-line testing of delay faults in NoC interconnects

Bengtsson, Tomas; **Jutman, Artur**; Kumar, Shashi; Peng, Zebo; **Ubar, Raimund-Johannes** 9th EUROMICRO Conference on Digital Systems Design : Architectures, Methods and Tools (DSD 2006) : 30 August 2006-1 September 2006, Cavtat near Dubrovnik, Croatia : proceedings 2006 / p. 677-680 : ill <http://dx.doi.org/10.1109/DSD.2006.72>

On automatic software-based self-test program generation based on high-Level decision diagrams

Jasnetski, Artjom; Ubar, Raimund-Johannes; Tšertov, Anton LATS 2016 : 17th IEEE Latin-American Test Symposium, Foz do Iguaçu, Brazil, 6th-9th April 2016 2016 / p. 177 <http://dx.doi.org/10.1109/LATW.2016.7483357>

On coverage of timing related faults at board level

Jutman, Artur; Alekseev, Igor; Devadze, Sergei 2016 21st IEEE European Test Symposium (ETS) : May 23rd-26th 2016, Amsterdam, The Netherlands : proceedings 2016 / [2] p. : ill <https://doi.org/10.1109/ETS.2016.7519295>

On efficient logic-level simulation of digital circuits represented by the SSBDD model

Jutman, Artur; Raik, Jaan; Ubar, Raimund-Johannes 23rd International Conference on Microelectronics : MIEL 2002, Niš, Yugoslavia, 12-15 May 2002 : proceedings. Volume 2 2002 / p. 621-624 : ill <https://ieeexplore.ieee.org/document/1003334>

On LFSR polynomial calculation for test time reduction

Jutman, Artur Computer Science Meets Automation : 10-13 September 2007 : proceedings. Volume II 2007 / p. 153-158 : ill
https://www.db-thueringen.de/receive/dbt_mods_00008867

On mutating UPPAAL timed automata to assess robustness of web services

Siavashi, Faezeh; Truscan, Dragos; **Vain, Jüri** Proceedings of the 11th International Joint Conference on Software Technologies (ICSOT 2016). Vol. 1, ICSOT-EA 2016 / p. 15-26 : ill <http://dx.doi.org/10.5220/0005970800150026>

On reusability of verification assertions for testing

Jenihhin, Maksim; Raik, Jaan; Ubar, Raimund-Johannes; Tšepurov, Anton BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 151-154 : ill

On reusability of verification assertions for testing

Jenihhin, Maksim; Raik, Jaan Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK kolmanda aastakonverentsi artiklite kogumik : 25.-26. aprill 2008, Voore külalistemaja 2008 / p. 43-46 : ill

On test generation for microprocessors for extended class of functional faults

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan VLSI-SoC: New technology enabler : 27th IFIP WG 10.5/IEEE International Conference on Very Large Scale Integration, VLSI-SoC 2019 Cusco, Peru, October 6–9, 2019 : Revised and Extended Selected Papers 2020 / p. 21-44 <https://doi.org/10.1007/978-3-030-53273-4> [Conference proceedings at Scopus](#) [Article at Scopus](#)

On testing microservice systems

Koschel, Arne; **Astrova, Irina**; Bartels, Mirco; Helmers, Mark; Lyko, Marcel Proceedings of the Future Technologies Conference (FTC) 2020 ; vol. 3 2021 / p. 597–609 https://doi.org/10.1007/978-3-030-63092-8_40 [Conference Proceedings at Scopus](#) [Article at Scopus](#)

On the combined use of HLDDs and EFSMs for functional ATPG

Di Guglielmo, Giuseppe; Fummi, Franco; **Jenihhin, Maksim**; Pravadelli, Graziano; **Raik, Jaan; Ubar, Raimund-Johannes** 5th IEEE East-West Design & Test Symposium EWDTS 2007 : September 7-10, 2007, Yerevan, Armenia 2007 / p. 503-508 : ill

On the reuse of TLM mutation analysis at RTL

Guarnieri, Valerio; **Hantson, Hanno; Raik, Jaan; Jenihhin, Maksim; Ubar, Raimund-Johannes** Journal of electronic testing : theory and applications 2012 / p. 435-448 : ill <https://link.springer.com/article/10.1007/s10836-012-5303-6>

On using genetic algorithm for test generation

Brik, Marina; Raik, Jaan; Ubar, Raimund-Johannes; Ivask, Eero BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 233-236 : ill

Online testing of nondeterministic systems with the reactive planning tester

Vain, Jüri; Kääramees, Marko; Markvardt, Maili Dependability and computer engineering : concepts for software-intensive systems 2012 / p. 113-150 : ill <https://www.igi-global.com/chapter/online-testing-nondeterministic-systems-reactive/55327>

Optical detection methods for droplet microfluidic applications = Optilised tuvastusmeetodid tilkade mikrofluidiliste rakenduste jaoks

Pärnamets, Kaiser 2023 <https://doi.org/10.23658/taltech.31/2023> <https://digikogu.taltech.ee/et/Item/ffb85150-fb85-4a7c-b130-0d7f2c3b7fb5> https://www.ester.ee/record=b5569973*est

Optimierte Steuerung der Fehlersuche auf digitalen Leiterplatten

Thomä, E.; **Ubar, Raimund-Johannes** Proceedings of the 27th International Conference, Technical University of Ilmenau, October, 1982 1982 / p. 65-68

Optimization of built-in self-test in digital systems = Sisseehitatud enesetestimise optimeerimine digitaalsüsteemides **Kruus, Helena** 2011

Optimization of memory-constrained hybrid BIST for testing core-based systems

Jervan, Gert; Kruus, Helena; Orasson, Elmet; Ubar, Raimund-Johannes Proceedings of the IEEE 2nd International Symposium on Industrial Embedded Systems : SIES'2007 : Lisbon, Portugal, 4-6 July 2007 2007 / p. 71-77 <https://ieeexplore.ieee.org/document/4297319>

Optimization of memory-constrained hybrid BIST for testing core-based systems

Jervan, Gert; Kruus, Helena; Orasson, Elmet; Ubar, Raimund-Johannes Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK teise aastakonverentsi artiklite kogumik : 11.-12. mai 2007, Viinistu kunstimuseum 2007 / lk. 133-136 : ill

Optimization of the store-and-generate based built-in self-test

Ubar, Raimund-Johannes; Jervan, Gert; Kruus, Helena; Orasson, Elmet; Aleksejev, Igor BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 199-202 : ill

Out-of-step protection based on discrete angle derivatives

Tealane, Marko; Kilter, Jako; Bagleybter, Oleg; Heimisson, Birkir; Popov, Marjan IEEE Access 2022 / p. 78290-78305 <https://doi.org/10.1109/ACCESS.2022.3193390> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Overview about low-level and high-level decision diagrams for diagnostic modeling of digital systems

Ubar, Raimund-Johannes Facta Universitatis [Niš]. Series electronics and energetics 2011 / p. 303-324 : ill <http://dx.doi.org/10.2298/FUEE1103303U>

Overview about low-level and high-level decision diagrams for diagnostic modeling of digital systems

Ubar, Raimund-Johannes Proceedings of the Reed-Muller 2011 Workshop : May 25-26, 2011, Tuusula, Finland 2011 / p. 1-10 : ill <https://scindeks-clanci.ceon.rs/data/pdf/0353-3670/2011/0353-36701103303U.pdf>

Overview of e-learning environment for web-based study of testing and diagnostics of digital systems

Jutman, Artur; Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich Microelectronics education : proceedings of the 5th European

Workshop on Microelectronics Education, held in Lausanne, Switzerland, April 15-16, 2004 2004 / p. 253-258 : ill
https://link.springer.com/chapter/10.1007/978-1-4020-2651-5_41

Overview of e-learning environment for web-based study of testing and diagnostics of digital systems

Jutman, Artur; Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich 5th European Workshop on Microelectronics Education - EWME 2004, Lausanne, 2004 2004 / p. 173-176 https://link.springer.com/chapter/10.1007/978-1-4020-2651-5_41

Parallel critical path tracing fault simulation in sequential circuits

Kõusaar, Jaak; Ubar, Raimund-Johannes; Kostin, Sergei; Devadze, Sergei; Raik, Jaan Proceedings of 25th International Conference MIXED DESIGN OF INTEGRATED CIRCUITS AND SYSTEMS : MIXDES 2018 : Gdynia, Poland, June 21–23, 2018 2018 / p. 305-310 : ill <https://doi.org/10.23919/MIXDES.2018.8436880>

Parallel exact critical path tracing fault simulation with reduced memory requirements

Devadze, Sergei; Ubar, Raimund-Johannes; Raik, Jaan; Jutman, Artur 4th International Conference on Design and Technology of Integrated Systems in Nanoscale Era : DTIS'09 : Cairo, Egypt, April 6-9, 2009 2009 / p. 155-160 : ill
<https://ieeexplore.ieee.org/document/4938046>

Parallel pseudo-exhaustive testing of array multipliers with data-controlled segmentation

Oyeniran, Adeboye Stephen; Azad, Siavoosh Payandeh; Ubar, Raimund-Johannes 2018 IEEE International Symposium on Circuits and Systems (ISCAS) : 27-30 May 2018, Florence, Italy : proceedings 2018 / 5 p.: ill
<https://doi.org/10.1109/ISCAS.2018.8350936> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Performance estimation of embedded applications on microcontrollers

Ruberg, Priit; Lass, Keijo; Liiv, Elvar; Ellervee, Peeter 2017 IEEE Nordic Circuits and Systems Conference (NORCAS 2017): NORCHIP and International Symposium of System-on-Chip (SoC 2017) : Linköping, Sweden, 23-25 October, 2017 2017 / p. 170-175 : ill <http://dx.doi.org/10.1109/NORCHIP.2017.8124964>

Performance testing of frost damage model by hygrothermal simulation

Ilomets, Simo; Kalamees, Targo; Raado, Lembi-Merike Proceedings of the 5th International Building Physics Conference (IBPC) : Kyoto, Japan, May 28-31, 2012 2012 / p. 73-80 : ill

Pilvtestimisest

Leis, Paul A & A 2010 / 3, lk. 3-4 : ill https://artiklid.elnet.ee/record=b2183722*est

PLA-based FSM state assignment for testability

Kasirova, Lilia; Keevallik, Andres; Kruus, Margus Proceedings of the International Conference "Computer-Aided Design of Discrete Devices", Minsk, 1995 1995 / p. 50-51

Post-silicon validation of IEEE 1687 reconfigurable scan networks

Damljanovic, Aleksa; Jutman, Artur; Squillero, Giovanni; Tšertov, Anton 2019 IEEE European Test Symposium (ETS) : proceedings 2019 / 6 p. : ill <https://doi.org/10.1109/ETS.2019.8791546>

Power-constrained hybrid BIST test scheduling in an abort-on-first-fail test environment

He, Zhiyuan; Jervan, Gert; Peng, Zebo; Eles, Petru Proceedings : DSD'2005 : 8th Euromicro Conference on Digital System Design : Architectures, Methods and Tools : Porto, Portugal, August 30 - September 3, 2005 2005 / p. 83-86 : ill
<https://ieeexplore.ieee.org/document/1559782>

Precision force and move measurement systems in tribotechnical testing of journal bearings

Tamre, Mart Symposium naukowe : Mechatronica '92, Warszawa, 1992 1992

Prillid eelmisest sajandist viska prügikasti : [TTÜ füüsikalaboris testiti päikesepille]

Heinsoo, Enn Äripäev 2006 / 7. juuli, Puhkepäev, lk. 30-31 <https://www.aripaev.ee/uudised/2006/07/06/prillid-eelmisest-sajandist-viska-prugikasti>

Procedure for implementing new materials to the component additive method

Mäger, Katrin Nele; Just, Alar; Schmid, Joachim; Werther, Norman; Klippel, Michael; Brandon, Daniel; Frangi, Andrea Fire safety journal 2019 / p. 149-160 : ill <https://doi.org/10.1016/j.firesaf.2017.09.006> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Product platform modularization for test adapters

Sarkans, Martinš; Roosimölder, Lembit OST-03 Symposium on Machine Design 2003 / p. 100-106

Production quality related propagating faults of induction machines

Kudelina, Karolina; Asad, Bilal; Vaimann, Toomas; Rassõlkin, Anton; Kallaste, Ants 2020 XI International Conference on Electrical Power Drive Systems (ICEPDS), Saint-Petersburg, Russia, October 4-7, 2020 2020 / p. 311-315 : ill
<https://doi.org/10.1109/ICEPDS47235.2020.9249355>

Proficiency testing in the area of measuring instruments belonging to verification

Kulderknap, Edi; Laaneots, Rein Proc. 12th International Metrology Congress : Lyon, France 2005 / [6] p

A proposal for optimisation of low-powered FSM testing

Brik, Marina; Fomina, Jelena; Ubar, Raimund-Johannes Proceedings of IEEE East-West Design & Test Workshop (EWDWTW'05) : Odessa, Ukraine, September 15-19, 2005 2005 / p. 15-20

Provably correct test development for timed systems

Vain, Jüri; Anier, Aivo; Halling, Evelin Databases and information systems VIII : selected papers from the Eleventh International Baltic Conference, DB&IS 2014 2014 / p. 289-302 : ill <https://doi.org/10.3233/978-1-61499-458-9-289> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Provably correct test generation for online testing of timed systems

Vain, Jüri; Anier, Aivo; Halling, Evelin Databases and Information Systems : proceedings of the 11th International Baltic Conference, Baltic DB&IS 2014 : Tallinn, Estonia, 8-11 June, 2014 2014 / p. 337-348 : ill

Pseudojuhuslikud bitijadad ja nende juhuslikkuse testimine

Lossmann, Eerik; Meister, Ants Ringhääling 2003 : X rahvusvahelise telekommunikatsioonipäeva materjalid 2003 / lk. 54-59 : ill

Quality assurance system of metals testing laboratory

Päärsoo, Riho; Veinthal, Renno Proceedings of the 2nd International Conference, 27-29th April 2000, Tallinn, Estonia / DAAAM International Vienna, DAAAM National Estonia 2000 / p. 313-315

Quality assurance in mechanical testing laboratory by participating in proficiency test

Päärsoo, Riho; Veinthal, Renno; Peetsalu, Priidu; Saarna, Mart Proceedings of the 3rd International Conference Industrial Engineering - New Challenges to SME : 25-27 April 2002, Tallinn, Estonia 2002 / p. 242-244 : ill

Rail and rail weld testing

Saarna, Mart; Laansoo, Andres Proceedings of the 4th International Conference Industrial Engineering - New Challenges to SME : 29-30 April 2004, Tallinn, Estonia 2004 / p. 223-225 : ill

Raytraced images for testing the reconstruction of fibre orientation distributions

Eik, Marika; Herrmann, Heiko Proceedings of the Estonian Academy of Sciences 2012 / p. 128-136 : ill

Reactive testing of nondeterministic systems by test purpose-directed tester

Vain, Jüri; Kull, Andres; Kääramees, Marko; Markvardt, Maili; Raiend, Kullo Model-based testing for embedded systems 2012 / p. 425-452 : ill https://www.researchgate.net/publication/234117187_Reactive_Testing_of_Nondeterministic_Systems_by_Test_Purpose-Directed_Tester

Recognition and analysis of the contours drawn during the Poppelreuter's test

Nõmm, Sven; Bardoš, Konstantin; Mašarov, Ilja; Kozhenkina, Julia; Toomela, Aaro; Toomsoo, Toomas 15th IEEE International Conference on Machine Learning and Applications : 18-20 December 2016, Anaheim, California : proceedings 2016 / p. 170-175 : ill <http://doi.org/10.1109/ICMLA.2016.0036>

Reflection segments based robust PID controller solution for benchmark problem

Avanessov, Sergei; Nurges, Ülo 22nd Mediterranean Conference on Control and Automation (MED) : University of Palermo, June 16-19, 2014, Palermo, Italy 2014 / p. 1406-1411 : ill

Regular bridge inspection data improvement using non-destructive testing

Kušar, M.; Galvao, N.; Sein, Sander Life cycle analysis and assessment in civil engineering: towards an integrated vision : proceedings of the Sixth International Symposium on Life-Cycle Civil Engineering (IALCCE 2018), 28-31 October 2018, Ghent, Belgium 2019 / p. 1793-1797 <https://www.taylorfrancis.com/books/9781351857574> <https://doi.org/10.1201/9781351857574>

Replication-based deterministic testing of 2-dimensional arrays with highly interrelated cells

Azad, Siavoosh Payandeh; Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes 21st IEEE International Symposium on Design and Diagnostics of Electronic Circuits and Systems : DDECS 2018 : Budapest, Hungary 25-27 April, 2018 : proceedings 2018 / p. 21-26 : ill <https://doi.org/10.1109/DDECS.2018.00011>

Requirements for e-testing services in the afgREN cloud-based e-learning system

Saay, Salim; Laanpere, Mart; Norta, Alexander Technology Enhanced Assessment, 19th International Conference, TEA 2016, Tallinn Estonia, October 5-6, 2016 : revised selected papers 2017 / p. 133-147 https://doi.org/10.1007/978-3-319-57744-9_12 [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Requirements-driven model-based testing of the IP Multimedia Subsystem

Ernits, Juhan-Peep; Kääramees, Marko; Raiend, Kullo; Kull, Andres BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008,

RESCUE: interdependent challenges of reliability, security and quality in nanoelectronic systems

Jenihhin, Maksim; Raik, Jaan 2020 Design, Automation & Test in Europe Conference & Exhibition (DATE) : proceedings 2020 / art. 19690741 , 6 p <https://doi.org/10.23919/DATE48585.2020.9116558>

Research and training environment for digital design and test

Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich 34th ASEE/IEEE Frontiers in Education Conference : October 20-23, 2004, Savannah, GA 2004 / p. S3F-18-S3F-23 : ill <http://dx.doi.org/10.1109/FIE.2004.1408779>

Research and training environment for digital design and test

Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich Proceedings of the Eighth IASTED International Conference on Computers and Advanced Technology in Education : August 29-31, 2005, Oranjestad, Aruba 2005 / p. 232-237 : ill <https://ieeexplore.ieee.org/document/1408779>

Research and training scenarios for design and test of SOC [Electronic resource]

Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich WCETE 2004 : World Congress on Engineering and Technology Education : Engineering Education in the Changing Society : March 14-17, 2004, Guarujá/Santos, Brazil 2004 / p. 320-324 : ill. [CD-ROM]

Research in digital design and test at Tallinn University of Technology

Ubar, Raimund-Johannes; Jervan, Gert; Jutman, Artur; Raik, Jaan; Ellervee, Peeter; Kruus, Margus Radioelectronics & informatics 2008 / p. 4-12 : ill <http://www.ewdtest.com/ri/%E2%84%96-1-40-january-march-2008/>

Reseeding using compaction of pre-generated LFSR sequences

Jutman, Artur; Aleksejev, Igor; Raik, Jaan; Ubar, Raimund-Johannes ICECS 2008 : The 15th IEEE International Conference on Electronics, Circuits and Systems : 31st August to 3rd September 2008, Malta : conference guide 2008 / p. 215

Reseeding using compaction of pre-generated LFSR sub-sequences

Jutman, Artur; Aleksejev, Igor; Raik, Jaan; Ubar, Raimund-Johannes ICECS 2008 : The 15th IEEE International Conference on Electronics, Circuits and Systems : Malta 2008 / p. 1290-1295 : ill <http://dx.doi.org/10.1109/ICECS.2008.4675096>

Response of stress relieving and solution annealing treatment on tensile properties and fracture toughness of additively manufactured stainless steel 316L

Kumar, Deepak; Arya, Abhinav; Dutta, Shubhendu Anupam; Jhavar, Suyog; **Prashanth, Konda Gokuldoss**; Suwas, Satyam Journal of Materials Engineering and Performance 2025 / art. 145021 <https://doi.org/10.1007/s11665-025-11334-y>

Re-using chip level DFT at board level

Gu, Xinli; **Jutman, Artur** Proceedings : 2012 17th IEEE European Test Symposium (ETS) : May 28th–June 1st, 2012, Annecy, France 2012 / 1 p https://www.academia.edu/25351525/Re_using_chip_level_DFT_at_board_level

Robot reducing mining industry's environmental impact tested in Estonia

news.err.ee 2023 [Robot reducing mining industry's environmental impact tested in Estonia](#)

Role of experimental damage mechanics for the circular economy implementation in cotton industries

Hussein, Abrar; Abbas, Muhammad Mujtaba Journal of Modern Nanotechnology 2021 / 9 p <https://doi.org/10.53964/jmn.2021004>

RT-level identification of potentially testable initialization faults

Raik, Jaan; Fujiwara, Hideo; **Krivenko, Anna** The Ninth IEEE Workshop on RTL and High Level Testing (WRTL 2008), Sapporo, Japan 2008 / [6] p https://www.researchgate.net/publication/234032548_RT-level_identification_of_potentially_testable_initialization_faults

RT-level test point insertion for sequential circuits

Raik, Jaan; Govind, Vineeth; **Ubar, Raimund-Johannes** IWoTA 2004 : IEEE 1st International Workshop on Testability Assessment : November 2, 2004, Rennes, France : proceedings 2004 / p. 34-40 : ill <https://ieeexplore.ieee.org/document/1428412>

Run-time reconfigurable instruments for advanced board-level testing

Aleksejev, Igor; Jutman, Artur; Devadze, Sergei IEEE AUTOTESTCON 2016 : Anaheim, California, USA, September 12-15, 2016 : proceedings 2016 / p. 385-392 : ill <https://doi.org/10.1109/AUTEST.2016.7589627>

Run-time reconfigurable instruments for advanced board-level testing

Aleksejev, Igor; Jutman, Artur; Devadze, Sergei IEEE instrumentation & measurement magazine 2017 / p. 23-30 : ill <https://doi.org/10.1109/MIM.2017.8006390>

Safeguarding female reproductive health against endocrine disrupting chemicals-The FREIA project

Duursen, Majorie B.M. van; Boberg, Julie; Christiansen, Sofie; Jääger, Kersti; Salumets, Andres; **Velthut-Meikas, Agne** International journal of molecular sciences 2020 / art. 3215 <https://doi.org/10.3390/ijms21093215> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

A scalable technique to identify true critical paths in sequential circuits

Ubar, Raimund-Johannes; Kostin, Sergei; Jenihhin, Maksim; Raik, Jaan Proceedings 2017 IEEE 20th International Symposium on Design and Diagnostics of Electronic Circuit & Systems (DDECS) : April 19-21, 2017, Dresden, Germany 2017 / p. 152-157 : ill <https://ieeexplore.ieee.org/stamp/stamp.jsp?tp=&arnumber=7934553>

Scenario oriented model-based testing = Stsenaariumjuhitud mudelipõhine testimine

Halling, Evelin 2019 <https://digi.lib.ttu.ee/i/?11943>

Scenario-based Validation for Autonomous Vehicles with Different Fidelity Levels

Malayjerdi, Mohsen; Kaljavesi, Gemb; Diermeyer, Frank; **Sell, Raivo** 2023 IEEE Conference on Intelligent Transportation Systems (ITSC 2023) 2023 / 6 p <https://doi.org/10.1109/ITSC57777.2023.10422403>

Scenario-based validation of safety and performance of an autonomous vehicle by a software in loop simulation method = Autonomse sõiduki ohutuse ja jõudluse stsenaariumipõhine valideerimine tsüklisimulatsiooni meetodi abil

Malayjerdi, Mohsen 2023 <https://doi.org/10.23658/taltech.43/2023> <https://digikogu.taltech.ee/et/Item/5d3435ba-8ce1-4da6-8d16-4b279e88c861> https://www.ester.ee/record=b5574240*est

Second IEEE East-West Design and Test Workshop

Hahanov, Vladimir; Ubar, Raimund-Johannes IEEE journal of design & test of computers 2004 / p. 594

Selected issues of modeling, verification and testing of digital systems

Jutman, Artur 2004 https://www.ester.ee/record=b1989760*est

Self-diagnosis in digital systems = Isediagnoosivad digitaalsüsteemid

Kostin, Sergei 2012 https://www.ester.ee/record=b2757857*est

Self-driving bus to be tested in Mustamäe this summer [online resource]

news.err.ee 2021 ["Self-driving bus to be tested in Mustamäe this summer "](#)

Self-learning tool for digital test

Ubar, Raimund-Johannes; Orasson, Elmet; Evtartson, Teet Proceedings of 2nd International Conference "Distance Learning - Educational Sphere of the XXI Century" 2002 / p. 36-38 : ill

Self-testing of pipe-lined signal processing architectures at-speed

Gorev, Maksim; Ubar, Raimund-Johannes; Ellervee, Peeter Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK seitsmenda aastakonverentsi artiklite kogumik : 15.-16. novembril 2013, Haapsalu 2013 / p. 25-28 : ill

Sequential circuit test generation using decision diagram models

Raik, Jaan; Ubar, Raimund-Johannes Design, Automation and Test in Europe : DATE : Conference and Exhibition 1999 : Munich, Germany, March 9-12, 1999 : proceedings 1999 / p. 736-740: ill https://www.cs.york.ac.uk/rts/docs/SIGDA-Compendium-1994-2004/papers/1999/date99/pdffiles/11e_1.pdf

Sequential circuits BIST synthesis from signal specifications

Raik, Jaan; Jenihhin, Maksim; Adelbert, Rain Proceedings 23rd NORCHIP Conference : Oulu, Finland, 21-22 November 2005 2005 / p. 196-199 : ill <https://ieeexplore.ieee.org/document/1597023>

Sequential circuits BIST with status bit control

Raik, Jaan; Orasson, Elmet; Ubar, Raimund-Johannes Proceedings of the 11th International Conference : Mixed Design of Integrated Circuits and Systems : MIXDES 2004 : Szczecin, Poland, 24-26 June 2004 2004 / p. 507-510 : ill https://pld.ttu.ee/~raiub/files/aaaaa_pulk/MIXDES/jaan.pdf

Sequential test set compaction in LFSR reseeding

Jutman, Artur; Aleksejev, Igor; Raik, Jaan Design and test technology for dependable systems-on-chip 2011 / p. 476-493 : ill <https://ieeexplore.ieee.org/document/4738292>

A set of tools for estimating quality of built-in self-test in digital circuits

Jervan, Gert; Markus, Antti; Paomets, Priidu; Raik, Jaan; Ubar, Raimund-Johannes Proceedings of the International Symposium on Signals, Circuits and Systems, Iasi (Romania), October 2-3, 1997 1997 / p. 362-365

Shift register based TPG for at-speed interconnect BIST

Jutman, Artur MIEL 2004 : 24th International Conference on Microelectronics : Niš, Serbia and Montenegro, 16-19 May 2004 : proceedings. Volume 2 2004 / p. 751-754 : ill <https://ieeexplore.ieee.org/document/1314941?signout=success>

Simulation and automated test development system for digital devices

Birger, Alexander BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn

Simulation of wear in a rolling-sliding contact by a semi-Winkler model and the Archard's wear law

Telliskivi, Tanel Wear 2004 / 7/8, p. 817-831 : ill <https://www.sciencedirect.com/science/article/abs/pii/S0043164803005246>

Single-stage buck–boost inverters: a state-of-the-art survey

Azizi, Mohammadreza; Husev, Oleksandr; Vinnikov, Dmitri Energies 2022 / art. 1622 <https://doi.org/10.3390/en15051622> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Sisseehitatud isetestimine digitaalsüsteemides

Kruus, Helena A & A 2011 / lk. 32-37 : ill https://artiklid.elnet.ee/record=b2472216*est

Smooth coordination and management of impact of EstLink 2 transmission testing on electricity markets, power system operations and system technical performance

Rauhala, T.; Laasonen, M.; Kilter, Jako CIGRE Session 2016 : 21-26 August 2016, Paris, France 2016 / p. 1-11

SoC and board modeling for processor-centric board testing

Tšertov, Anton; Ubar, Raimund-Johannes; Jutman, Artur; Devadze, Sergei 14th Euromicro Conference on Digital System Design : Architectures, Methods and Tools : DSD 2011 : 31 August - 2 September 2011, Oulu, Finland : proceedings 2011 / p. 575-582 : ill <https://ieeexplore.ieee.org/document/6037463>

SoC and NoC test technology [Electronic resource] : [PowerPoint presentation]

Raik, Jaan Design and Test Technology for Dependable Hardware/Software Systems : DEDIS/DAAD Summer Academy : BTU Cottbus, Sept. 1st-12th, 2008 2008 / [41] p. : ill. [CD-ROM]

Soft-sensor approach in characterization of VRLA batteries

Tenno, Ander; Tenno, Robert; Suntuio, Teuvo Proc. INTELEC 2001 2001 / p. 554-562
<https://ieeexplore.ieee.org/document/988617/similar#similar>

Software environment for synthesis of testable FSM through decomposition

Devadze, Sergei; Sudnitsõn, Aleksander 2008 26th International Conference on Microelectronics (MIEL 2008) : proceedings 2008 / p. 433-436 <https://ieeexplore.ieee.org/document/4559314>

Software-based self-test for microprocessors with high-level decision diagrams = Mikroprotsessorite tarkvara-põhine enesetestimine kõrgtasandi otsustusdiagrammide põhjal

Jasnetski, Artjom 2018 <https://digi.lib.ttu.ee/ii/?10629> https://www.ester.ee/record=b5151486*est

Software-based self-test generation for microprocessors with high-level decision diagrams

Ubar, Raimund-Johannes; Tšertov, Anton; Jasnetski, Artjom; Brik, Marina LATW2014 : 15th IEEE Latin-American Test Workshop : Fortaleza, Brazil, March 12th-15th, 2014 2014 / [6] p. : ill

Software-based self-test generation for microprocessors with high-level decision diagrams

Jasnetski, Artjom; Ubar, Raimund-Johannes; Tšertov, Anton; Brik, Marina Proceedings of the Estonian Academy of Sciences 2014 / p. 48-61 : ill https://artiklid.elnet.ee/record=b2665215*est <https://doi.org/10.3176/proc.2014.1.08> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Software-based self-test with decision diagrams for microprocessors

Ubar, Raimund-Johannes; Jasnetski, Artjom; Tšertov, Anton; Oyeniran, Adeboye Stephen 2018

Solaride lõpetas testsõidu maastikupõlengu tõttu

Hansar, Helina postimees.ee 2023 [Solaride lõpetas testsõidu maastikupõlengu tõttu](#)

Some aspects about insulator puncture tests

Annus, Aleksander; Metusala, Tiit; Oidram, Rein; Tapupere, Olev Stockholm Power Tech, June 18-22 1995 : International Symposium on Electric Power Engineering. High-voltage technology 1995 / p. 18-21: ill

Some aspects of testing speaking skills in UK

Putrova, M.; Gridneva, I. V Regional Seminar East-West Meeting of Language Testing, Tallinn, September 2-4, 1991 : summaries 1991 / p. 74-76

Special session : approximation and fault resiliency of DNN accelerators

Ahmadilivani, Mohammad Hasan; Barbareschi, Mario; Barone, Salvatore; Bosio, Alberto; Daneshtalab, Masoud; Torca, Salvatore Della; Gavarini, Gabriele; Jenihhin, Maksim; Raik, Jaan; Taheri, Mahdi 2023 IEEE 41st VLSI Test Symposium (VTS) : proceedings 2023 / 10 p. : ill <https://doi.org/10.1109/VTS56346.2023.10140043> [Conference proceeding at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Statistical strength of brittle materials : test methods and weibull modulus

Preis, Irina Proceedings of the 3rd International Conference Industrial Engineering - New Challenges to SME : 25-27 April 2002, Tallinn, Estonia 2002 / p. 205-208 : ill

Step-wise approximated multi-cycle sine wave for dynamic tests of AD converters

Land, Raul XVI IMEKO World Congress : IMEKO2000 : proceedings of the 5th Workshop on ADC Modelling and Testing (EWADC'2000) : Vienna, Austria, Sept. 25-28, 2000 2000 / p. 217-220

Structural fault collapsing by superposition of BDDs for test generation in digital circuits

Ubar, Raimund-Johannes; Mironov, Dmitri; Raik, Jaan; Jutman, Artur Proceedings of the Eleventh International Symposium on Quality Electronic Design ISQED 2010 : March 22-24, 2010 San Jose, California USA 2010 / p. 250-257 : ill
<https://ieeexplore.ieee.org/document/5450451>

Structural test generation with employment of multiple observation time strategy

Skobtsov, Vadim BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 299-302: ill

Structure and properties of HVOF-sprayed and PTA-welded cermet hard phase reinforced Fe-matrix based coatings

Kulu, Priit; Zikin, Arkadi; Surženkov, Andrei; Tarbe, Riho 2nd Mediterranean Conference & New Challenges on Heat Treatment and Surface Engineering : Dubrovnik-Cavtat, Croatia, 11-14 June 2013 2013 / p. 37-44
<https://www.inderscienceonline.com/doi/abs/10.1504/IJMMP.2014.061054>

Studioosus testis liiklust : [marsruudil TTÜ peahoone - Viru keskus]

Nassar, Bia; Käger, Maarja Studioosus 2008 / märts, lk. 10

Study of effects of modulated microwaves by method of face masking

Rodina, Anastasia; Lass, Jaanus; Bachmann, T.; Hinrikus, Hiie Proceedings of the 25th Annual International Conference of the IEEE Engineering in Medicine and Biology Society. Vol. 25, A New Beginning for Human Health : volume 4 of 4 : 17-21 September 2003, Cancun, Mexico 2003 / p. 3249-3252 <https://ieeexplore.ieee.org/document/1280836>

Subsurface of Cr₃C₂-Ni cermets modified by wear [Electronic resource]

Antonov, Maksim; Hussainova, Irina Proceedings of the 10th International Conference of the European Ceramic Society 2008 / ? p. [CD-ROM] https://www.academia.edu/24587100/Subsurface_of_Cr_3_C_2_Ni_Cermets_Modified_by_Wear

A suite of IEEE 1687 benchmark networks

Tšertov, Anton; Jutman, Artur; Devadze, Sergei 2016 IEEE International Test Conference (ITC) : proceedings 2016 / art. 6.1, p. 1-10 : ill <https://doi.org/10.1109/TEST.2016.7805840>

A symbolic approach to model-based online testing = Mudelipõhine online-testimine kasutades sümbolarvutust

Kääramees, Marko 2012 http://www.ester.ee/record=b2890159*est

Symbolic test generation for hierarchically modeled digital systems

Zaugarov, Viktor 1993 https://www.ester.ee/record=b2090336*est

Synthesis of decision diagrams from clock-driven multi-process VHDL descriptions for test generation

Leveugle, R.; Ubar, Raimund-Johannes Proceedings of the 5th International Conference on Mixed Design of Integrated Circuits and Systems, Lodz, Poland, June 18-20, 1998 1998 / p. 353-358 <https://hal.science/ccsd-00015077/>

Synthesis of hierarchically testable FSM networks

Kasirova, Lilia; Keevalik, Andres; Kruus, Margus BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 347-352: ill

Synthesis of high-level decision diagrams for functional test pattern generation

Ubar, Raimund-Johannes; Raik, Jaan; Karputkin, Anton; Tombak, Mati Proceedings of the 16th International Conference Mixed Design of Integrated Circuits and Systems MIXDES 2009 : Lodz, Poland, 25-27 June, 2009 2009 / p. 519-524 : ill

Synthesis of multiple fault oriented test groups from single fault test sets [Electronic resource]

Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan 2013 8th International Conference on Design & Technology of Integrated Systems in Nanoscale Era (DTIS) : 26-28 March 2013, Abu Dhabi, UAE 2013 / p. 36-41 : ill [CD-ROM]

Synthesis of on-line planning tester for non-deterministic EFSM models

Kääramees, Marko; Vain, Jüri; Raiend, Kullo Testing - Practice and Research Techniques : 5th International Academic and Industrial Conference TAIC PART 2010 : Windsor, UK, September 3-5, 2010 : proceedings 2010 / p. 147-154
https://link.springer.com/chapter/10.1007/978-3-642-15585-7_14

Synthesis of test purpose directed reactive planning tester for nondeterministic systems

Vain, Jüri; Raiend, Kullo; Kull, Andres; Ernits, Juhan-Peep 22nd IEEE/ACM International Conference on Automated Software Engineering (ASE 2007) : November 5-9, 2007, Atlanta, Georgia, USA 2007 / p. 363-372
https://www.researchgate.net/publication/220883693_Synthesis_of_test_purpose_directed_reactive_planning_tester_for_nondeterministic_systems

Synthesis of test purpose directed reactive planning tester for nondeterministic systems (extended abstracts)

Vain, Jüri; Raiend, Kullo; Kull, Andres; Ernits, Juhan-Peep NWTP'07/FLACOS'07 Workshop Proceedings : Oslo, 10-12 October 2007 / p. 55-57

A synthesis-agnostic behavioral fault model for high gate-level fault coverage

Karputkin, Anton; Raik, Jaan 2016 Design, Automation & Test in Europe Conference & Exhibition (DATE) : proceedings 2016 / p. 1124-1127 : ill <https://ieeexplore.ieee.org/document/7459477/figures#figures>

System assurances : modeling and management

2022 <https://doi.org/10.1016/C2020-0-03092-6>

System modeling for processor-centric test automation = Süsteemide modelleerimine protsessorikesksete testprogrammide sünteesi automatiseerimiseks

Tšertov, Anton 2012 https://www.ester.ee/record=b2751131*est

A system of test patterns to check and validate the semantic hierarchies of wordnet-type dictionaries = Testmustrite süsteem wordnet-tüüpi sõnastike semantiliste hierarhiate kontrollimiseks ja valideerimiseks

Lohk, Ahti 2015 http://www.ester.ee/record=b4495412*est

A systematic approach on modeling refinement and regression testing of real-time distributed systems

Pal, Deepak; Vain, Jüri IFAC-PapersOnLine 2019 / p. 1091-1096 <https://doi.org/10.1016/j.ifacol.2019.11.341> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

zamiaCAD : understand, develop and debug hardware designs

Jenihhin, Maksim; Tihomirov, Valentin; Saif Abrar, Syed; Raik, Jaan; Bartsch, Günter DUHDe : 1st Workshop on Design Automation for Understanding Hardware Designs : March 28, 2014 : Friday Workshop at DATE 2014, Dresden, Germany 2014 / p. 1-6

Tallinna kooli õpilased löid Baltikumi esimese keskkonnasõbralike filtritega õhupuha

Õigus, Birgit moodnekodu.delfi.ee 2023 [Tallinna kooli õpilased löid Baltikumi esimese keskkonnasõbralike filtritega õhupuha](#)

Tallinnas avati NATO DIANA piirkondlik keskus

Eesti Elu : [Kanada ajaleht] 2024 / lk. 2

TalTech käivitab 5G testvõrgud. Eesti firmad saavad arendada teenuseid välisturgudele

Kald, Indrek ituudised.ee 2023 [TalTech käivitab 5G testvõrgud. Eesti firmad saavad arendada teenuseid välisturgudele](#)

TalTechis hakatakse testima 6G võrku. Margus Rohtla: „Oleks vaid minu õpingute ajal sellised võimalused olnud!“

Lindpere, Elle Isabel forte.delfi.ee 2023 [TalTechis hakatakse testima 6G võrku. Margus Rohtla: „Oleks vaid minu õpingute ajal sellised võimalused olnud!“](#)

Targeting conditional operations in sequential test pattern generation

Raik, Jaan; Ubar, Raimund-Johannes 9th European Test Symposium : ETS'04 : Congress Center, Ajaccio, Corsica, France, May 23-26, 2004 / p. 17-18 : ill

https://www.researchgate.net/publication/239717327_Targeting_Conditional_Operations_in_Sequential_Test_Pattern_Generation

Tarkvara omaduste parandamine kasutatavuse testimise kaudu

Eessaar, Erki A & A 1999 / 2, lk. 26-31

Tarkvara testimisest ja testijatest Eestis

Markvardt, Maili A & A 2010 / 3, lk. 62-65

Teaching advanced test issues in digital electronics

Ubar, Raimund-Johannes; Orasson, Elmet; Raik, Jaan; Wuttke, Heinz-Dietrich Proceedings of the 6th IEEE International Conference on Information Technology Based Higher Education and Training : ITHET : July 7-9, 2005, Juan Dolio, Dominican Republic 2005 / p. S2B-1 - S2B-6 : ill <http://dx.doi.org/10.1109/ITHET.2005.1560318>

Teaching digital RT-level self-test using a Java applet

Devadze, Sergei; Jutman, Artur; Sudnitsõn, Aleksander; Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich 20th IEEE NORCHIP Conference : Copenhagen, Denmark, November 11-12, 2002 / p. 322-328 : ill

Teaching digital system test

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Kruus, Margus The 27th EAAEIE Annual Conference : June 7-9, 2017, Grenoble 2017 / [6] p

Teaching digital test with BIST analyzer

Jutman, Artur; Tšertov, Anton; Tšepurov, Anton; Aleksejev, Igor; Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich 19th EAAEIE Annual Conference : June 29-July 2, 2008, Tallinn, Estonia : formal proceedings 2008 / p. 123-128 : ill
<http://dx.doi.org/10.1109/EAAEIE.2008.4610171>

Teaching test and design for testability with TURBO-TESTER software

Jervan, Gert; Markus, Antti; Paomets, Priidu; Raik, Jaan; Ubar, Raimund-Johannes Proceedings of the 3rd Workshop on Mixed Design of Integrated Circuits and Systems, Lodz, May 1996 1996 / p. 589-594

Tehnikaülikoolis on uus katseseade, mis võib välja panna Abramsi tanki kaalu

Ehitaja 2023 / lk. 35 : fot https://www.ester.ee/record=b1072123*est https://artiklid.elnet.ee/record=b2904596*est

Temporally extended high-level decision diagrams for PSL assertions simulation

Jenihhin, Maksim; Raik, Jaan; Tšepurov, Anton; Ubar, Raimund-Johannes Proceedings : Thirteenth IEEE European Test Symposium : ETS 2008 : 25-29 May 2008, Verbania, Italy 2008 / p. 61-68 : ill <https://ieeexplore.ieee.org/document/4556029>

Tension stiffening model based on test data of RC beams

Idnurm, Siim; Bacinskas, Darius; Gribniak, Viktor; Sokolov, Aleksandr; Kaklauskas, Gintaris The 10th International Conference "Modern Building Materials, Structures and Techniques" : May 19-21, 2010, Lithuania : selected papers 2010 / p. 810-814 : ill
https://www.researchgate.net/publication/265635200_Tension-stiffening_model_based_on_test_data_of_RC_beams

10th IEEE European Test Symposium

Ubar, Raimund-Johannes; Prinetto, Paolo; Raik, Jaan IEEE journal of design & test of computers 2005 / p. 480-481 : phot
<http://dx.doi.org/10.1109/MDT.2005.106>

"Tervis ruudus", ehk, Tippkeskuse CEBE lugu

Ubar, Raimund-Johannes Teadusmõte Eestis (X). Tehnikateadused. 3 : [artiklikogumik] 2019 / lk. 200-215 : ill., fot
https://www.ester.ee/record=b5208765*est

Test cost minimization for hybrid BIST

Jervan, Gert; Peng, Zebo; Ubar, Raimund-Johannes IEEE International Symposium on Defect and Fault Tolerance in VLSI Systems : 25-27 October 2000, Yamanashi, Japan : proceedings 2000 / p. 283-298 : ill
<https://ieeexplore.ieee.org/abstract/document/887168>

Test development and deployment tool-set for mixed-signal and digital devices

Mellik, Andres; Raik, Jaan BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 163-166 : ill

Test driven domain modelling

Piho, Gunnar; Tepandi, Jaak; Parman, Marko; Puusep, Viljam; Roost, Mart MIPRO 2011 : 34th International Convention on Information and Communication Technology, Electronics and Microelectronics : May 23-27, 2011, Opatija, Croatia : proceedings 2011 / p. 576-581 <https://ieeexplore.ieee.org/stamp/stamp.jsp?arnumber=5967121>

Test generation for control faults in digital systems

Dušina, Julia; Brik, Marina BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 325-330: ill

Test generation for digital systems

Ubar, Raimund-Johannes Digest of papers - FTCS 13th Annual International Symposium on Fault-Tolerant Computing, June 28 - 30, 1983, Milano, Italy 1983 / p. 374-377

Test generation for digital systems at functional level

Ubar, Raimund-Johannes; Kuchcinski, Ktysztof; Peng, Z. Research report LiTH-IDA-R-90-06, Linköping University, Sweden 1990 / p. 1-21

Test generation for finite state machines

Ubar, Raimund-Johannes; Brik, Marina BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 233-236: ill

Test generation for microprocessor control mechanisms

Lohuaru, Tõnu; Ubar, Raimund-Johannes FTSD-10 : Deseta Mezdunarodnaja Konferencija "Nadezdnost i Diagnostika na ECM. Mikrokompjutri i Sistemi", Varna, Bulgaria, 1987 = 10th International Conference on Fault-Tolerant Systems and Diagnostics (1987) 1987 / p. 305-311

Test generation for microprocessors on alternative graphs

Alango, Villem; Kont, Toomas; Ubar, Raimund-Johannes 33. Internationales Wissenschaftliches Kolloquium : 24.-28.10.1988. H.3 Vortragsreihe B, technische und angewandte Informatik/Computertechnik 1988 / p. 11-14

Test generation for sequential digital systems based on symbolic simulation

Skobtsov, Vadim; Skobtsov, Yu. BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 341-344: ill

Test generation techniques and algorithms

Ubar, Raimund-Johannes; Gramatova, Elena; Fisherova, Maria Handbook of testing electronic systems 2005 / p. 99-173 : ill

Test generation with structurally synthesized BDD models

Raik, Jaan; Ubar, Raimund-Johannes Proceedings of the 5th Electronic Devices and Systems Conference, Brno, June 11-12, 1998 1998 / p. 66-68

Test method for determining radiation absorptivity and emissivity coefficients of ACSR conductors

Kiitam, Ivar 18th International Symposium "Topical Problems in the Field of Electrical and Power Engineering". Doctoral School of Energy and Geotechnology III : Toila, Estonia, January 14-19, 2019 : [proceedings] 2019 / p. 185-186 : ill
https://www.ester.ee/record=b5183874*est

Test method for the total content of non-volatile phenols in wastewater

Johannes, Ille; Mölder, Leevi; Tiikma, Laine Oil shale 1998 / 3, p. 232-238

Test pattern generation at the behavioral level from VHDL circuit description containing several processes

Gramatova, Elena; Bezakova, Jana; Cibakova, Tatiana BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 145-148

Test program generation for microprocessor systems

Dušina, Julia 1993 https://www.ester.ee/record=b2090526*est

Test scenario generator learning for model-based testing of mobile robots

Kanter, Gert; Liibert, Marti Ingmar System assurances : modeling and management 2022 / p. 67-84 <https://doi.org/10.1016/B978-0-323-90240-3.00005-9>

Test scenario specification language for model-based testing

Halling, Evelin; Vain, Jüri; Boyarchuk, Artem; Illiashenko, Oleg International Journal of Computing 2019 / p. 408-421 : ill
<http://www.computingonline.net/computing/article/view/1611> <https://doi.org/10.47839/ijc.18.4.1611> Journal metrics at Scopus Article at Scopus

Test set minimization using bipartite graphs

Markus, Antti; Raik, Jaan; Ubar, Raimund-Johannes BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 175-178: ill

Test strategy for a 486 computer multichip module

Magnhagen, Bengt BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 339-340: ill

Test synthesis from register-transfer level descriptions

Raik, Jaan; Paomets, Priidu BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 311-314: ill

Test time minimization for hybrid BIST of core-based systems

Jervan, Gert; Eles, Petru; Peng, Zebo; **Ubar, Raimund-Johannes; Jenihhin, Maksim** Journal of computer science and technology 2006 / 6, p. 907-912 : ill <https://link.springer.com/article/10.1007/s11390-006-0907-x>

Test time minimization for hybrid BIST of core-based systems

Jervan, Gert; Eles, Petru; Peng, Zebo; **Ubar, Raimund-Johannes; Jenihhin, Maksim** 12th Asian Test Symposium (ATS 2003) : 17-19 November 2003, Xian, China 2003 / p. 318-325 : ill <https://link.springer.com/article/10.1007/s11390-006-0907-x>

Test time minimization for hybrid BIST with test pattern broadcasting

Ubar, Raimund-Johannes; Jenihhin, Maksim; **Jervan, Gert;** Peng, Zebo IEEE NORCHIP 2003 : 21 Norchip Conference : Riga, Latvia, 10-11 November 2003 : proceedings 2003 / p. 112-116 : ill <https://www.ida.liu.se/labs/eslab/publications/pap/db/norchip03.pdf>

Testability analysis for efficient register-transfer level test generation [Electronic resource]

Nõmmeots, Tanel; Raik, Jaan; Ubar, Raimund-Johannes 9th International Conference MIXDES 2002 : Mixed Design of

Testability analysis of digital design verification

Hahanov, V.; Kaminska, M.; **Fomina, Jelena** BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 171-174 : ill

Testability calculation for digital circuits with decision diagrams

Ubar, Raimund-Johannes 3rd IEEE Latin American Test Workshop : LATW'02, Montevideo, Uruguay, February 10-13, 2002 : digest of papers 2002 / p. 137-143 : ill <https://dblp.org/rec/conf/latw/Ubar02.html>

Testability guided hierarchical test generation with decision diagrams

Ubar, Raimund-Johannes; Raik, Jaan; Nõmmeots, Tanel 20th IEEE NORCHIP Conference : Copenhagen, Denmark, November 11-12, 2002 / p. 265-271 <https://www.semanticscholar.org/paper/Testability-Guided-Hierarchical-Test-Generation-Ubar-Raik/c6301ac35d003c92f3867f26e2e75b87e1ad9b47>

Testentwurf für digitale Geräte mit Hilfe der Alternativgraphen

Voolaine, Andrus; Pall, Martin; **Plakk, Mari** Fehler in Automaten 1989 / S. 31-44 : ill

Tester partitioning and synchronization algorithm for testing real-time distributed systems

Pal, Deepak; Vain, Jüri Proceedings of the 10th Junior Researcher Workshop on Real-Time Computing : JRWRTC 2016 : Brest, France, October 19-21, 2016 / p. 13-16 : ill <http://jrwrtc2016.gforge.inria.fr/>

Testid harjutamiseks

Teichmann, Mare; Anton, Riina 1997

Testieren der kommunikativen Sprachkompetenz

Serwuta, A. V Regional Seminar East-West Meeting of Language Testing, Tallinn, September 2-4, 1991 : summaries 1991 / p. 92-94

Testing a method for evaluating the performance of coatings on end mills in semi-industrial conditions

Leemet, Tõnu; Allas, Jaanus; Madissoo, Marten; Adoberg, Eron; **Saar, Rando** Agronomy research 2014 / p. 263-268 : ill <https://www.cabidigitallibrary.org/doi/pdf/10.5555/20143184842> [Journal metrics at Scopus](#) [Article at Scopus](#)

Testing as a means of consolidation of students' knowledge

Shaymardanova, Sh.Kh. V Regional Seminar East-West Meeting of Language Testing, Tallinn, September 2-4, 1991 : summaries 1991 / p. 94-95

Testing beyond the SoCs in a lego style

Tšertov, Anton; Jutman, Artur; Devadze, Sergei Proceedings of IEEE East-West Design & Test Symposium (EWDTS'10) : St. Petersburg, Russia, September 17-20, 2010 / p. 334-338 : ill <https://ieeexplore.ieee.org/document/5742052>

Testing different power system out-of-step detection algorithms

Tealane, Marko 18th International Symposium "Topical Problems in the Field of Electrical and Power Engineering". Doctoral School of Energy and Geotechnology III : Toila, Estonia, January 14-19, 2019 : [proceedings] 2019 / p. 199-200 : ill https://www.ester.ee/record=b5183874*est

Testing English for specific purposes

Tsurova, I. V Regional Seminar East-West Meeting of Language Testing, Tallinn, September 2-4, 1991 : summaries 1991 / p. 100-102

Testing flash A/D converters in real time

Vedral, Josef; Krecl, Jaromir BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 67-70: ill

Testing foreign language proficiency

Andrejeva, I.V.; Akhtyamova, F.A.; Khvesina, M.V. V Regional Seminar East-West Meeting of Language Testing, Tallinn, September 2-4, 1991 : summaries 1991 / p. 8-10

Testing generic strong accessibility of nonlinear control systems via polynomial (quadratic) immersion

Carravetta, Francesco; Sarafrazi, Mohammad Amin; Bartosiewicz, Zbigniew; **Kotta, Ülle** 61st IEEE Conference on Decision and Control, CDC 2022, Cancun, 6 December - 9 December 2022, proceedings 2022 / p. 1841-1846 <https://doi.org/10.1109/CDC51059.2022.9992952> [Conference Proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Testing in evaluating the effectiveness of teacher's work

Golikova, Zh. V Regional Seminar East-West Meeting of Language Testing, Tallinn, September 2-4, 1991 : summaries 1991 / p. 40-43

Testing in teaching speaking to non-communicative learners

Krasyuk, N.I. V Regional Seminar East-West Meeting of Language Testing, Tallinn, September 2-4, 1991 : summaries 1991 / p. 61-62 https://www.ester.ee/record=b1257906*est

Testing knowledge-based systems : a case study and implications

Heino, P.; Jaakkola, Hannu; **Tepandi, Jaak** Proceedings of the SAFECOMP '92 1992

Testing of object-oriented programs

Tepandi, Jaak; Trausan-Matu S. Data processing, compiler writing, problems of programming 1989 / p. 20-27

Testing of rail welds

Päärsoo, Riho; Saarna, Mart Engineering Materials & Tribology : BALTMATTRIB - 2003 : 12th International Baltic Conference : October 2-3, 2003, Tallinn, Estonia : abstracts 2003 / p. 58

Testing of Software and Communicating Systems : work-in-progress and position papers, tool demonstrations, and tutorial abstracts of TestCom/Fates 2007 : Tallinn, Estonia, 26-29 June 2007

Petrenko, Alexandre; Veanes, Margus; Tretmans, Jan; Grieskamp, Wolfgang 2007 https://www.ester.ee/record=b2271047*est

Testing of systems using software

Ubar, Raimund-Johannes Concise encyclopedia of software engineering 1993 / p. 352-356

Testing procedure for gunn oscillator as a load variation detector

Krasavin, Jevgeni XIX Convetion on Radio Science, Otaniemi, Oct. 25-26, 1993 : abstracts of papers. Report 21 1993 / p. 37-38

Testing requirements for the intensive course conditions

Gnatkevich, Y.; Leshchinskaya, V. V Regional Seminar East-West Meeting of Language Testing, Tallinn, September 2-4, 1991 : summaries 1991 / p. 37-40

Testing speaking skills

Gredasova, N. V Regional Seminar East-West Meeting of Language Testing, Tallinn, September 2-4, 1991 : summaries 1991 / p. 47-48

Testing strategies for networks on chip

Ubar, Raimund-Johannes; Raik, Jaan Networks on chip 2003 / p. 131-152 : ill https://link.springer.com/chapter/10.1007/0-306-48727-6_7

Testing technique for embedded ADC

Zagursky, V.; Gertners, A. BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 167-170: ill

Testing the basic writing skills

Hromov, Vjatšeslav V Regional Seminar East-West Meeting of Language Testing, Tallinn, September 2-4, 1991 : summaries 1991 / p. 56-58

Testing the characteristics of phasor measurement units using real-time digital simulator

Trummal, Tarmo 18th International Symposium "Topical Problems in the Field of Electrical and Power Engineering". Doctoral School of Energy and Geotechnology III : Toila, Estonia, January 14-19, 2019 : [proceedings] 2019 / p. 229-230 : ill https://www.ester.ee/record=b5183874*est

Testing the level of development of skills and habits of dialogic speech with students of non-linguistic colleges : (on the material of the English language)

Omeltchenko, L.; Yatel, G.; Barkhatov, N.; Provotar, T. V Regional Seminar East-West Meeting of Language Testing, Tallinn, September 2-4, 1991 : summaries 1991 / p. 70-73

Testing the location and discrimination capability of Nordic-Baltic virtual seismic network in the Baltic region

Nikulin, V.G.; **Soosalu, Heidi Elisabet**; Uski, Marja; Pacesa, Andrius The 39th Nordic Seismology Seminar : June 4-6, 2008 : Oslo, Norway 2008 / p. 29

Testing tools

Jutman, Artur Handbook of testing electronic systems 2005 / p. 361-365 : ill

Testing tools

Raik, Jaan Handbook of testing electronic systems 2005 / p. 373-378 : ill

Testing tools for training and education

Balaž, M.; **Jutman, Artur; Raik, Jaan; Ubar, Raimund-Johannes** Proceedings of the 12th International Conference : Mixed Design of Integrated Circuits and Systems : MIXDES 2005 : Krakow, Poland, 22-25 June, 2005. Vol. 1 of 2 2005 / p. 671-676 : ill

Testing web services with model-based mutation

Siavashi, Faezeh; Iqbal, Junaid; Truscan, Dragos; **Vain, Jüri** Software Technologies : 11th International Joint Conference, ICSOFT 2016 : Lisbon, Portugal, July 24–26, 2016 : revised selected papers 2017 / p. 45-67 https://doi.org/10.1007/978-3-319-62569-0_3
[Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

TestIt: an open-source scalable long-term autonomy testing toolkit for ROS

Kanter, Gert; Vain, Jüri Conference Proceedings of 2019 10th International Conference on Dependable Systems, Services and Technologies DESSERT'2019, United Kingdom, Leeds, June 5-7, 2019 2019 / art. 8770011, p. 45-50
<http://dx.doi.org/10.1109/DESSERT.2019.8770011>

Testrig for complete acoustic characterization of turbochargers

Tiikoja, Heiki; **Rämmal, Hans**; Abom, Mats; Boden, Hans International Aeronautics and Aeroacoustics Conference, Stockholm, Sweden, 07-09 June, 2010 2010 https://www.researchgate.net/publication/268581496_Test-Rig_for_Complete_Acoustic_Characterization_of_Turbochargers

Tests of graphics rendering in browsers

Henno, Jaak; Jaakkola, Hannu; Mäkelä, Jukka Sixth Workshop on Software Quality Analysis, Monitoring, Improvement, and Applications : SQAMIA 2017 : Belgrade, Serbia, 11-13.09.2017 : proceedings 2017 / p. 3:1-3:10 <https://ceur-ws.org/Vol-1938/paper-hen.pdf> [Conference proceedings at Scopus](#) [Article at Scopus](#)

The control of jitter and wander within digital networks

Kravets, Valeri Ringhääling '99 : VI Rahvusvahelise Telekommunikatsioonipäeva konverentsi ettekannete materjalid 1999 / lk. 68-73: ill

The didactical and pedagogical advantages of testing in computer assisted language learning (CALL)

Ilyinskaja, L.; Lasmane, B.; Vevere, I. V Regional Seminar East-West Meeting of Language Testing, Tallinn, September 2-4, 1991 : summaries 1991 / p. 49-51

The dildis-project-using applets for more demonstrative lectures in digital systems design and test

Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich Proceedings of the 31st ASEE/IEEE Frontiers in Educations Conference : FIE'2001 : Reno, Nevada 2001 / p. SIE-2-7 <https://ieeexplore.ieee.org/document/963996>

The dildis-project-using applets for more demonstrative lectures in digital systems design and test

Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich FIE 2001 : 31st Annual Frontiers in Educations Conference : Impact on Engineering and Science Education : Reno, Nevada, October 10-13, 2001 : conference program 2001 / p. 83
<https://ieeexplore.ieee.org/document/963996>

The effects of intermittent charging on VRLA battery life expectancy in telecom applications

Suntio, Teuvo; Waltari, P.; **Tenno, Ander**; Tenno, Robert Proc. 24th INTELEC Conf., Montreal, Canada, 2002 2002 / p. 121-127
<https://ieeexplore.ieee.org/document/1048644>

The handle of substation remote terminal unit configuration

Dmitrienko, Igor; Laugis, Juhan Scientific journal of Riga Technical University. Serija 4, Power and electrical engineering 2010 / p. 63-68 : ill <https://ui.adsabs.harvard.edu/abs/2010SJRP...26...64D/abstract>

The method for determinating the dynamic hardness of materials

Kleis, Ilmar; Remi, Toomas International Symposium on Machine Design OST 2001 : [Tallinn, Estonia, October 4-5, 2001] : abstracts 2001 / [1] p

The method of conformance testing for presentation data transfer syntax

Shevelkov, V. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 359-364: ill

The stability of phenolic compounds in fruit, berry, and vegetable purees based on accelerated shelf-life testing methodology

Saarniit, Kärt; Lang, Hanna; Kuldjärv, Rain; Laaksonen, Oskar; Rosenvald, Sirli Foods 2023 / art. 1777
<https://doi.org/10.3390/foods12091777> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

The surface miner sustainable oil-shale mining technology testing results in Estonia

Nikitin, Oleg; Väli, Erik; Pastarus, Jüri-Rivaldo; Sabanov, Sergei Proceedings of the Sixteenth International Symposium on Mine Planning and Equipment Selection (MPES 2007) and the Tenth International Symposium on Environmental Issues and Waste Management in Energy and Mineral Production (SWEMP 2007) : Bangkok, Thailand, December 11-13, 2007 2007 / p. 678-687

The system of language testing at Lvov Polytechnic Institute

Belyakevich, I.I.; Knjazevsky, B.N.; Savenko, O.M. V Regional Seminar East-West Meeting of Language Testing, Tallinn, September 2-4, 1991 : summaries 1991 / p. 10-12

The testing of the bioimpedance measurement ASIC

Sillakivi, Peeter Telekommunikatsioon 2002 : IX rahvusvahelise telekommunikatsioonipäeva materjalid 2002 / lk. 15-20 : ill

The toxicity of brewed coffee according to the ecotoxicological tests

Ivask, Angela; Reiman, Rain; Rätsep, Anneli; Maloverjan, Alla; Laht, Mailis; Kahru, Anne Microbiological Safety of Food : joint conference organized by Society for Applied Microbiology (UK), World Health Organization and Estonian Society for Microbiology : 10-11 May 2000, Tartu, Estonia 2000 / l. 54

Thermal investigations of microsystems

Szekely, Vladimir BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 29-36: ill

Thermographic measurement and simulation of power losses due to interlaminar contacts in electrical sheets

Shah, Sahas Bikram; Osemwinyen, Osaruyi; Rasilo, Paavo; **Belahcen, Anouar**; Arkkio, Antero IEEE transactions on instrumentation and measurement 2018 / p. 2628–2634 : ill <https://doi.org/10.1109/TIM.2018.2829321>

Time semantics of executable activity diagrams for relativized conformance testing

Iqbal, Junaid; Truscan, Dragos; **Vain, Jüri** MODELS '20: Proceedings of the 23rd ACM/IEEE International Conference on Model Driven Engineering Languages and Systems: Companion Proceedings 2020 / p. 251-256 <https://doi.org/10.1145/3417990.3421399>

A tool for random test generation targeting high diagnostic resolution

Osimiry, Emmanuel Ovie; Kostin, Sergei; Raik, Jaan; Ubar, Raimund-Johannes BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 79-82 : ill http://www.ester.ee/record=b2150914*est

A tool set for teaching design-for-testability of digital circuits

Kostin, Sergei; Orasson, Elmet; Ubar, Raimund-Johannes EWME 2016 : 11th European Workshop on Microelectronics Education : May 11-13, 2016, Southampton, UK 2016 / [6] p. : ill <https://doi.org/10.1109/EWME.2016.7496466>

Towards a unified model for test and design quality

Aas, Einar J. BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 17-20: ill

Towing test tank control system

Tamre, Mart; Liyanage, Dhanushka Chamara; Hiimaa, Maito NCSIE : труды Международной мультikonференции Сетевое партнерство в науке, промышленности и образовании : Санкт-Петербург, Россия, 4-6 июля 2016 2016 / p. 275-282 : ill

Toxicities of detergents used in cleaning chemicals and hygiene products in a test battery of Ex Vivo and in Vitro assays

Andersson, Maria A.; Nagy, Szabolcs; Mikkola, Raimo; **Kurnitski, Jarek**; Salonen, Heidi Sisäilmastoseminaari 2019 : 14.3.2019 2019 / p. 297-302 https://www.sisailmauutiset.fi/Sisailmastoseminaari_2019.pdf

Toxicity of 39 MEIC chemicals to bioluminescent Photobacteria (the Biotox™ test) : correlation with other test systems

Kahru, Anne; Borchardt, Barbara ATLA 1994 / p. 147-160

Trainer 1149 : a boundary scan simulation bundle with hardware support for labs

Shibin, Konstantin; Jutman, Artur Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK viienda aastakonverentsi artiklite kogumik : 25.-26. novembril 2011, Nelijärve 2011 / p. 135-138 : ill

Trainer 1149: a boundary scan simulation bundle for labs

Jutman, Artur; Ubar, Raimund-Johannes; Devadze, Sergei; Shibin, Konstantin; Rosin, Vjatšeslav MIXDES 2011 : 18th International Conference "Mixed Design of Integrated Circuits and Systems" : June 16-18, 2011, Gliwice, Poland 2011 / p. 520-525

Transportvõrkude testimistulemuste analüüs

Kravets, Valeri Raadiotehnika 2001 : VIII rahvusvahelise telekommunikatsioonipäeva materjalid 2001 / lk. 42-45 : ill

Trend analysis of water quality data in Lake Ladoga and the River Neva

Bovykin, I.V.; Raspletina, G.F.; Rumyantsev, A.O. Environmental Protection Strategy Standardization and Control of Pollution Load on the Marine Environment : 1st International Conference, 20-24 September 1993, Tallinn, Estonia : abstracts 1993 / p. 33

TTBist: a DfT tool for enhancing functional test for SoC

Hermann, K.; **Raik, Jaan; Jenihhin, Maksim** BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of

Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 191-194 : ill

TTÜ katsetas arvutihiiri : [tootearenduse tudengid Birthe Matsi ja Triin Toon]

Üliõpilasleht 2005 / lk. 4

TTÜ teadlased arendasid maailmas ainulaadse narkotestri

Männiste, Agnes Mente et Manu 2017 / lk. 18-21 : fot http://www.ttu.ee/public/m/mente-et-manu/MM_01_2017/index.html
https://artiklid.elnet.ee/record=b2811464*est

TTÜ testib veine rohelisel moel

Olesk, Arko Postimees 2012 / lk. 6 <https://www.postimees.ee/800228/ttu-testib-veine-rohelisel-moel>

TTÜ-s testiti esimesena maailmas arvutihiirte täpsust

Ummelas, Mart Õpetajate Leht 2005 / 26. aug., lk. 18 https://artiklid.elnet.ee/record=b2347931*est

Turbo tester : a CAD system for teaching digital test

Jervan, Gert; Markus, Antti; Paomets, Priidu; Raik, Jaan; Ubar, Raimund-Johannes Microelectronics education : proceedings of the 2nd European Workshop held in Noordwijkerhout, The Netherlands, 14-15 May 1998 1998 / p. 287-290: ill
https://link.springer.com/chapter/10.1007/978-94-011-5110-8_66

Turbo Tester : a low cost PC-based CAD system for training digital test

Ubar, Raimund-Johannes SampTA'95 : 1995 Workshop on Sampling Theory & Applications, Jurmala, Latvia, September 20-22, 1995 1995

Turning JTAG inside out for fast extended test access

Devadze, Sergei; Jutman, Artur; Aleksejev, Igor; Ubar, Raimund-Johannes 10th IEEE Latin American Test Workshop : 2-5 March 2009, Brazil 2009 / [6] p. : ill <https://ieeexplore.ieee.org/document/4813799>

A Two-layered approach for the validation of an operational autonomous shuttle

Malajerdi, Mohsen; Goss, Quentin A.; Akbas, Mustafa Ilhan; Sell, Raivo; Bellone, Mauro IEEE Access 2023 / p. 89124-89137
<https://doi.org/10.1109/ACCESS.2023.3306602> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Two-level simulation-based test generation for finite state machines

Brik, Marina; Ubar, Raimund-Johannes 17th NORCHIP Conference : Oslo, Norway, 8-9 November 1999 : proceedings 1999 / p. 211-216: ill

Ultra-low latency NoC testing via pseudo-random test pattern compaction

Tatenguem, Herve; Govind, Vineeth; Raik, Jaan SoC 2012 : International Symposium on System-on-Chip 2012 : Tampere, Finland, October 11-12, 2012 2012 / 6 p. : ill <https://ieeexplore.ieee.org/document/6376370>

Understanding boundary scan test with Trainer 1149

Jutman, Artur; Devadze, Sergei; Shibin, Konstantin; Rosin, Vjatšeslav; Ubar, Raimund-Johannes 22nd EAAEIE annual conference : June, 13-15, 2011, Maribor, Slovenija : conference book 2011 / p. 21-22 <https://ieeexplore.ieee.org/document/6165727>

Unmanned ground vehicle energy efficiency validation in territory surveillance mission

Väljaots, Eero; Sell, Raivo; Rimasauskas, Marius Mechatronic Systems and Materials VII 2016 / p. 164-170
<https://doi.org/10.4028/www.scientific.net/SSP.251.164> [Conference Proceedings at Scopus](#) [Article at Scopus](#)

Unsupervised fouling reconstruction in the pipe bend

lablonskyi, Denys; Rasgado Moreno, Carlos Omar; Ratssepp, Madis; Klami, Arto; Hæggström, Edward; Salmi, Ari 2023 IEEE International Ultrasonics Symposium (IUS) 2023 / 3 p <https://doi.org/10.1109/IUS51837.2023.10306373>

Use of a newly-developed portable capillary electrophoresis analyser to detect drugs of abuse in oral fluid: A case study

Saar-Reismaa, Piret; Brilla, Chelsa-Ann; Leiman, Kristiina; Kaljurand, Mihkel; Vaher, Merike; Kulp, Maria; Mazina-Šinkar, Jekaterina Talanta 2020 / art. 120662, 9 p <https://doi.org/10.1016/j.talanta.2019.120662> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Use of luminescent bacteria in toxicity testing

Kahru, Anne Biobalt'92 : Biotechnology in Estonia, Latvia and Lithuania : Tallinn, November 1992 : conference abstracts 1992 / p. 33

Using constraint solver in Test Pattern Generation Tool

Viilukas, Taavi; Raik, Jaan Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK kolmanda aastakonverentsi artiklite kogumik : 25.-26. aprill 2008, Voore külalistemaja 2008 / p. 14-17 : ill

Using of small punch test for determination of tensile properties for power plant steels

Klevtsov, Ivan; Dedov, Andrei; Molodtsov, Artjom Proceedings of the 6th International Conference of DAAAM Baltic "Industrial Engineering" : 24-26th April 2008, Tallinn, Estonia. [2] 2008 / p. 473-477 : ill <https://www.semanticscholar.org/paper/USING-OF-SMALL-PUNCH-TEST-FOR-DETERMINATION-OF-FOR/a805d3e782523dc705919256b453002f5a71598f>

Using simulation statistics for bug localization in RTL designs

Tihhomirov, Valentin; Jenihhin, Maksim; Raik, Jaan Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK seitsmenda aastakonverentsi artiklite kogumik : 15.-16. novembril 2013, Haapsalu 2013 / p. 107-110 : ill

Using STLs for effective in-field test of GPUs

Rodriguez Condia, Josie E.; Da Silva, Felipe Augusto; **Bagbaba, Ahmet Cagrl**; Guerrero-Balaguera, Juan-David; Hamdioui, Said; Sauer, Christian; Reorda, Matteo Sonza IEEE Design and Test 2023 / p. 109-117 <https://doi.org/10.1109/MDAT.2022.3188573> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Using Tabu Search for optimization of memory-constrained hybrid BIST

Kruus, Helena; Jervan, Gert; Ubar, Raimund-Johannes BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 155-158 : ill

Using Tabu Search for optimization of memory-constrained hybrid BIST

Kruus, Helena; Jervan, Gert; Ubar, Raimund-Johannes Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK kolmanda aastakonverentsi artiklite kogumik : 25.-26. aprill 2008, Voore külalistemaja 2008 / p. 85-88 : ill

Using Tabu search method for optimizing the cost of hybrid BIST

Kruus, Helena; **Ubar, Raimund-Johannes; Jervan, Gert**; Peng, Z. XVI Conference on Design of Circuits and Integrated Systems : Porto, Portugal, 2001 2001 / p. 445-450 <https://citeseerx.ist.psu.edu/document?repid=rep1&type=pdf&doi=e97bb394ff71aa0affcc5fb372404bbc246888a8>

Using test pattern generation tool decider in hardware verification

Viilukas, Taavi; Raik, Jaan Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK teise aastakonverentsi artiklite kogumik : 11.-12. mai 2007, Viinistu kunstimuuseum 2007 / lk. 166-169 : ill

Uued viisid bituumensideainete kvaliteediomaduste määramiseks ja võimalused nende rakendamiseks, pidades silmas konkreetsele objektile vastavaid kriteeriume sideaine eeldatavast elueast ja kasutuskohast lähtuvalt : teadus- ja arendustöö lõpparuanne [Võrguteavik]

Aavik, Andrus; Kulp, Maria; Sillamäe, Sven; Lill, Kristjan; Hesp, Simon A. M.; Teymourpour, Ponya; Bahia, Hussain 2015 https://www.mnt.ee/sites/default/files/survey/bituumeniuurung_2015.pdf

Uus projekt tõstab tarkvara kvaliteeti

Lepmets, Marion Äripäev 2006 / 23. veebr., lk. 17 <https://www.aripaev.ee/uudised/2006/02/22/uus-projekt-tostab-tarkvara-kvaliteeti>

Wafer-level die re-test success prediction using machine learning

Selg, Hardi; **Jenihhin, Maksim; Ellervee, Peeter** 21st IEEE Latin-American Test Symposium (LATS) 2020 : proceedings 2020 / 5 p <https://doi.org/10.1109/LATS49555.2020.9093672>

Validation, verification and testing of object-oriented programs

Tepandi, Jaak; Trausan-Matu, S. Research report Institute for Computers and Informatics 1989 / p. 1-22

Validation, verification and testing of object-oriented programs

Tepandi, Jaak; Trausan-Matu, S. Studies and researches in computers and informatics 1990 / 1, p. 113-128

Variability of high voltage circuit breaker performance parameters for condition monitoring

Asefi, Sajjad; Kiitam, Ivar; Manninen, Henri; Kilter, Jako; Tealane, Marko; Landsberg, Mart International Conference on Condition Monitoring, Diagnosis and Maintenance 2023 - CMDM 2023 (7th edition), Bucharest, Romania, October 31th - November 2nd, 2023 : proceedings 2023 / p. 1-10

Water hammer and column separation due to accidental simultaneous closure of control valves in a large scale two-phase flow experimental test rig

Bergant, Anton; Westende, Jos M.C.van't; **Koppel, Tiit**; Gale, Janez; Hou, Qingzhi; Pandula, Zoltan; Tijsseling, Arris S. 2010 https://www.researchgate.net/publication/280624441_Water_hammer_and_column_separation_due_to_accidental_simultaneous_closure_of_control_valves_in_a_large-scale_two-phase_flow_experimental_test_rig

Water hammer and column separation due to accidental simultaneous closure of control valves in a large scale two-phase flow experimental test rig

Bergant, Anton; Westende, Jos M.C.van't; **Koppel, Tiit**; Gale, Janez; Hou, Qingzhi; Pandula, Zoltan; Tijsseling, Arris S. Proceedings of the ASME 2010 Pressure Vessels & Piping Division/K-PVP Conference : PVP2010 : July 18-22, 2010, Bellevue, Washington, USA 2010 / [10] p.: ill

https://www.researchgate.net/publication/280624441_Water_hammer_and_column_separation_due_to_accidental_simultaneous_closure_of_control_valves_in_a_large-scale_two-phase_flow_experimental_test_rig

Ways for board and system test to benefit from FPGA embedded instrumentation

Ehrenberg, Heiko; **Odintsov, Sergei; Devadze, Sergei; Jutman, Artur; Aleksejev, Igor**; Wenzel, Thomas 2019 IEEE AUTOTESTCON 2019 / 10 p : ill <https://doi.org/10.1109/AUTOTESTCON43700.2019.8961057>

Web based tools for synthesis and testing of digital devices

Devadze, Sergei; Jutman, Artur; Kruus, Margus; Sudnitsõn, Aleksander; Ubar, Raimund-Johannes Proceedings of the International Conference on Computer Systems and Technologies (e-Learning) : CompSysTech'2002, Sofia, Bulgaria, 20-21 June 2002 / p. 1.9-1 - 1.9-6 : ill https://www.researchgate.net/publication/250738271_Web_Based_Tools_for_Synthesis_and_Testing_of_Digital_Devices

Web services testing in e-learning environments

Õunapuu, Enn; Tepandi, Jaak Second International Conference on Multimedia and Information & Communication Technologies in Education (m-ICTE 2003) : Badajoz, Spain, 2003 2003 / p. 1170-1177

Web-based environment for digital electronics test tools

Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes; Schneider, Andre Virtual Enterprises and collaborative networks : IFIP 18th World Computer Congress [and] TC5/WG5.5 - 5th Working Conference on Virtual Enterprises : 22-27 August 2004, Toulouse, France 2004 / p. 435-442 : ill https://link.springer.com/chapter/10.1007/1-4020-8139-1_46

Web-based framework for parallel distributed test [Electronic resource]

Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes 2008 IEEE Design and Diagnostics of Electronic Circuits and Systems : Bratislava, Slovakia, April 16-18, 2008 2008 / p. 271-274 : ill. [CD-ROM] <https://ieeexplore.ieee.org/document/4538800>

WebTT - digitaalskeemide testimine ja diagnostikaalaste õppelaborite e-keskkond : [TTÜ arvutitehnika instituut esitles e-Ülikooli konverentsil kolme õppetöös kasutatavat süsteemi]

Robal, Tarmo; Orasson, Elmet Mente et Manu 2005 / 5. mai, lk. 5 : fot https://www.ester.ee/record=b1242496*est

Verification of new 1000 [degree] C tester designed for investigation of wear-corrosion properties of advanced materials for high temperature applications

Antonov, Maksim; Hussainova, Irina; Kimmari, Eduard; Juhani, Kristjan Proceedings of the 6th International Conference of DAAAM Baltic "Industrial Engineering" : 24-26th April 2008, Tallinn, Estonia. [2] 2008 / p. 395-399 : ill <http://innomet.ttu.ee/daaam08/online/Materials%20Engineering/Antonov.pdf>

Verification of the test quality

Matrosova, Anjela; Bochun, Tatiana BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 307-310: ill

Verification, testing and validation of rule-based expert systems

Tepandi, Jaak Preprints 11th IFAC World Congress "Automatic Control in the Service of Mankind" : Tallinn, Estonia, USSR, August 13-17, 1990. Vol. 7 1990 / p. 162-167

VHDL based test generation system

Jervan, Gert; Markus, Antti; Raik, Jaan; Ubar, Raimund-Johannes Proceedings of the 5th Electronic Devices and Systems Conference, Brno, June 11-12, 1998 1998 / p. 145-148

VHDL design debug framework based on zamiaCAD

Tihhomirov, Valentin; Tšepurov, Anton; Saif Abrar, Syed; Jenihhin, Maksim; Raik, Jaan DATE 2013 : Design Automation and Test in Europe, March 18-22, 2013, Grenoble, France 2013 / [1] p. : ill

VILAB test generation tools running under the MOSCITO system

Schneider, Andre; **Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes** VILAB User Forum : Győr, Hungary, 2001 2001 / [12] p

Õpilastele tarnib kiirteste uus firma

Hussar, Karoliina Eesti Päevaleht 2021 / Lk. 7 <https://dea.digar.ee/article/eestipaevaleht/2021/11/24/7.5>

Über einige Probleme der Testsatzanalyse für digitale Systeme

Ubar, Raimund-Johannes Wissenschaftliche Zeitschrift 1976 / p. 447-449 https://www.ester.ee/record=b1516616*est

Über einige Probleme der Testsatzanalyse für digitale Systeme

Ubar, Raimund-Johannes Nachrichtentechnik, Elektronik : technisch-wissenschaftliche Zeitschrift für die gesamte elektronische Nachrichtentechnik 1977 / p. 149-150 https://www.ester.ee/record=b1550811*est

Алгоритм оценки качества вероятностного тестирования цифровых схем

Grigorjeva, Ksenja Машинное проектирование электронных устройств и систем 1989 / с. 97-103

Анализ диагностических тестов для комбинационных цифровых схем методом обратного прослеживания неисправностей

Ubar, Raimund-Johannes Автоматика и телемеханика 1977 / с. 168-176 https://www.ester.ee/record=b1515055*est

Анализ методов тестирования микропроцессоров

Toomsalu, Arvo Синтез и диагностика цифровых устройств и систем 1982 / с. 53-62 : илл https://www.ester.ee/record=b1328194*est
<https://digikogu.taltech.ee/et/Item/febd586e-d7fa-4fbd-bf41-40576a75f94b>

В волости Раэ тестируют беспилотные автобусы

Stolitsa.ee 2023 [В волости Раэ тестируют беспилотные автобусы](#)

В Ласнамяэ до 29 апреля можно прокатиться на беспилотном автобусе [Online resource]

rus.err.ee 2022 ["В Ласнамяэ до 29 апреля можно прокатиться на беспилотном автобусе"](#)

Вероятностное тестирование цифровых схем и альтернативные графы

Ubar, Raimund-Johannes Машинное проектирование электронных устройств и систем 1989 / с. 89-96

Генерирование групповых тестов для цифровых схем на модели альтернативных графов

Kivi, E.; Ubar, Raimund-Johannes Тезисы докладов XXXI студенческой научно-технической конференции 1980 / с. 52-55
https://www.ester.ee/record=b1319482*est

Генерирование реализации шума на ЭВМ

Lumberg, Tõnu; Ots, Avo Тезисы докладов XXXI студенческой научно-технической конференции 1980 / с. 60
https://www.ester.ee/record=b1319482*est

Генерирование тестов для комбинационных схем с кратными неисправностями

Ubar, Raimund-Johannes Вопросы проектирования и расчета автоматических информационных систем : [Сборник статей] 1978 / с. 6-10

Генерирование тестов микропроцессорных систем на модели АГ

Ubar, Raimund-Johannes Техническая диагностика : Тезисы докладов III Международного симпозиума ИМЕКО, Москва, окт. 1983 1983 / с. 100-103

Генерирование тестов по функциональной модели микропрограммного автомата

Viilup, Agu Проектирование и диагностика вычислительных средств 1987 / с. 64-75 : илл https://www.ester.ee/record=b1273275*est

Генерирование универсальных тестов для дискретных устройств на альтернативных графах

Ubar, Raimund-Johannes Методы синтеза и диагностирования цифровых схем 1985 / с. 51-60 : ил
https://www.ester.ee/record=b1302568*est <https://digikogu.taltech.ee/et/Item/e00f2c15-fd8c-48ac-9963-76da1d62d592>

Дедуктивный анализ тестов в синхронных цифровых схемах без обратных связей

Viilup, Agu; Kitsnik, Peeter; Ubar, Raimund-Johannes Материалы конференции "Автоматизация технического проектирования ЦВМ" (май-июнь 1977 г.) 1977 / с. 178-181

Единый подход к решению задач тестового диагностирования дискретных систем

Ubar, Raimund-Johannes; Lohuaru, Tõnu; Evartson, Teet IX симпозиум по проблеме избыточности в информационных системах, 3-8 июня 1986 г. : тезисы докладов 1986 / с. 32-35

Единый подход к решению задач тестового диагностирования дискретных систем

Ubar, Raimund-Johannes; Lohuaru, Tõnu; Evartson, Teet IX симпозиум по проблеме избыточности в информационных системах, 3 июня - 8 июня 1986 года : Тезисы докладов 1986 / с. 32-35

Измерение параметров аналоговых микросборок применением компенсационного метода

Laansoo, Ants; Männama, Vello; Pikkov, Otto Машинное проектирование электронных устройств и систем 1988 / с. 105-112

Использование тепловизионного контроля при испытаниях железа статоров генераторов

Dorovatovski, Nikolai; Rozov, G. Электрические станции 2003 / 11, с. 44-46 : ил

Испытание коротких железобетонных балок на действие поперечных сил

Otsmaa, Vello Теория и расчет тонкостенных пространственных конструкций 1984 / с. 21-29 : ил
https://www.ester.ee/record=b1351702*est <https://digikogu.taltech.ee/et/Item/108ebc34-9030-40f2-9b6b-d7d76669d96c>

Исследование и разработка методов анализа диагностических тестов для цифровых схем : автореферат ...

кандидата технических наук (05.13.01)

Kitsnik, Peeter 1981 https://www.ester.ee/record=b1337813*est

Исследование и разработка методов анализа диагностических тестов для цифровых схем : диссертация на соискание ученой степени кандидата технических наук (05.13.01)

Kitsnik, Peeter 1980 https://www.ester.ee/record=b4632972*est

Исследование и разработка методов тестового диагностирования дискретных систем : автореферат ... доктора технических наук (05.13.13)

Ubar, Raimund-Johannes 1986 https://www.ester.ee/record=b1564280*est

Исследование и разработка методов управления поиском дефектов в цифровых схемах : автореферат кандидата технических наук (05.13.01)

Evertson, Teet 1986 https://www.ester.ee/record=b1301665*est

Исследование износостойкости материалов в условиях эрозии скользящей струей абразива : автореферат ... кандидата технических наук (05.02.04)

Stupnitski, Anatoli 1977 http://www.ester.ee/record=b1563942*est

Исследование износостойкости подшипниковых материалов на четырехшариковых трибометрах

Ajaots, Mairo; Lepre, M. Тезисы докладов XXXI студенческой научно-технической конференции 1980 / с. 85-86
https://www.ester.ee/record=b1319482*est

Исследование форм предъявления лексических единиц в тесте исходного уровня

Murumets, S.; Võrk, Evi-Mai; Kokkota, Valmar Тезисы докладов II зонального совещания заведующих кафедрами иностранных языков неязыковых факультетов и вузов Эстонской ССР, Белорусской ССР, Латвийской ССР, Литовской ССР и Калининградской области : Тарту, (4-7 мая 1977 г.) 1977 / с. 82-84 https://www.ester.ee/record=b1317941*est

Лингводидактическое тестирование

Kokkota, Valmar 1989 https://www.ester.ee/record=b1521036*est

Маятниковый склерометр для испытания эластомеров

Pallase, Ado Трение и износ в машинах. 14 1987 / с. 3-13

Метод дедуктивного анализа тестов для логических схем

Viilup, Agu; Kitsnik, Peeter; Ubar, Raimund-Johannes Вопросы технической диагностики 1977 / с. [?]
https://www.ester.ee/record=b2353473*est

Методы тестового диагностирования дискретных систем

Ubar, Raimund-Johannes Машинное проектирование электронных устройств и систем 1986 / с. 57-69

Некоторые проблемы создания стандартных методов испытания на абразивное изнашивание в свете энергетической концепции : автореферат ... кандидата технических наук (05.02.04)

Pappel, Toivo 1975 http://www.ester.ee/record=b1318201*est

Некоторые проблемы создания стандартных методов испытания на абразивное изнашивание в свете энергетической концепции : диссертация ... кандидата технических наук : 05.02.04 - трение и износ в машинах

Pappel, Toivo 1975 http://www.ester.ee/record=b2332186*est

О вынужденных колебаниях камертона при возбуждении одной ветви

Kenk, Kalju; Mäeots, R. Тезисы докладов XXXI студенческой научно-технической конференции 1980 / с. 46-47
https://www.ester.ee/record=b1319482*est

О проверке полноты контролирующих тестов цифровых схем

Ubar, Raimund-Johannes XV Областная научно-техническая конференция по системам и средствам управления, май 1979 года : Тезисы докладов Пермь / с. 74-75

О синтезе тестов для микропроцессорных БИС

Lohuaru, Tõnu; Ubar, Raimund-Johannes Проектирование и диагностика вычислительных средств 1987 / с. 30-42 : илл
https://www.ester.ee/record=b1273275*est

О функциональном моделировании диагностических тестов в схемах ЦВМ

Vaher, V.; Ubar, Raimund-Johannes XX студенческая научно-техническая конференция вузов Прибалтийских республик, Белорусской ССР и Молдавской ССР : тезисы докладов. Часть 1 1974 / с. 133 https://www.ester.ee/record=b1306141*est

Подход к автоматизации построения тестов для микропроцессорных БИС

Kont, Toomas Машинное проектирование электронных устройств и систем 1988 / с. 55-64

Построение тестов для дискретных систем на простых альтернативных графах

Voolaine, Andrus; Pall, M.; Ubar, Raimund-Johannes Тезисы докладов всесоюзной научно-технической конференции "Методы и средства борьбы с помехами в цифровой технике" 1986 / с. 88-89

Построение тестов для неисправностей комбинационных схем на основе анализа ортогональных дизъюнктивных нормальных форм, представляемых альтернативными графами

Matrosova, A.Yu.; Pleshkov, A.G.; Ubar, Raimund-Johannes Автоматика и телемеханика 2005 / с. 158-174 : ил
<http://mi.mathnet.ru/at1333>

Построение тестов для проверки операционных частей дискретных систем

Ubar, Raimund-Johannes; Lohuaru, Tõnu; Štraube, B.; Elst, G. Машинное проектирование электронных устройств и систем 1988 / с. 65-77

Применение модели АГ для автоматизации синтеза тест-программ микропроцессорных БИС

Ubar, Raimund-Johannes Электронная техника. Серия 8, Управление качеством, стандардизация, метрология, испытания : научно-технический сборник 1985 / с. 110-113 https://www.ester.ee/record=b2160764*est

Проектирование контролепригодных дискретных систем : учебное пособие

Ubar, Raimund-Johannes 1988 https://www.ester.ee/record=b1225400*est

Проектирование контрольных экспериментов в автоматизированной системе контроля цифровых автоматов "НАКС"

Voolaine, Andrus; Jõgi, Aksel; Pall, Martin Синтез и диагностика цифровых устройств и систем 1982 / с. 3-21 : илл
https://www.ester.ee/record=b1328194*est <https://digikogu.taltech.ee/et/Item/febd586e-d7fa-4fbd-bf41-40576a75f94b>

Система синтеза тестовых программ для дискретных объектов диагностирования (ОД)

Zaugarov, Viktor; Saarepera, Maimu; Storožev, Sergei Tallinna Tehnikaülikooli Toimetised 1990 / lk. 78-89: ill

Сотрудничество по тестированию в КПИ, РПИ и ТПИ

Kokkota, Valmar Тезисы докладов II зонального совещания заведующих кафедрами иностранных языков неязыковых факультетов и вузов Эстонской ССР, Белорусской ССР, Латвийской ССР, Литовской ССР и Калининградской области : Тарту, (4-7 мая 1977 г.) 1977 / с. 53-55 https://www.ester.ee/record=b1317941*est

Тестирование баз знаний

Terandi, Jaak Обработка данных. Построение трансляторов. Вопросы программирования 1988 / с. 3-11

Тестирование производственных систем по критерию покрытия операторов

Terandi, Jaak Известия АН Эстонии. Физика. Математика 1990 / 1, с. 9-13

Тестовая диагностика цифровых устройств : учебное пособие. II, Синтез и анализ тестов. Дешифрация диагностических экспериментов

Ubar, Raimund-Johannes 1981 https://www.ester.ee/record=b1326795*est

Трансляция выходных реакций многовыходного модуля

Plakk, Mari Расчет и проектирование приборов, устройств и систем технической кибернетики 1981 / с. 63-72 : илл
https://www.ester.ee/record=b1319172*est <https://digikogu.taltech.ee/et/Item/4c9b1559-97b9-4d9b-bac8-6c40840ba442>

Фактор времени в языковых тестах

Kokkota, Valmar; Võrk, Evi-Mai Исследования по методике преподавания иностранных языков 1978 / с. 41-49
https://www.ester.ee/record=b1314236*est

Формальный синтез тестов для микропроцессоров

Toomsalu, Arvo; Ubar, Raimund-Johannes XVII областная научно-техническая конференция по вопросам повышения эффективности и качества систем и средств управления (май 1981 г.): Тезисы докладов 1981 / с. 111-112

Формирование тест-программ для микропроцессорных БИС при автоматическом генерировании тестов

Alango, Villem; Kont, Toomas; Ubar, Raimund-Johannes Машинное проектирование электронных устройств и систем 1988 / с. 78-87

Центробежное устройство для испытания конструкционных материалов на изнашивание

Ajaots, Mairo; Ianeots, Rein; Lees, Rein; Saar, Bernhard Трение и износ в машинах. 13 1985 / с. 89-94

Экспертная система тестирования программ по спецификациям

Terandi, Jaan III Всесоюзная конференция "Автоматизация производства систем программирования" : тезисы докладов
1986 / с. 137-138 https://www.ester.ee/record=b1216891*est

Электрические аппараты : пособие к лабораторным работам для студентов специальности 0628 и 0601

1982 https://www.ester.ee/record=b1264696*est